

DESIGN OF HIGH-SPEED CMOS LASER DRIVER USING A STANDARD CMOS TECHNOLOGY FOR OPTICAL DATA TRANSMISSION

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DESIGN OF HIGH-SPEED CMOS LASER DRIVER USING A STANDARD CMOS TECHNOLOGY FOR OPTICAL DATA TRANSMISSION

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To my parents who are always believing in me.
To my lovely wife, Soojung, who kept encouraging me
and my precious Youjin.

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LIST OF ABBREVIATIONS

BER	Bit error rate
BERT	Bit error rate tester
BPS	Bit per second
CH	Cherry-Hooper
CMOS	Complementary metal oxide silicon
COB	Chip-on-board
CS	Current switch
CW	Continuous wave
DFB	Distributed feedback
DH	Double heterojunction
ELO	Epitaxial liftoff
ESD	Electrostatic discharge
FP	Febry-Perrot
FTTX	Fiber-to-the-curb/home/building/desktop
GaAs	Gallium arsenide
InP	Indium phosphide
ISI	Intersymbol interference
LAN	Local area network
LED	light emitting diode
LVDS	Low voltage differential signal
MIM	Metal-Insulator-Metal
MQW	Multiquantum well
NA	Numerical aperture
NRZ	Non return to zero
OOK	On-off keying
PCB	Printed Circuit Board
PRBS	Pseudo random bit sequence
SDH	Synchronous digital hierarchy
SiO₂	Silicon dioxide
SMU	Source measurement unit
SONET	Synchronous optical networks
TSMC	Twain semiconductor manufacturing service
VCSEL	Vertical cavity surface emitting laser
WAN	Metropolitan area network
WMD	Wavelength division multiplexing

SUMMARY

Many researchers and engineers designing laser drivers for data rates at or above 10 gigabits per second (Gbps) implemented their designs using integrated circuit technologies that provide high bandwidth and good quality passive components such as GaAs, silicon bipolar, and InP. However, in low-cost and high volume short-haul applications at data rates of around 10 Gbps (such as LAN, MAN, and board-to-board interconnection), there has been an increasing interest in commercial CMOS technology for implementing the laser driver. This is because CMOS technology has unique advantages such as low power and low cost of fabrication that are the result of high yield and a high degree of integration. Therefore, the objective of this research in this dissertation is to investigate the possibility of implementing a high-speed CMOS laser driver for these cost sensitive applications.

The high-speed CMOS laser drivers designed in this research are of two types. The first type is a low power laser driver for driving a vertical cavity surface emitting laser (VCSEL). The other driver type is a high current laser driver for driving edge-emitting lasers such as double-heterojunction (DH), multiquantum well (MQW), or Fabry-Perrot (FP) lasers.

The parasitic effects of the layout geometry are crucial in the design of the high-speed laser drivers. Thus, in this research, all simulations contain a complete set of parasitic elements extracted from the layout of the laser driver. To test laser drivers, chip-on-board (COB) technology is employed, and printed circuit boards (PCBs) to test the laser drivers are designed at the same time as the laser drivers themselves and manufactured specifically for these tests.

This research makes two significant new contributions to the technology that are reported and described here. One is the first 10 Gbps performance of a differential CMOS laser driver with better than 10^{-14} bit-error-rate (BER). The second is the first demonstration of a heterogeneous integration method to integrate independently grown and customized thin film lasers onto CMOS laser driver circuits to form an optical transmitter.

CHAPTER I

INTRODUCTION

As the technology of communication systems has advanced in modern society, the amount of information transported has increased enormously. The technology of first the electronic era and then the microelectronic era led to the development of a profusion of analog and digital communication techniques that resulted in the installation and expansion of wireless and satellite links. Repeatedly scientists and engineers have found ways to exploit the available bandwidth and to expand its capacity for information to the point where fundamental constraints of noise, interference, power, cost, and other issues began to limit progress in electronic communication links. Research in how to surmount these limitations brought the next step in the evolution of communication systems, which is the use of optics as a replacement for electronics. The inherent advantages of optics, as compared with conventional electronics, have led a widespread replacement of copper wires for communication at data rates above Mbps and over kilometers. For example, wide bandwidth optical fibers allow high data rates and large data capacity with low transmission loss, which allows vastly increased distances between repeaters. In addition, a natural immunity to RF electromagnetic interference helps keep signal noise ratios low and permits the use of optical communication systems in noisy environments. As a consequence of these advantages, optical systems have replaced conventional electronic communication systems in long-distance applications and gradually are coming into use in networks involving shorter distances.

Today optical communication systems are used in many applications such as synchronous digital hierarchy (SDH)/synchronous optical networks, (SONET) systems, wavelength division multiplexing (WDM) network systems, Local Area Networks (LANs), Metropolitan Area Networks (MANs), fiber-to-the-curb/home/building/desktop (FTTX), and board-to-board interconnections, all of which use optical fiber for data conveyance [1].

A typical optical communication system has three main components: a transmitter, a transmission medium, and a receiver. This basic structure of the system resembles conventional electronic communication systems. The difference is that optical communications use optical signals as a carrier of information instead of using electronic pulses to transmit information through copper wires. The transmitter is composed of optical sources such as a laser or a light emitting diode (LED) and driver circuits. Semiconductor lasers are currently the main light output source in high-speed applications. The laser driver circuit is one of the key components because it performs as the interface between the electronic devices and the optical devices and, as such, affects the performance of the entire optical communication system. Its design, although simple in concept, is very challenging because of the difficulty of determining specifications that accommodate both large output current and operation at high-speed. To determine these design constraints a general understanding of the system into which the laser driver integrates is necessary.

Many researchers and engineers designing laser drivers for data rates at or above 10 gigabits per second (Gbps) implemented their designs using integrated circuit technologies that provide high bandwidth and good quality passive components such as

GaAs [2-8], silicon bipolar [1, 9], and InP [10-12]. However, in low-cost and high volume short-haul applications at data rates of around 10 Gbps (such as LAN, MAN, FTTX, and board-to-board interconnection) there has been an increasing interest in commercial CMOS technology for implementing the laser driver. This is because CMOS technology has unique advantages such as low power and low cost of fabrication that are the result of high yield and a high degree of integration. Therefore, the objective of this research in this dissertation is to investigate the possibility of implementing a high-speed CMOS laser driver for these cost sensitive applications.

The high-speed CMOS laser drivers designed in this research are of two types. The first type is a low power laser driver for driving a vertical cavity surface emitting laser (VCSEL). This laser driver must deliver a maximum of 10 mA_{p-p} modulation current and 10 mA bias current.

The other driver type is a high current laser driver for driving edge-emitting lasers such as double-heterojunction (DH), multiquantum well (MQW), or Fabry-Perrot (FP) lasers. This type of laser driver requires larger currents to drive the lasers: for example, the modulation currents need to be above 20 mA_{p-p} and bias currents of more than 20 mA are needed.

The parasitic effects of the layout geometry are crucial in the design of the high-speed laser drivers. Thus, in this research, all simulations contain a complete set of parasitic elements extracted from the layout of the laser driver. To test laser drivers, chip-on-board (COB) technology is employed, and printed circuit boards (PCBs) to test the laser drivers are designed at the same time as the laser drivers themselves and manufactured specifically for these tests. This research makes two significant new

contributions to the technology that are reported and described here. One is the first 10 Gbps performance of a differential CMOS laser driver with better than 10^{-14} bit-error-rate (BER). The second is the first demonstration of a heterogeneous integration method to integrate independently grown and customized thin film lasers onto CMOS laser driver circuits to form an optical transmitter.

1.1 Dissertation Outline

This dissertation presents the results of designs and experimental study of high-speed CMOS laser drivers for short-haul applications. The first part (Chapters III and IV) of this dissertation is dedicated to the design, layout, and measurements of a low power and high-speed laser driver. The second part (Chapter V) presents the design of a high current laser driver with low voltage differential signal (LVDS) input stages. A brief chapter-to-chapter outline of the dissertation is given below.

Chapter II provides background information on laser driver design. It starts with a discussion of the comparison of optical interconnects and electrical interconnects to provide the motivation of the research. Also covered in this chapter are a review of optical communication systems and descriptions of each component in the system. In addition, a brief comparison between lasers and LEDs as optical source is presented. Also included in this chapter is a basic concept of laser drivers. This section gives a brief review of modulation schemes, external and direct modulation. Some examples of laser drivers are also covered, along with an analysis of their comparative advantages and disadvantages. The last section of Chapter II describes the criteria, such as eye-diagram and BER test, for evaluating system performance of laser drivers.

Chapter III covers the design and implementation of a low power and high-speed CMOS laser driver. In the first section, design considerations are presented with the simulation process. The equivalent laser model provided by a corporate research partner and modified for this research is explained. Because the parasitic effects play a significant role in the implementation of a high-speed laser driver, the layout considerations are covered. To solve those parasitics effects on laser drivers, a decoupling technique using metal-insulator-metal (MIM) capacitors is employed. A test setup and some measurements results of the laser driver also are included in the chapter.

Chapter IV describes the optical transmitter, which consists of the laser driver and a thin film laser. The first section of this chapter covers the integration techniques used to form an optical transmitter. More established hybrid integration techniques such as flip-chip and epitaxial liftoff (ELO) are discussed. The fabrication of the thin film laser and some measurements results are also included. At the time of this writing, the thin film laser independently developed and optimized at Georgia Tech has thermal problems that require a pulsed mode testing setup. Therefore, the pulsed mode setup and experimental results are shown in this chapter. Using a transfer diaphragm heterogeneous integration process, a thin film laser is integrated onto a silicon CMOS laser driver, and the results of measurements are included in this chapter.

Chapter V describes the high-output current laser driver for driving edge-emitting lasers. This laser driver is compatible with the IEEE standard for low-voltage differential signals. To obtain high gain, modified Cherry-Hooper amplifier stages are included as a pre-driver stage. In addition, the bandwidth enhancement techniques used in CMOS technology are discussed in this chapter.

The final chapter summarizes the goal of this research and the contributions made to the field. It also points out how this research can be extended into the future.

CHAPTER II

BACKGROUND

This chapter presents basic concepts necessary for a better understanding of optical laser drivers. The first section compares optical and electrical links as a way to explain the advantages of the optical links. The second section then explains the basic concept of optical links as well as each component that makes up optical links. The next section examines laser driver circuits and the characteristics of the laser diode that are used in them. Finally, methods such as eye-diagram and BER test that are used to evaluate the system performances are explained.

2.1 Comparison of Optical and Electrical Links

The ongoing multimedia trend and the amount of communication required in the modern information and knowledge society imposes enormous performance requirements on computer networks and on the electronic equipment itself. In turn, these demands force the semiconductor industry to develop and manufacture even more powerful and faster components, especially microprocessors operating with clock frequencies of more than 3 GHz [13]. In addition, the continuing exponential reduction in feature sizes on electronic chips, known as Moore's law [2], results in large numbers of faster devices at lower cost. However, this advance alters the balance between devices and interconnections in systems; electrical interconnections do not scale proportionally with the devices. Consequently, these high-speed devices and components cannot deliver their

optimal performances because of the technical deficiency of interconnections. For example, the buses inside computer systems that carry the information from one part of the system to another run much slower than the clock rate on the core chips because of the various problems in the electrical interconnections. Moreover, the performance of many digital systems is limited by the bandwidth of the electrical interconnections that use printed circuit boards (PCB) and a multichip module between the chips and boards. Hence, the system has a bandwidth limitation that is imposed by the length of the interconnection line rather than by the performance of the semiconductor technology.

Problems associated with scaling create one of the most critical limitations in electrical interconnection technology. If simple electrical interconnections are considered, as shown in Figure 2.1, and scaled down with a scaling factor α , then the thickness (H_{int}), the width (W_{int}), the space between wires (W_{sp}), and the length (L_{int}) could shrink by $1/\alpha$. The conductor cross section area would shrink $1/\alpha^2$, increasing the resistance per unit length accordingly to α^2 , shown in equation (2.1.1). The National Technology Roadmap for Semiconductors (NTRS) [14] uses a nominal value of $\alpha = \sqrt{2}$ for generation to generation scaling, or $1/\alpha=0.707$.

$$W_{\text{int}} \times H_{\text{int}} = 1/\alpha^2, R_{\text{int}} = \rho_{\text{int}} \cdot \frac{1}{W_{\text{int}} \times H_{\text{int}}} = \alpha^2 \quad (2.1.1)$$

where ρ_{int} is the resistivity of materials. The capacitance per unit length does not change in such a shrinking-it depends only on the geometry of the line, not its size. The length of the interconnection line has been shrunk to $1/\alpha$, and so the total RC delay is $R_{\text{int}}C_{\text{int}}L_{\text{int}}^2=1$. This means that the RC time constant cannot be reduced by the scaling factor but has to be reduced for global interconnections.

With increasing levels of integration, the die size will increase and require fatter wires in the chip. This will increase cross talk and decrease the yield of the die. The transistors on a chip get faster as the technology dimension shrinks, but the electrical interconnections are not keeping up with the transistors. Obviously, the electrical interconnections do rely on wires with their associated inductance, resistance, and capacitance. Hence, problems in the electrical interconnections included in scaling are relevant to the physics of wires and hardly avoidable in principle.

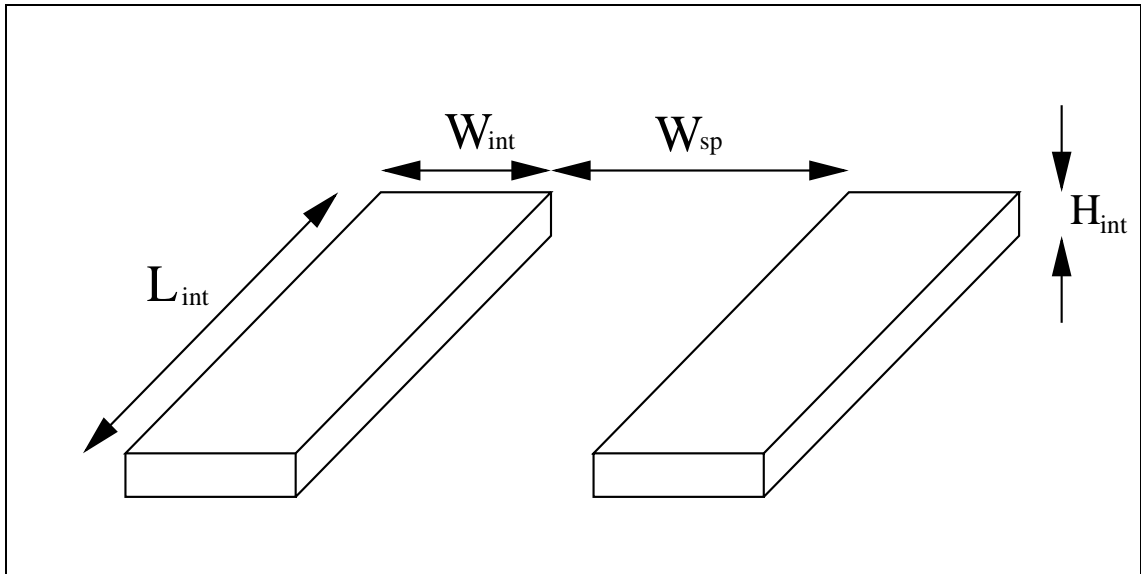


Figure 2.1. Illustration of electrical interconnection lines.

Because these problems are inherent in the physics of wires, there has been significant interest in using optics for interconnection technology as a way to solve many physical problems such as signal and clock distortion, skew and attenuation, impedance mismatching, cross-talk, power dissipation, wave reflection phenomena, and interconnect density limitations [15]. Historically, optical interconnections have been successfully

implemented and have replaced electrical interconnections in long-distance applications in which relatively few optoelectronic interfaces are necessary. Moreover, electrical interconnections gradually are being replaced in short-distance communications such as in chip-to-chip interconnections.

Ever since optics began to be used in interconnection technology, many researchers have compared them with conventional electrical interconnections and discussed their potential [16-19]. In general, there exists a critical length above which optical interconnects are preferred from the point of view of performance, power dissipation, and a speed. Although the critical length varies with different technical assumptions, the trend away from electrical interconnections and to optical interconnections is clear and is becoming apparent in short-distance applications. A list of the advantages most often cited for optical interconnection technologies is presented in Table 2-1.

Recently a lot of research has been concentrated on developing optical chip-to-chip interconnections. The board, backplane [20], chip level 3-D stacking for free space [21], and plastic optical fiber-based (POF) interconnection [22, 23] all have been demonstrated. Also, cost-effective solutions for optoelectronic interconnects with CMOS circuitry were presented in [24].

Table 2-1. Relative merits of electrical and interconnection technologies [25].

Electrical	Optical
<ul style="list-style-type: none"> • High-Power Line-Driver Requirements • Thermal Management Problems • Signal Distortion • Dispersion: Interconnection delay varies with frequency • Attenuation: signal attenuation that varies with frequency • Crosstalk: capacitive and inductive coupling from signals on neighboring traces • Reflection/Ringing: impedance matching requirements not met • Signal Skew: variations in the delay between different waveforms on different paths in signal and clock traces • High-Sensitivity to Electromagnetic Interference (EMI) 	<ul style="list-style-type: none"> • Higher interconnection densities • Higher packing densities of gates on integrated circuit chips • Lower power dissipation and easier thermal management of systems that require high data rates • Less signal dispersion than comparable electronic scheme • Easier impedance matching of transmission lines • Less signal distortion • Greater immunity to EMI • Lower signal and clock-skew

2.2 Optoelectronic Links

The system block diagram for optoelectronic links is shown in Figure 2.2. It consists of an optical transmitter, optical source, optical medium, photodetector, and optical receiver. On the transmitting side, the optical transmitter converts the input signal from the optical source into a large current used to modulate the optical source. The light output propagates through the optical medium in which optical fiber, free space, or waveguide is commonly included. The light signal from the optical medium is collected by a photodetector that generates an electrical current. The optical receiver uses the photodetector to convert the optical signal into an electrical signal and amplifies it enough to be treated as a digital signal. It is the cost and efficiency of these processes that will determine whether such links are considered for on-chip and chip-to-chip communication.

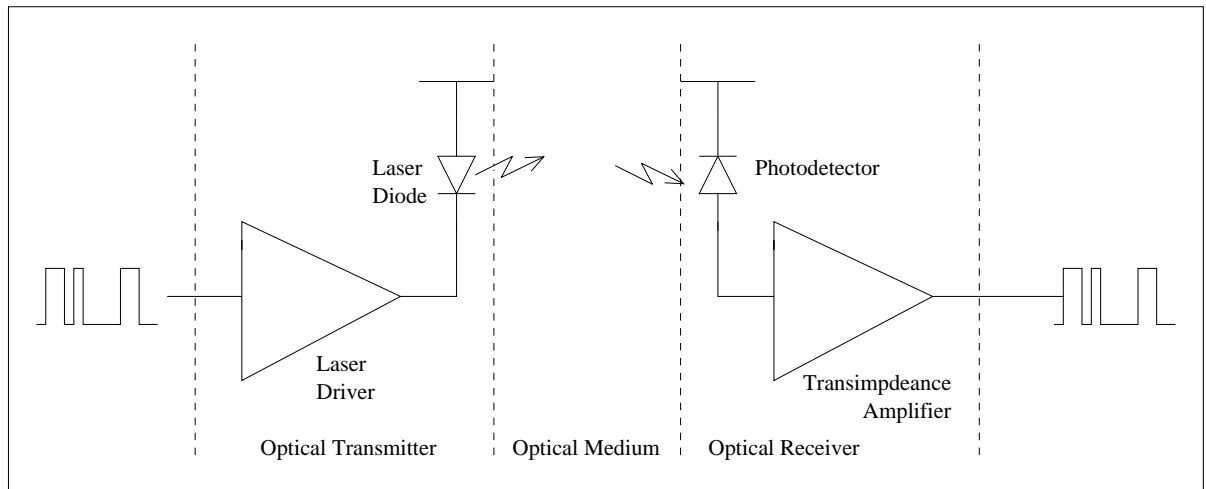


Figure 2.2. Simple block diagram of optoelectronic links.

Although the system topology shown in Figure 2.2 has changed little over the past several decades, the design of its building blocks and the levels of integration have. Driven by the evolution and affordability of IC technologies as well as by the demand for higher performance, this change has created new challenges that require new circuit and architecture techniques [26].

2.3 Semiconductor Laser

The main optical source in communication system is either light-emitting diodes (LEDs) or semiconductor lasers. The advantages of the laser over the LED, such as its unique size, spectral region of operation, high efficiency, and high-speed operation have led to dramatic improvements in high-speed optical communication systems. In the early stages of semiconductor laser development the trend was toward optimizing laser structures for improvements in static lasing characteristics in terms of threshold current, quantum efficiency, linearity of light versus current characteristic, operation at high optical power, and long-term reliability [27]. As laser fabrication technology improved, the high-speed dynamic characteristics of lasers become increasingly important. A plot of the light output power from a semiconductor laser and LED is shown in Figure 2.3.

If the current is less than a threshold value, I_{th} , the optical power of the laser is small, and the device operates as an LED, using spontaneous emission. As the current increases above the threshold value, the stimulated emission becomes dominant and the laser begins operating in the linear region with high slope efficiency (dL/dI) compared with the LED.

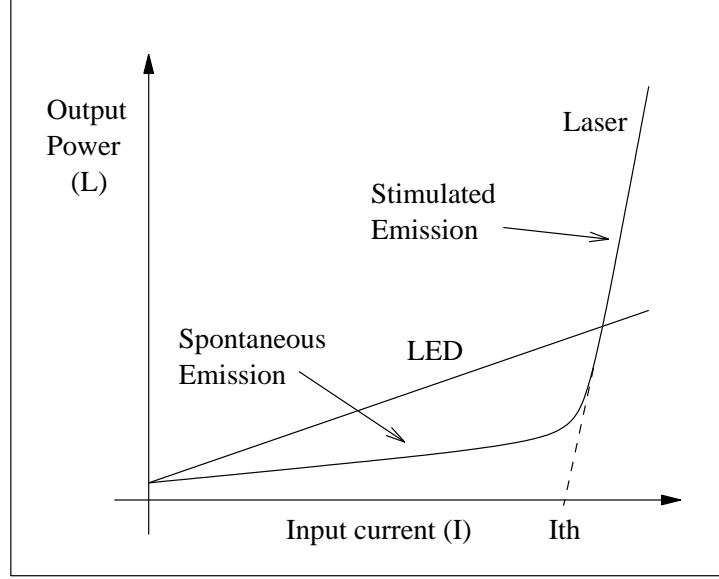


Figure 2.3. The L-I curve for laser and LED. I_{th} indicates the threshold current of the laser.

2.3.1 Modulation Bandwidth in Semiconductor Lasers

One of the most interesting characteristics of lasers in optical communication systems is the maximum modulation speed of the laser. The small-signal response of the laser is obtained by linearizing the rate equations. The resulting dynamic solution for small-signal modulation is a second-order transfer function [28].

$$\frac{\Delta P}{\Delta J} = \frac{P_o + \beta/\tau_s}{\left[\frac{1}{\tau_p} (\sigma_s P_o + \beta/\tau_s) - \omega^2 \right] + j\omega \left[\frac{1}{\tau_p} + \sigma_s P_o \right]} \quad (2.3.1)$$

where P is the photon density in a mode of the laser cavity, σ_s is a collection of constants describing the strength of the optical interaction; τ_s is the spontaneous recombination life time of the carriers; τ_p is the photon life time, which is the average time a photon stays in the cavity; P_o is the steady-state photon density; and β is the fraction of spontaneous

emission entering the lasing mode. At large frequencies, the ω^2 term in the denominator dominates and the small signal response of laser falls off rapidly with a frequency above a critical value [27, 28]. The critical frequency for modulation is when the denominator is minimized,

$$f_\tau \approx \frac{1}{2\pi} \sqrt{\frac{\sigma_s P_o}{\tau_p}} = \sqrt{\frac{\nu_g g_o \Gamma \eta_i (I - I_{th})}{qV}} \quad (2.3.2)$$

where η_i is the internal quantum efficiency; Γ is the optical confinement factor; ν_g is the group velocity of optical mode; q is the electron charge; V is the active region volume; $(I - I_{th})$ is the bias current above threshold; and g_o is the differential gain [29].

The modulation bandwidth of the laser is accepted as equal to f_τ . As illustrated in Figure 2.4, the output power by current modulation is a flat function at low frequency, but shows a peaking at near f_τ . Resonance in the modulation response, known in a laser as the relaxation oscillation [27], physically results from coupling between the intensity and the population inversion via stimulated emission. Such oscillation causes distortion (ringing) in the shape of the output light pulse that requires some time to settle. Thus, this oscillation limits the speed of the laser.

Equation (2.3.2) suggests three ways to increase the modulation bandwidth of laser. One is by increasing the optical gain coefficient σ_s , a second is by increasing photon density P_o , and the third is by decreasing the photon lifetime τ_p .

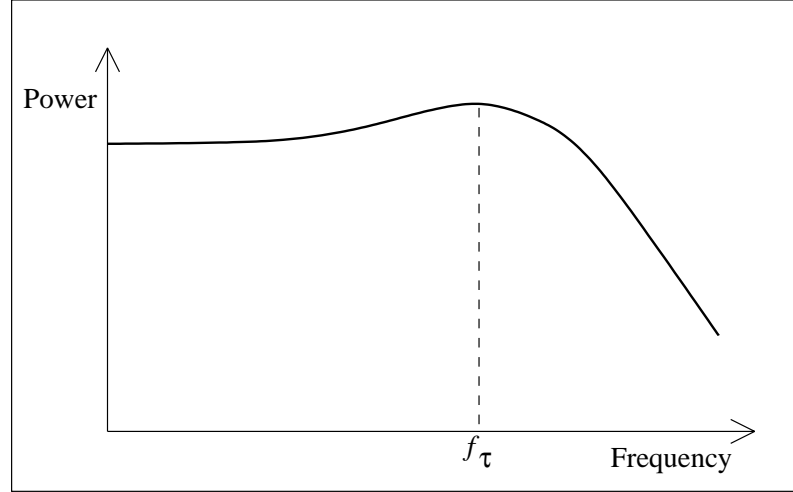


Figure 2.4. Output power vs. Frequency. f_τ is the relaxation oscillation frequency.

The gain coefficient can be increased roughly by a factor of five by cooling the laser from room temperature to 77 °K [27]. To increase photon density, the cavity of the laser should have higher reflectivity, which results in a smaller threshold current. The third way to increase the modulation bandwidth is to reduce the length of laser cavity. However, the maximum frequency only increases by the square root of changes in the power of the photon lifetime, so it is not easy to make dramatic improvement in the frequency response.

2.3.2 Turn-on delay

When a laser is turned on, photon generation begins as a spontaneous emission until the carrier density exceeds a threshold level. Thus, stimulated emission occurs after some delay. This turn-on delay is illustrated in Figure 2.5 and causes the jitters in the output. For an applied current pulse of amplitude of I_p the turn-on delay is given by [30]

$$\tau_d = \tau_{th} \left(\frac{I_p}{I_p + I_b - I_{th}} \right) \quad (2.3.3)$$

where I_b is a bias current, I_{th} is the threshold current, and τ_{th} is the delay at threshold. Equation (2.3.3) implies that the turn-on delay will be reduced by the use of a large modulation current and a low threshold current laser. Therefore, for a fast switching operation, common practice is to bias the laser diode slightly above the threshold to avoid turn-on delay.

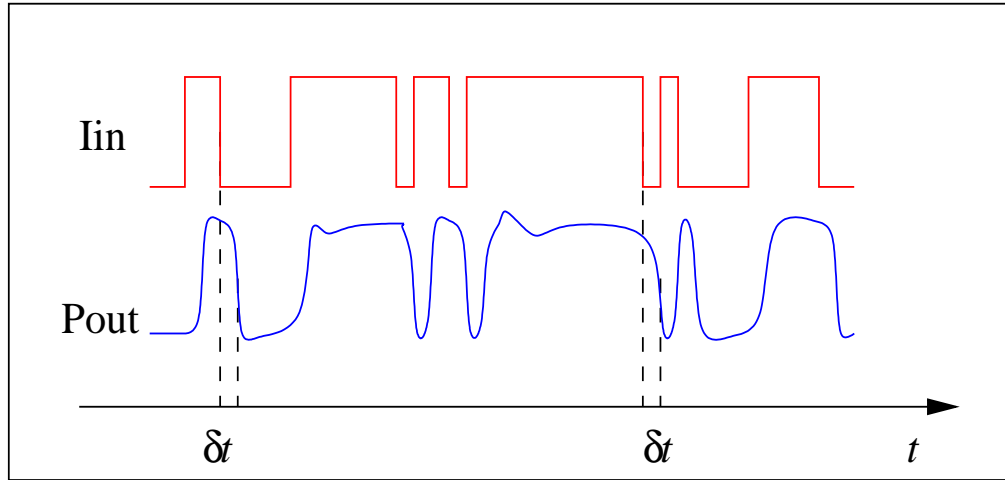


Figure 2.5. Effect of variable delay in lasers.

2.3.3 Frequency Chirping

As pulses get shorter with an increase in the bit rate, chromatic dispersion, the change of the index of refraction with wavelength, becomes important and plays a significant role in limiting the performance of optical communication systems. When the current through the laser is modulated, the laser wavelength is also modulated with the

power output from the laser. This effect is called frequency chirping. The principal consequence of chirping is the broadening of the light spectrum, leading to substantial dispersion in optical fibers carrying such signals, thereby creating intersymbol interference (ISI) [26]. This spectrum broadening coupled with the dispersive properties of optical fibers limits the maximum fiber transmission distance at high frequency. An approximate equation for chirping is given as:

$$\Delta \nu(t) = \frac{\alpha}{4\pi} \left(\frac{1}{P(t)} \frac{dP(t)}{dt} + \kappa P(t) \right) \quad (2.3.4)$$

where $\kappa = 2\Gamma\varepsilon/V\eta_d h\nu$, η_d is the differential quantum efficiency, h is a Planck's constant, ν is the optical frequency, α is the linewidth enhancement factor [31], and ε is the nonlinear gain coefficient. The equation (2.3.4) implies the frequency shift $\Delta \nu(t)$ is proportional to the rate of change of the optical output power $dP(t)/dt$ [29].

2.3.4 Temperature effects

A laser does not maintain a constant optical output if the temperature of device changes. As shown in Figure 2.6, the threshold current can be expressed approximately in terms of the working temperature such as:

$$I_{th}(T) = I_0 + K_I e^{\frac{T}{T_i}} \quad (2.3.5)$$

in which I_0 , K_I , and T_i are laser-specific constants. Example constants for a DFB laser are $I_0=1.8\text{mA}$, $K_I=3.85\text{mA}$, and $T_i=40^\circ\text{C}$ [32].

Slope efficiency (S) is defined as the ratio of the optical output power to the input current. As the temperature is increased, slope efficiency is decreased. The following equation provides an estimation of slope efficiency as a function of temperature:

$$S(T) = S_o - K_s e^{\frac{T}{T_s}} \quad (2.3.6)$$

For the same DFB laser in the above example, the characteristic temperature, T_s , is close to 40 °C, $S_o=0.485\text{mW/mA}$, and $K_s= 0.033\text{mW/mA}$ [32].

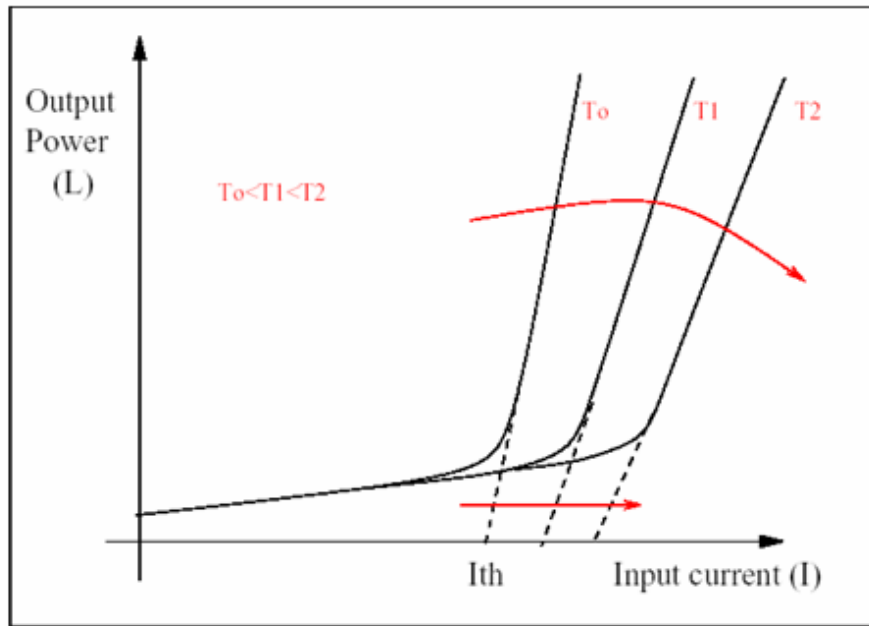


Figure 2.6. Temperature effects on semiconductor lasers.

2.4 Laser Driver

A laser driver can be considered a simple current switch that responds to an input signal modulated by the data stream. As shown in Figure 2.3, the light output from a laser is defined as a function of the input current rather than of voltage. If the temperature of the laser is changed, large current fluctuations can result, even if the voltage is held constant. Similarly, very small fluctuations in drive voltage would correspond to dramatic changes in current and output power. For this reason, and because of the speed advantages of current switching, laser diodes are driven by currents.

In general, in most optical systems, the electro-optic interface limits the maximum speed of the system. Therefore, laser drivers and optical receivers are very important components that determine the performance of optical systems. It is imperative that the laser driver be able to function reliably at high speed as an optical signal generator. One of the critical challenges of the laser driver is to deliver tens of milliamperes of current with very short rise and fall times because bandwidth is a trade-off for large output current.

Optical transmitter circuitry falls into two categories that are defined by methods of modulation. One is the directly modulated transmitter consisting of a laser diode and a laser driver. This type has been used in long- and short-haul transmission systems. As shown in Figure 2.7 (a), the input data stream is directly modulated by the laser driver, and the laser diode emits light output in response to the logic of “one” or “zero”. Although a variety of modulation schemes have been attempted, the simplest and most widely used modulation scheme is the direct modulation of the light intensity by data, called on-off keying (OOK).

As data rate is increased, however, a direct-modulated laser results in transient oscillations, which are known as relaxation oscillation. This condition results from coupling between the intensity and the population inversion via stimulated emission. Such oscillation causes distortion (ringing) in the shape of the output light pulse and broadens the signal's optical spectrum, leading to substantial dispersion in optical fibers. This dispersion induces inter-symbol interference (ISI) because of laser chirp, thus contributing to an increased bit error rate (BER).

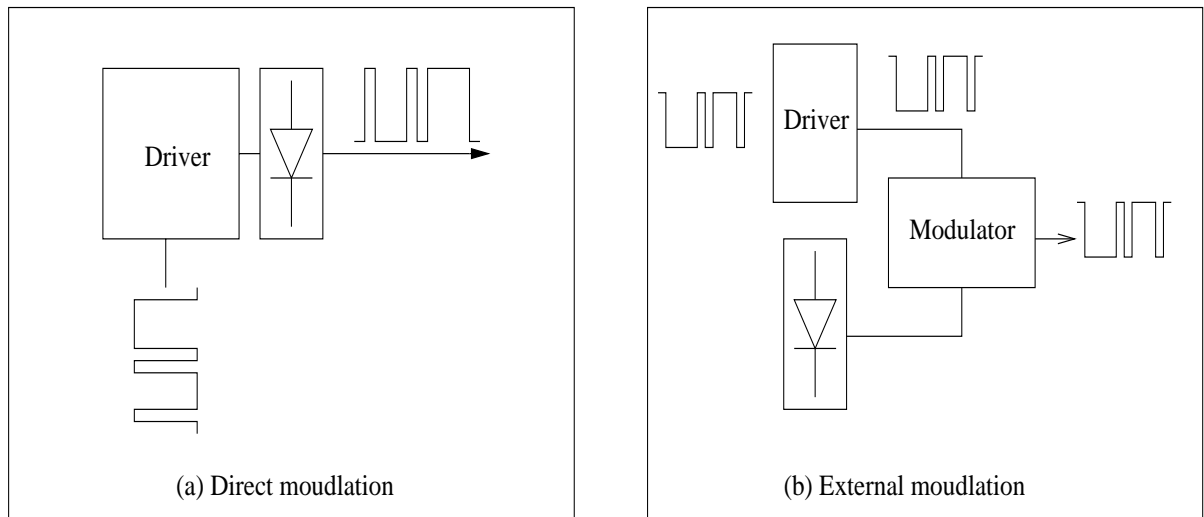


Figure 2.7. Modulation scheme: (a) Direct modulation and (b) External modulation.

Nevertheless, current research has focused on developing the direct-modulated laser because this type of transmitter has advantages such as low-cost, low-power consumption, and simple structure. In addition, many techniques to overcome the problems associated with direct modulation have been reported, such as solutions for chirp reduction and suppression of relaxation oscillation with the modification of the

physical laser devices [27, 33-35]. Consequently, for a 10 Gbps short-distance system, much effort has been devoted to a directly modulated transmitter.

The other type of optical transmitter is externally modulated and consists of a laser driver, a laser diode, and an external modulator, which can achieve a lower chirp, or even a negative chirp, to support the dispersion in the fiber [36]. External modulation can have higher link gain and lower link noise but it needs a higher-power laser, high electrical input power and it is more expensive. In this modulation scheme, shown in Figure 2.7 (b), the laser is maintained in a constant light-emitting state and the external modulator modulates the output intensity according to an externally applied voltage. Mach-Zehnder type electro-optic modulators fabricated in either lithium niobate or gallium arsenide are often used for this purpose.

Typically, the design of laser driver circuits incorporates the use of various feedback loops to compensate for the effects of variations of the input data stream and for temperature and aging. One simple laser driver circuit used to connect the output of a current driver circuit directly to the laser diode is shown in Figure 2.8 (a) [37]. The threshold current for a laser is provided by V_b , and the modulation current is provided by a source resistor, R_{mod} , respectively. This type of single-ended laser driver is typically used with low operating speed because of the unwanted parasitic inductance from the package's bonding wires, $L1$. When this parasitic inductance is combined with the high impedance of the laser driver circuits and the low impedance of the lasers, it degrades the output of the laser's rise time and causes a power supply current ripple.

The laser driver shown in Figure 2.8 (b) [38] makes use of open collector topology. The laser is connected directly to the collector of one transistor of a differential

pair with the bias current supplied by the current source, I_{mod} . The laser current is the sum of the collector currents of Q2 and I_{dc} . Whenever light output is called for, these currents can be controlled to exceed threshold and reach a point substantially up the lasing region of the L-I curve. Matching circuitry between the driver and the laser must be used to overcome the large impedance mismatch that occurs in this topology.

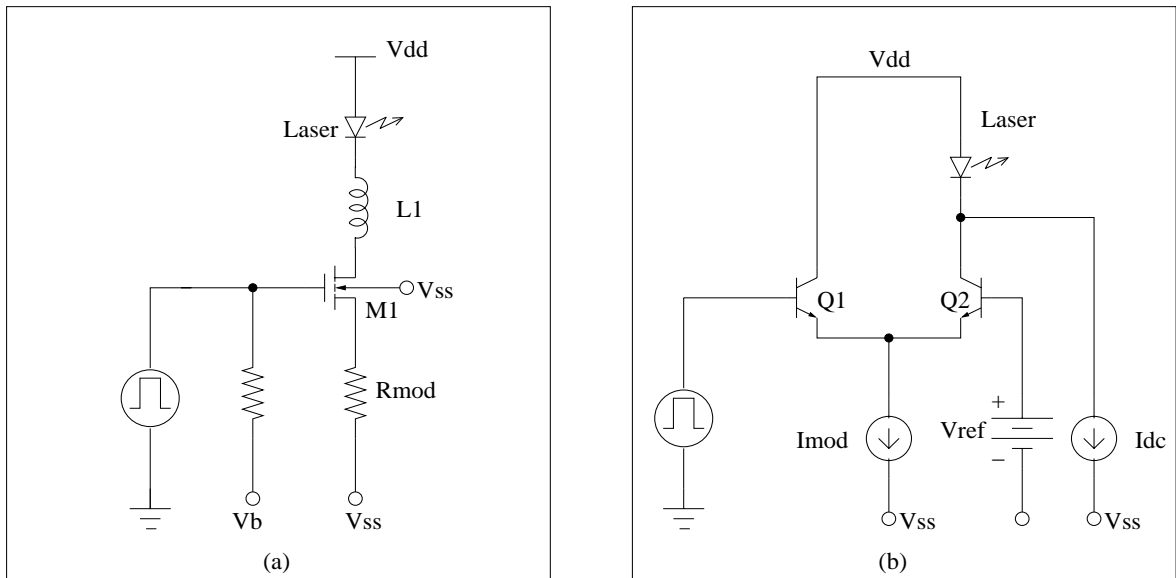


Figure 2.8. Schematic of simple laser drivers.

As data rates and transmission distances increase, the output of the laser diode needs to be more precisely controlled. Because the laser's output power can vary with temperature and over its lifetime, higher performance systems incorporate some method of monitoring the light output and providing feedback of this information to the driver [39].

2.5 Evaluating System Performances

2.5.1 Eye diagram

The eye diagram is, as shown in Figure 2.9, an overlay of many transmitted waveforms whose shape resembles a human eye. By using a clock signal as the trigger input to the oscilloscope, the transmitted waveform can be sampled over virtually the entire data pattern generated by the transmitter. Thus, all the various bit sequences that might be encountered can be sampled to build up the eye diagram.

The eye diagram can analyze the significant information about the transmitted output. The height of the central eye opening measures noise margin; thus, this vertical eye opening can determine the quality of the signal. A very clean signal will have a large, clear eye, and a noisy, low-quality signal will have a smaller or a closed one. Obviously, the more open the eye is, the easier it will be for the receiver to determine the signal logic level [40]. By measuring the thickness of the signal line at the top and bottom of the eye, signal distortion and noise can be analyzed in the output. The jitter, the deviation of the zero crossings from their ideal position in time, will cause the eye to close in the horizontal directions. Thus, the width of the signal band at the corner of the eye measures the jitter. The eye diagram also can measure the rise and fall times of the signal by measuring the transition time between the top and bottom of the eye [41]. The characteristics of an eye diagram are illustrated in Figure 2.10.

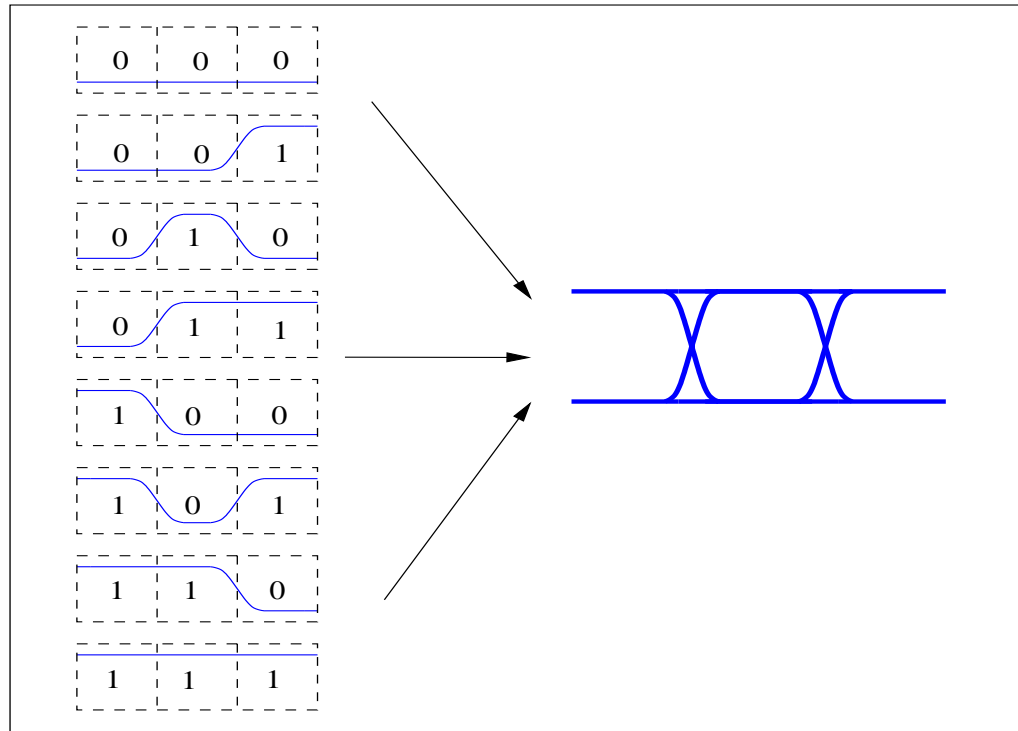


Figure 2.9. Various bit sequences and corresponding eye diagram.

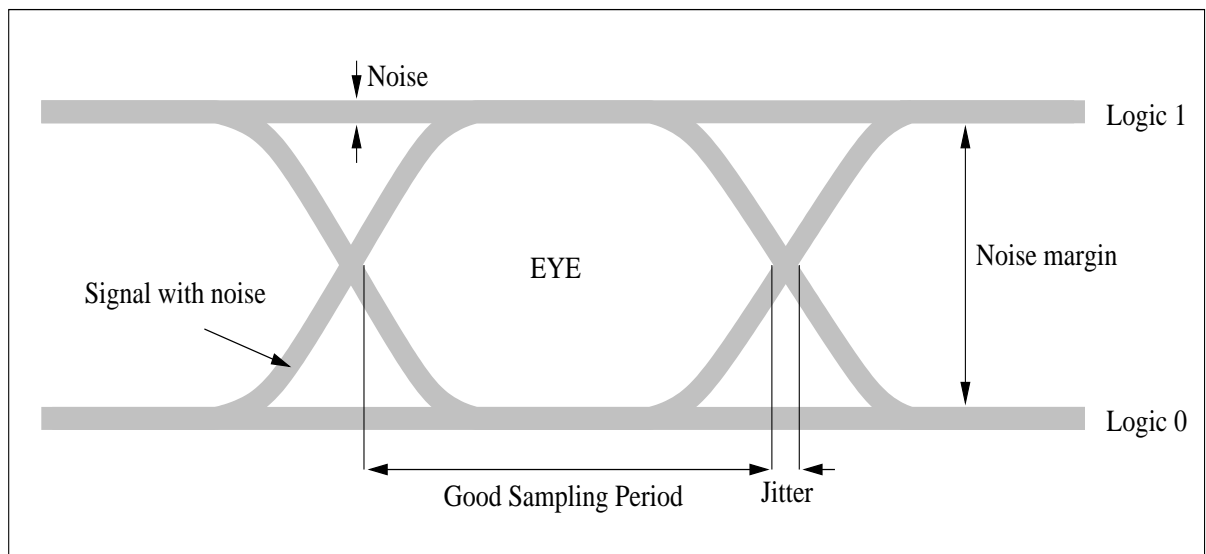


Figure 2.10. The characteristics of an eye diagram.

2.5.2 Eye pattern mask

It is not possible for two people speaking different languages to communicate. Only if two people speak the same language they can communicate with each other. The same situation prevails in the communication systems; Transmitters and receivers work together properly when both pieces of equipment use the same language. Thus, communication engineers have been developed standards to ensure that equipment from different companies will be able to interface properly. SONET and SDH are essentially the same standard for synchronous data transmission over fiber optic networks. SONET was developed in the mid-1980s and standardized in North America, and SDH is its international counterpart [42]. SONET/SDH defines a hierarchy of signals at multiples of the basic rate. The following table lists the hierarchy of signals at multiples of the base rate.

Table 2-2. Basic SONET/SDH data rates [42].

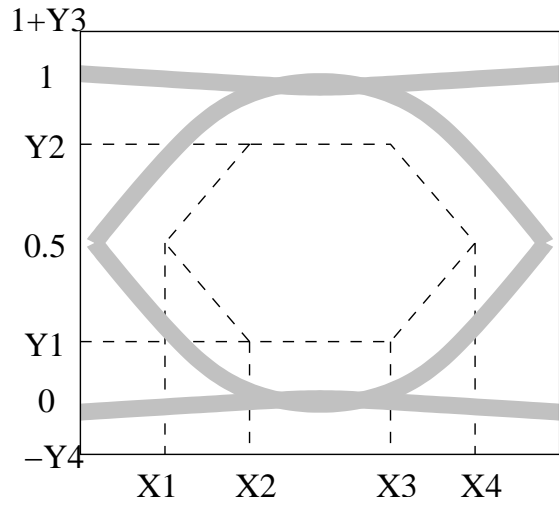
SONET		SDH	Rate (Mb/s)
Optical Level	Electrical Level		
OC-1	STS-1	-	51.840
OC-3	STS-3	STM-1	155.520
OC-12	STS-12	STM-4	622.080
OC-48	STS-48	STM-16	2488.320
OC-192	STS-192	STM-64	9953.280

The SONET/SDH standards provide parameters and values for optical interfaces. For the transmitter parts of such interfaces, they recommend an eye pattern mask to specify general transmitter pulse shape characteristics, including rise time, fall time, pulse overshoot, pulse undershoot, and ringing. The parameters in specifying the mask of the transmitter eye diagram are shown in Figure 2.11.

2.5.3 Bit error rate (BER) measurements

The definition of BER is simply the ratio of the erroneous bits to the total number of bits transmitted, received, or processed over some stipulated period, usually expressed as ten to a negative power. For example, a ratio of 10^{-10} means that one wrong bit is received for every 10 billion bits transmitted. Thus, the BER is a parameter of describing the quality of signals in digital systems. In addition, the specification for BER is dependent on the application requirements.

The power from the transmitter is large enough that if it were to arrive unattenuated at the system receiver, error-free communication would occur. System performance in terms of BER is often characterized in terms of the amount of attenuation between the transmitter and receiver. Similarly, the BER can be characterized in terms of power level at the receiver. Figure 2.12 shows [40] a typical BER characterization of a high-speed system. As the received power is decreased, the signal-to-noise ratio is reduced and the probability of a bit being received in error increases.



	STM-4	STM-16	STM-64
X1/X4	0.25/0.75	-	-
X2/X3	0.40/0.60	-	-
X3-X2	-	0.2	0.2
Y1/Y2	0.20/0.80	0.25/0.75	0.25/0.75
Y3/Y4	0.20/0.20	0.25/0.25	0.25/0.25

Figure 2.11. Mask of the eye diagram for the optical transmit signal [43].

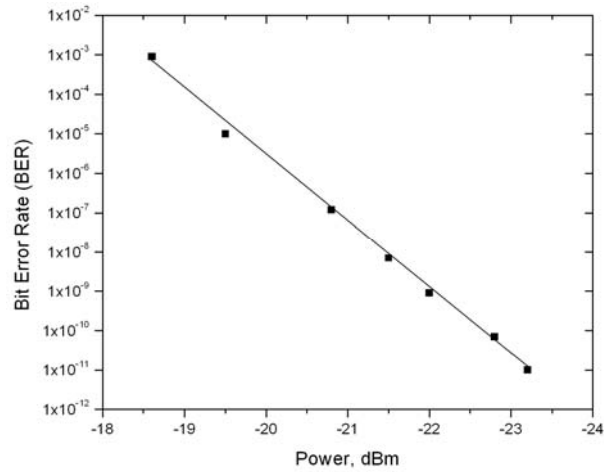


Figure 2.12. Typical BER characterization at high-speed [40].

CHAPTER III

DESIGN OF LOW-POWER CMOS LASER DRIVER

This chapter starts with the motivation for the design of high-speed and low-power CMOS laser drivers. In addition to the design considerations of the laser driver, preliminary simulations to verify the circuit schematic topology follow. Based on these simulation results, the circuit is laid out with careful consideration for parasitic effects. Then, with the data extracted from the layout, the driver circuit goes through a series of simulations again with packaging effects, decoupling, and protection circuits for electrostatic discharge (ESD).

3.1 Introduction

The motivation for the design and implementation of the high-speed and low-power CMOS laser drivers arises from their critical role in the performance of optical systems. To date, because of the rapid advances in multimedia applications, modern communication systems have required the data links with ever-increasing capacity. This necessitates high-speed optical communication systems. In such optical systems, the design of a high-speed laser driver and receiver circuit is critical to the optimization of the optical system because the electro-optic interface limits the maximum speed of the overall systems as mentioned in Chapter II. In addition to the high-speed operation, the laser driver should meet the systems requirements such as low BER and low electrical power consumption.

Various solutions to the problems of designing of the high-speed laser driver circuits have been demonstrated in GaAs [5] and InP [10, 12] based technologies to gain the required performance, but the low-level of integration with other digital ICs limits the sustainability of the end product for short-reach applications. Therefore, much effort to implement the laser drivers in silicon CMOS technology has been made in both research and commercial fields because of the high degree of integration of CMOS technology with other components. Besides the advantages of high levels of integration, CMOS technology has unique advantages of vast standard cell libraries, power efficiency, and high yield compared with other IC technologies. Thus, in this research, the laser driver was designed and fabricated in Twain Semiconductor Manufacturing Company's (TSMC) 0.18 μm mixed-signal CMOS technology through the MOSIS foundry service.

Table 3-1 summarized the specifications used in this research. The design goals were established so as to meet the needs of two groups, researchers at a corporate research partner and the integrated optoelectronics group at Georgia Institute of Technology. The laser driver was designed to have up to 10mA modulation currents and 10mA bias currents at 10 Gbps and also to have the lowest possible power consumption.

Table 3-1. Predetermined design goals of the laser driver.

Specifications	Goal
Speed	Greater than 10Gbps
Current	Laser bias current: >10mA Modulation current : >10mA
Current Density	< 1mA/ μm^2
Power Consumption	As low as possible

3.2 Design Considerations

The aggressive demand for more bandwidth in communication systems has led to increases in the density of integration and the switching speed of transistors. As switching speed increases, high current switching within a short time period can generate considerable dI/dt , and inductance (L) can lead to sizable voltage fluctuations, $V=L \cdot dI/dt$. This inductance results from the off-chip bonding wires and the on-chip parasitic inductance of the power supply rails. This noise, called simultaneous switching noise, ΔI noise, or ΔI noise [44, 45], can seriously degrade signal integrity and is one of the main noises that affects the design of laser drivers. Therefore, in this research the creation of a high-speed operating laser driver relies on the differential topology because it is immune to ΔI noise [46].

Differential drivers offer many advantages over single-ended circuits. First, they can maintain a relatively constant supply current by canceling unwanted common-mode signals, thus minimizing ΔI noise. Second, if the signals remain truly symmetry, they can reduce cross talk. Third, their complementary signals with symmetric transients

simplify the design of wideband signal transmission interconnects, resulting in improved eye diagrams at higher data rates [47]. Finally, they have low common-mode gain, a feature can help prevent oscillation despite the presence of unwanted common-mode feedback resulting from packaging parasitics.

The laser driver is designed to modulate a laser with a serial data stream and provides dc bias current to the laser. The circuit schematic for the laser driver is depicted in Figure 3.1.

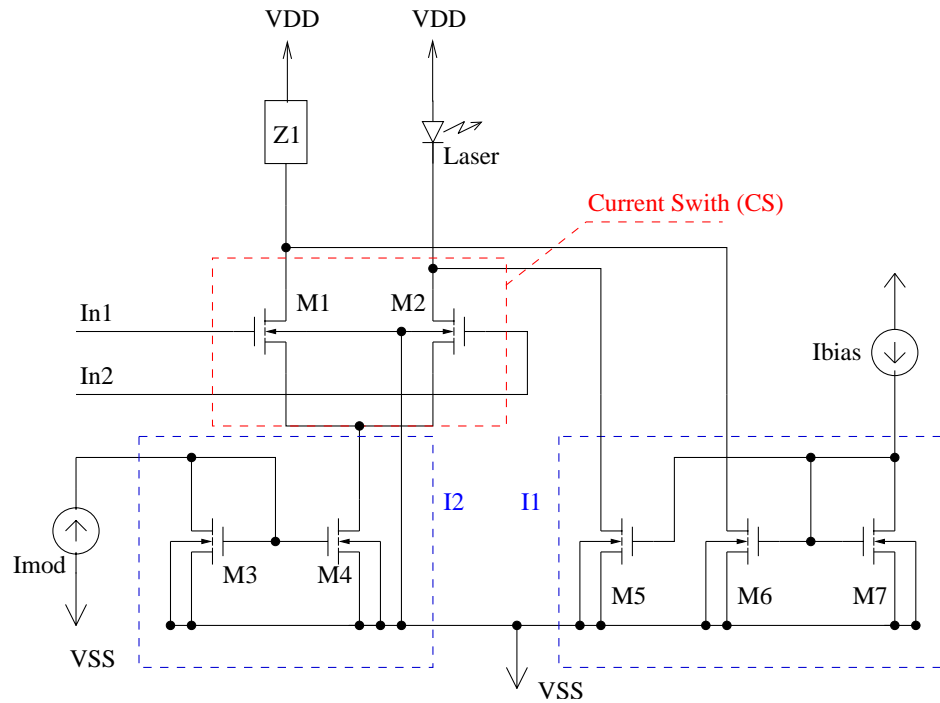


Figure 3.1. Schematic of laser driver.

It consists of a differential current switch (CS) and current mirrors (I1, I2). The current switch consists of two matched enhanced MOS transistors, M1 and M2. As the size of the input transistors increases, higher output current are achievable. However,

speed is decreased because of the increase of the input gate capacitance, which is dominant to switching delay. Thus, optimization of the size of the transistors is necessary so that the design of driver circuits can provide modulation current to maintain high-speed operation. To achieve proper driving current into the laser, the current sink (I2) is set to I_{mod} , and the current sink (I1) is fixed at I_{bias} . In the case of logic ONE, the M1 transistor is on and the M2 is off and the total current, I_{bias} , flows into the laser. At the logic ZERO, the M1 transistor is off and the M2 is on. Then, the current $I_{bias} + I_{mod}$ flows through the laser. Thus, as mentioned in Chapter II, the I_{bias} current was designed to have a value equal to or slightly larger than the threshold current of the laser diode to ensure a fast switching operation that will avoid turn-on delay.

One of the outputs of the differential switch is connected with the laser diode, and the other output is connected with a dummy load (Z1). The electrical characteristics of the dummy load were optimized to match those of a laser diode in simulation and implemented by on-chip diodes and resistors. These optimizations are required to reduce the impedance mismatch at output loads and to suppress ΔI noise. On-chip matching resistors, which are excluded in Figure 3.1, were used to minimize the return loss in the input line. Compared with off-chip matching resistors, the return has been improved [48].

3.3 Simulations

Once IC technology and circuit topology were determined, CMOS technology and differential topology were chosen to achieve the design specifications in this research, and simulations were performed using HSPICE on the overall laser driver circuitry using TSMC CMOS 0.18 μm BSIM3 model parameters (See Appendix) provided by MOSIS foundry service. A Cadence schematic tool was used to test the function of the laser

driver and estimate its speed. If the simulation results meet the design specifications, the layout of circuit were performed, then the circuitry was re-simulated using the extracted SPICE file from a Cadence layout tool to obtain information of parasitic parameters, which can be generated and calculated from the layout, are not generally considered in schematic simulation but play a significant role in high-speed circuit performance. The flowchart of the simulation process is depicted in Figure 3.2.

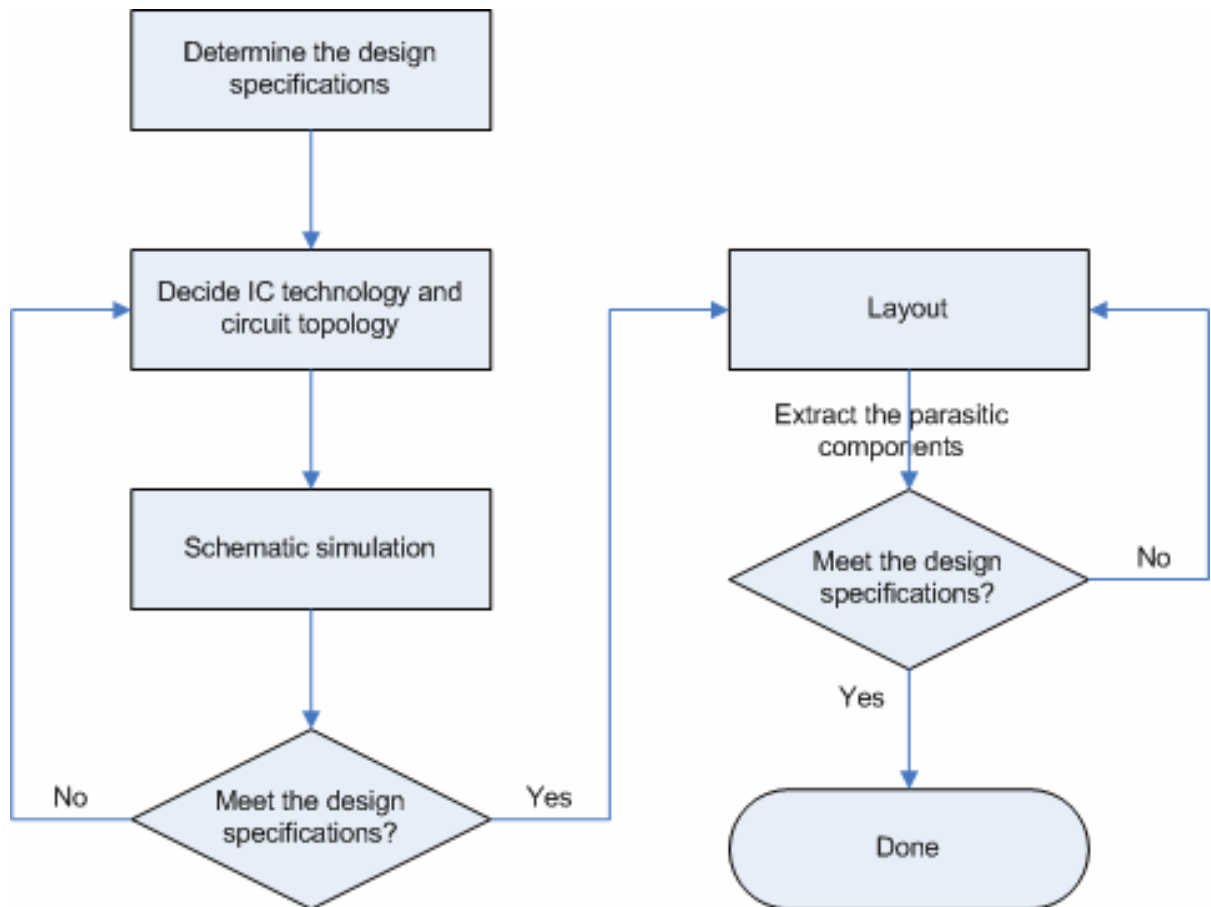


Figure 3.2. The flowchart of the simulation processes.

3.3.1 Schematic-based simulations

Figure 3.3 shows the transient response of the driver at 10 Gbps in schematic simulations. The top trace represents the pseudo random bit sequence (PRBS) input signal at 10 Gbps, and the middle trace is the output currents of laser diode. The bottom plot shows the eye diagram used to examine the intersymbol interference (ISI) effects that result from the limited circuit bandwidth or from any imperfection that affects the magnitude or phase response of a system [26]. As shown in the simulation results, when only on-chip parasitics are considered, the laser driver is working properly with 10mA modulation current at laser diode and variable laser bias currents at design specifications. However, this simulation shows results only for the functional verification of the laser driver. Therefore, off-chip parasitic and packaging effects should be included in the overall circuit simulations.

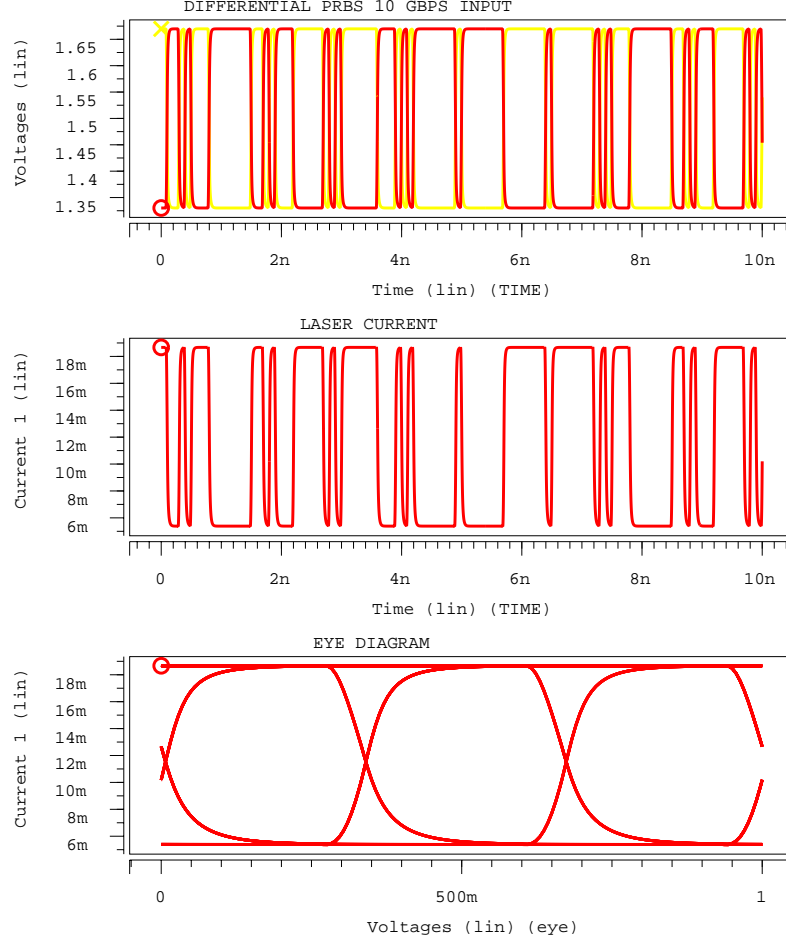


Figure 3.3. Simulated transient response of laser driver design at 10 Gbps with on-chip parasitics only.

After securing the preliminary simulation results, the voltage reference circuit is used to provide a stable dc voltage at the input node regardless of the variation of the power supply ripple. This circuit is based on the idea of using a negative feedback amplifier to keep the voltage across R , as shown in Figure 3.4(a). The implementation of this voltage reference circuit is illustrated in Figure 3.4(b). The operating principle of the circuit is briefly described as follows. If the current I_R and I_I are assumed as a constant value, the reference voltage (V_{ref}) is given by

$$V_{ref} = V_{GS1} + V_{GS2} \quad (3.3.1)$$

When the supply voltage VDD is increased, the current I1 is increased because of the increase of V_{SD3} . Consequently, V_{GS1} is increased. However, as the voltage across R is increased, V_{GS1} is decreased by the feedback network. Therefore, by setting the design parameters, a situation can be found in which V_{GS2} is decreasing that compensates for the increase of V_{GS1} . And results in a constant reference voltage (Vref) regardless of the change in the supply voltage [49]. The equations (3.3.2) and (3.3.3) show the relation between V_{GS} and V_{DS} if the channel-length modulation effect is included, also the situation necessary to achieve a supply independent reference voltage. Figure 3.5 shows dc simulations of the voltage reference circuit. A relative constant voltage is generated through compensation for supply voltage variation. This compensation occurs because as the supply voltage increases from zero to 4.5V, V_{GS2} is decreasing at the same rate as the increments of V_{GS1} .

$$V_{GS} = V_{TN} + \sqrt{\frac{2I}{\beta(1 + \lambda V_{DS})}} \quad (3.3.2)$$

$$\Delta V_{GS1} = -\Delta V_{GS2} \quad (3.3.3)$$

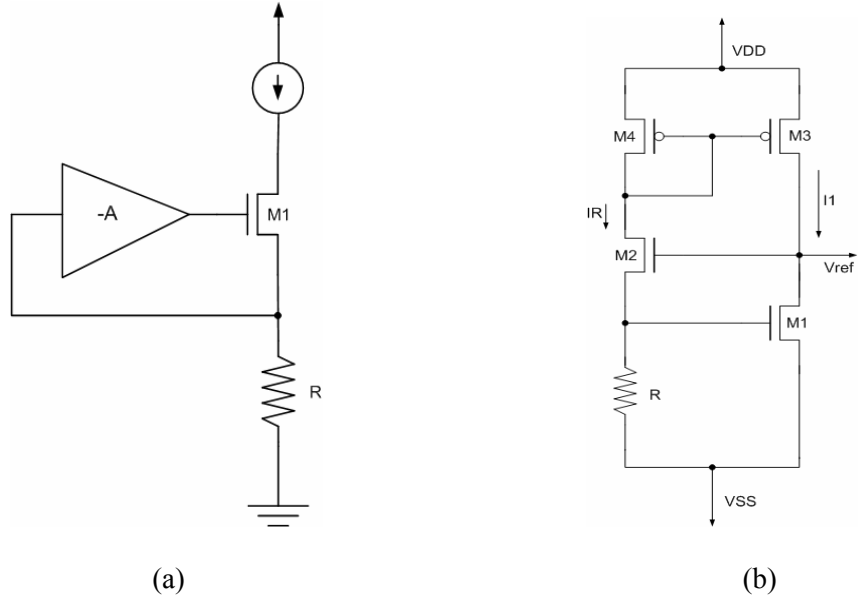


Figure 3.4. (a) A simplified supply-independent voltage reference circuit. (b) The implementation of a voltage reference circuit.

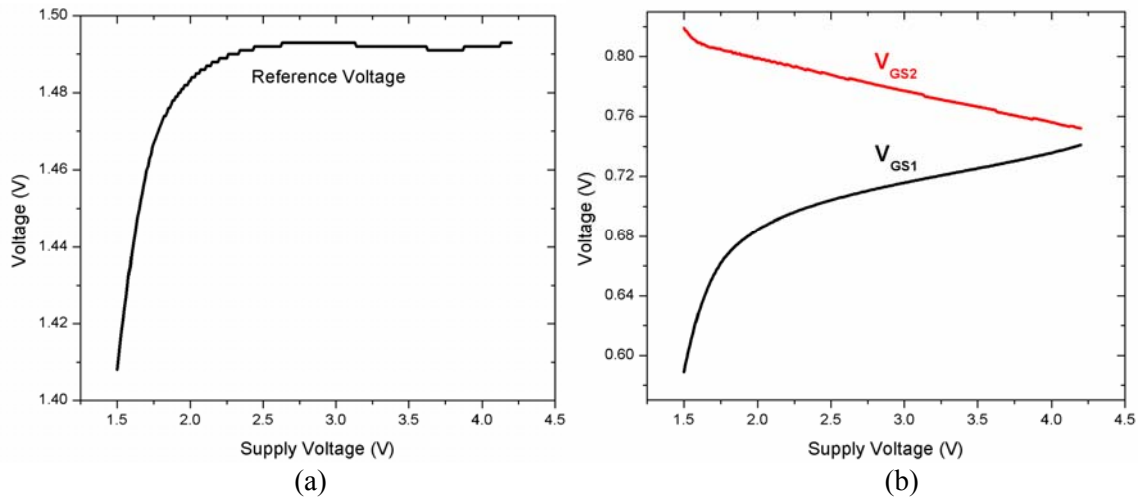


Figure 3.5. Simulation results of the voltage reference circuit. (a) represents the Vref and (b) represents the change of the Vgs1 and Vgs2. As the value of Vgs1 is increased, the Vgs2 is decreased, resulting in a compensated reference voltage.

One of the critical steps to design the laser drivers is arriving at an electrical equivalent circuit that is the equivalent of a laser diode so that the transient behavior common to laser diode can be accurately modeled. Most of researchers who have

reported on the design of laser drivers have focused mainly on the design. They have paid no heed to the electrical characteristics of laser diodes, assuming instead that the laser as a passive resistor [50-55]. However, considering the laser diode as a passive resistor require more conditions to drive laser diodes externally. For example, if a laser diode is assumed to be 50 ohm resistor and the value of the modulation currents of the resistor is 10 mA, then a voltage drop across the resistor is only 0.5 V. However, most of laser diodes require about 1.2 V for a standard edge-emitting laser and 1.5 V for VCSEL as a turn-on voltage. Therefore, the laser drivers need an external bias tee to provide the turn-on voltage. The utilization of external and expensive high-speed bias tee cannot be included in CMOS solutions. In addition, laser driver circuitry based on a more precise laser model can solve the difficulties in interfacing circuitry with a laser diode. Generally, laser drivers require complicated matching networks to compensate for overshoot and ringing. The more precise model a circuit designer has, the less effort required for matching networks. Therefore, more optimized systems can be obtained.

Figure 3.6 shows the electrical equivalent circuit model of a laser diode, including parasitic components applied into the series of simulations in this research. A model provided by a corporate research partner [56] is illustrated in the dotted blue box. However, the model was a small-signal model at a specific bias point that did not include the dc voltage drop between the anode and the cathode of diode and wire bonding. Because the simulations of a laser driver are required to have a large-signal model, the small-signal model was modified by adding a diode (D1) with optimized diode parameters. The other modification was the addition of inductance associated with

bonding wires so that in simulations the model would match the dc characteristics of the measured data of laser diodes.

The right side of Figure 3.6 shows the results of the optimization of the diode parameters to build the large-signal model of the laser diode. The black line represents the measured dc data of the laser diode, and the red line represents the dc characteristics of the simulated diode with the optimized diode parameters. As shown in the curve-fitting plot, the optimized diode parameters are matched into the measured data. Now, the modified large-signal model can be applied to the simulations. By using this model, the optical output of the laser is considered an electrical output that can be displayed by SPICE.

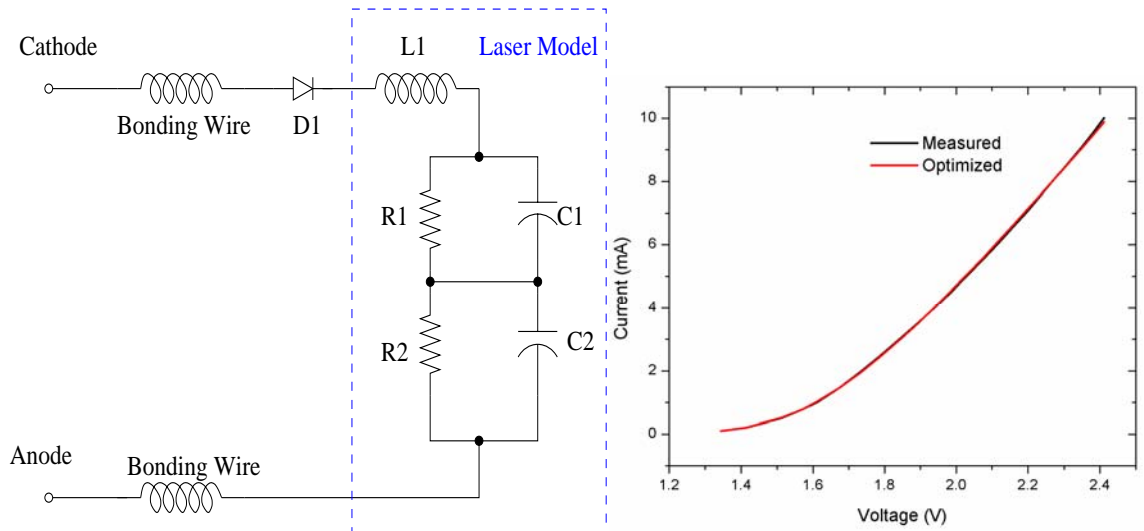


Figure 3.6. The equivalent circuit of a laser diode and parameter fitting for bias information.

After the schematic simulation results meet the desired specifications, the next step is to perform a series of simulations based on the layout. The considerations in the

layout of circuitry will be presented in the next section, and the layout-based simulation results will be discussed.

3.3.2 Layout-based simulations

As operating speed increases, design of high-speed CMOS circuits requires consideration of the effects of layout and packaging parasitics. This is important because the results of the results of schematic simulations are inaccurate because of missing parasitic components such as capacitances, resistances, diodes, and inductance, all of which often play an important role in circuit performance as operating speed increases [57, 58].

To emphasize the importance of the layout-base simulations, an example is shown in Figure 3.7 that compares the schematic-based simulations and the layout-based simulations. Parasitic effects including power supply inductance were added into the layout-based simulations. The first trace showed the eye diagram in schematic-based simulations. The second trace represents the eye diagram results of layout-based simulations. In comparing the results, the layout-based simulation showed more rise and fall time and signal degradations such as jitters and eye closure than the results obtained from the schematic-based simulations. Therefore, a layout-based simulation is vital to anticipating the real transient behaviors at high-speed applications and is one of critical stage in the implementing high-speed circuitry. In addition, the last eye diagram represents the transient response of the laser driver with a 50 ohm resistor. As shown in the eye diagram, the output current flowing resistors were not affected by parasitics or

packaging effects; therefore, simulations with a more accurate equivalent model are a much better approach to implementing laser drivers.

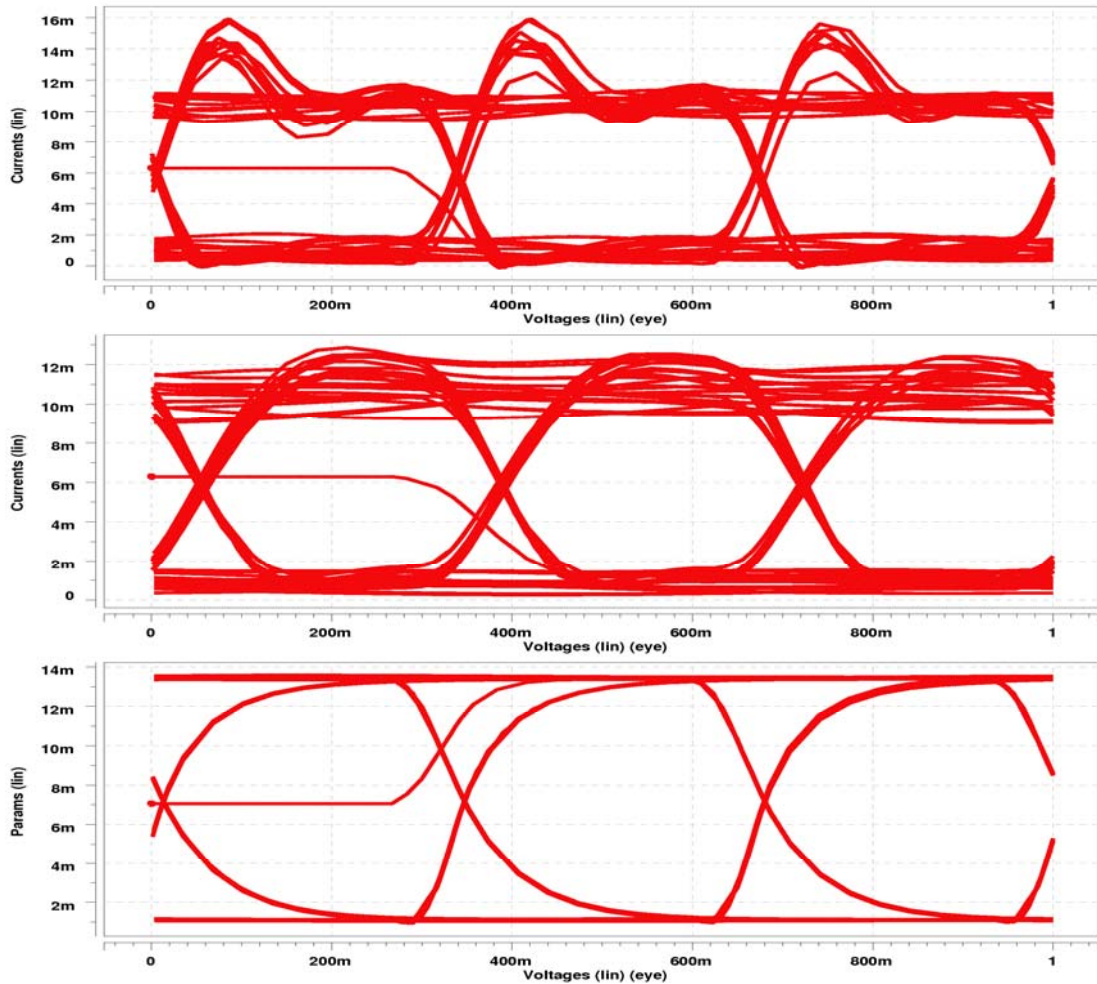


Figure 3.7. Comparisons of layout-based simulation vs. schematic simulations. The top trace represents the schematic simulation. The second trace represents the layout-based simulations. The last trace indicates the 50 ohm load laser driver instead of a laser model.

Since the layout could generate big differences in schematic simulations as shown in previous simulations, the laser driver was laid out carefully to minimize unwanted

behaviors such as common-mode noise, signal delay, and crosstalk. The transistor size has been optimized for high-speed and relatively large current operation, and a multiple finger structure has been used to reduce the input capacitances, which are the dominant factor of switching delay. Matching the performance of two input transistors is very important to overall laser driver operation. Thus, input transistors M1 and M2 have identical shapes with respect to signal path. Both M1 and M2 transistors of a differential pair in a laser driver consist of M1A and M1B, and M2A and M2B, respectively. At the upper left corner, a matching diode also included in the layout. An M4 transistor shown in Figure 3.1 is divided into two M3A and M3B, which are identical to create a symmetrical layout. Although the surroundings seen by M1 and M2 are different because of the presence of current mirrors to provide bias and modulation current and matching diodes, matching performance can be normally improved by making the intermediate surroundings identical. This general rule has been applied repeatedly to all components. The symmetric structure of the input transistors along the signal path is shown in Figure 3.8.

The metal lines and vias have the current density rule in the process. Therefore, the width of metal lines and the number of vias should be carefully optimized. For example, the width of the power supply rail should be more than 20 μm for the current driving capacity of 20 mA. If 10 mA currents flow through a five μm -wide transistor, the transistor should have a multiple finger structure to keep the current density rule. However, making every metal line wide unnecessarily wastes space because as line width increases, the parasitic capacitance and resistance also are increased, which can significantly degrade performance or generate unwanted noise. Therefore, it is necessary

that the layout designer should track all currents at every node to meet the current density rule, and the metal width and number of vias should be optimized for reliable operations in high-speed circuitry. To minimize the degradation of the input and output signal resulting from the packaging effects at 10 Gbps or higher speed, Cascade 100 μm pitch-to-pitch ground-signal-ground-signal-ground (GSGSG) probes are used at the input and output. These probes are supposed to operate up to 40 GHz.

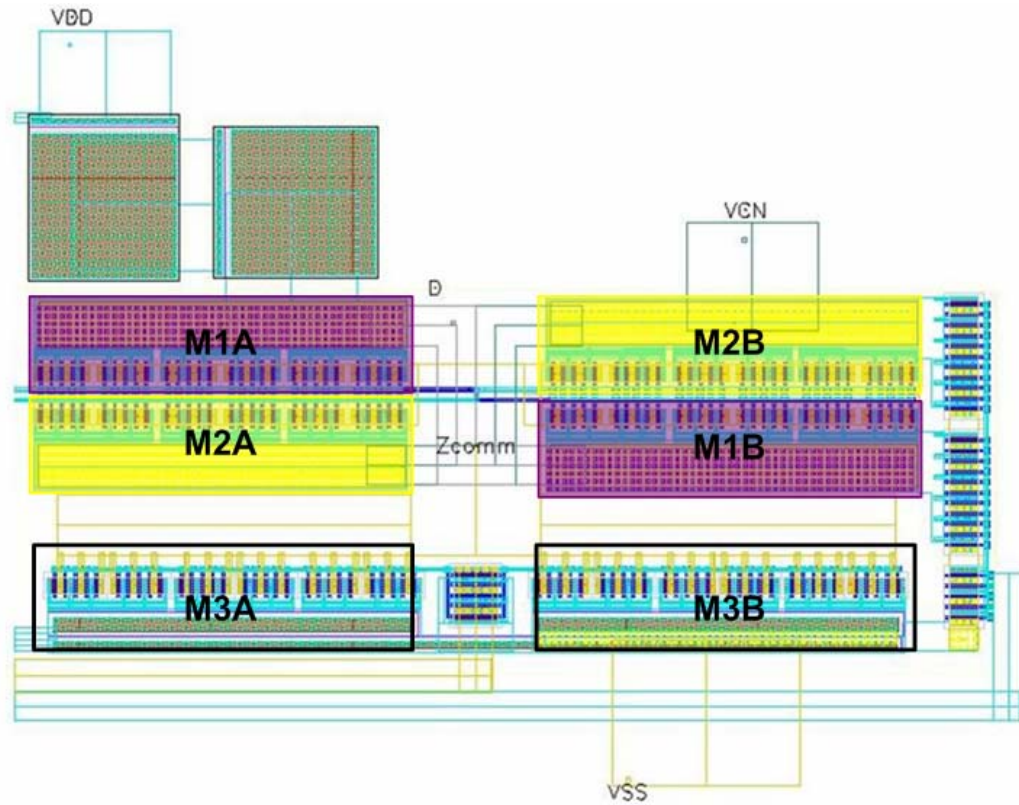


Figure 3.8. Differential switch divided into two parts to make a symmetrical layout along the signal path.

Electrostatic discharge (ESD) protection circuits are connected to all pads. A block diagram of the ESD protection circuit is illustrated in Figure 3.9. The current flow

is always in the diode's forward direction and positive ESD pulses are clamped to ESD_VDD, and negative ESD pulses are clamped to ESD_VSS. A screen capture of the laser driver layout is shown in Figure 3.10. In addition, a screen capture of the whole chip image is shown in Figure 3.11. Three types of laser drivers are located in the middle of the chip, and a red rectangle in the middle represents the integration site for thin film devices. ESD circuits surround the whole chip and the transimpedance amplifier is located in the left half of the chip. The right side of Figure 3.11 shows the test structures for characterization of transistors.

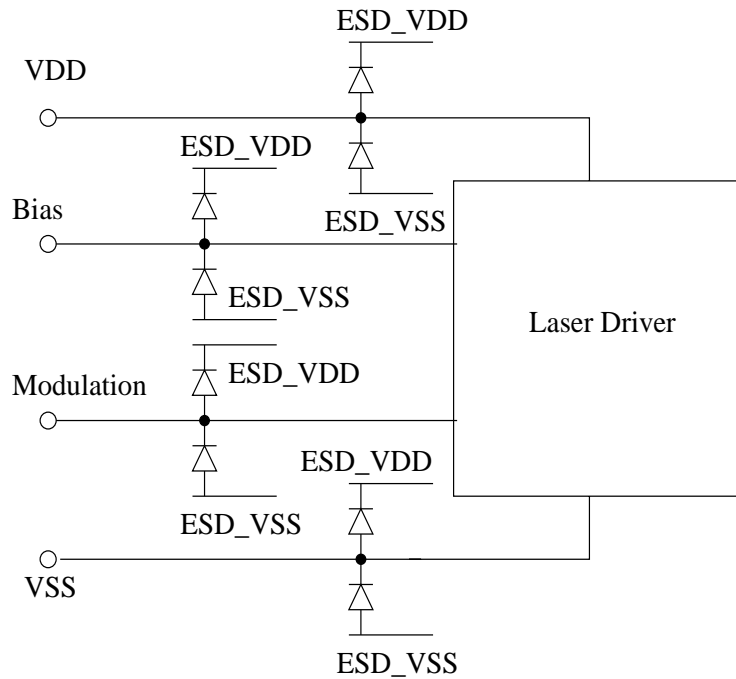


Figure 3.9. Block diagram of ESD circuitry.

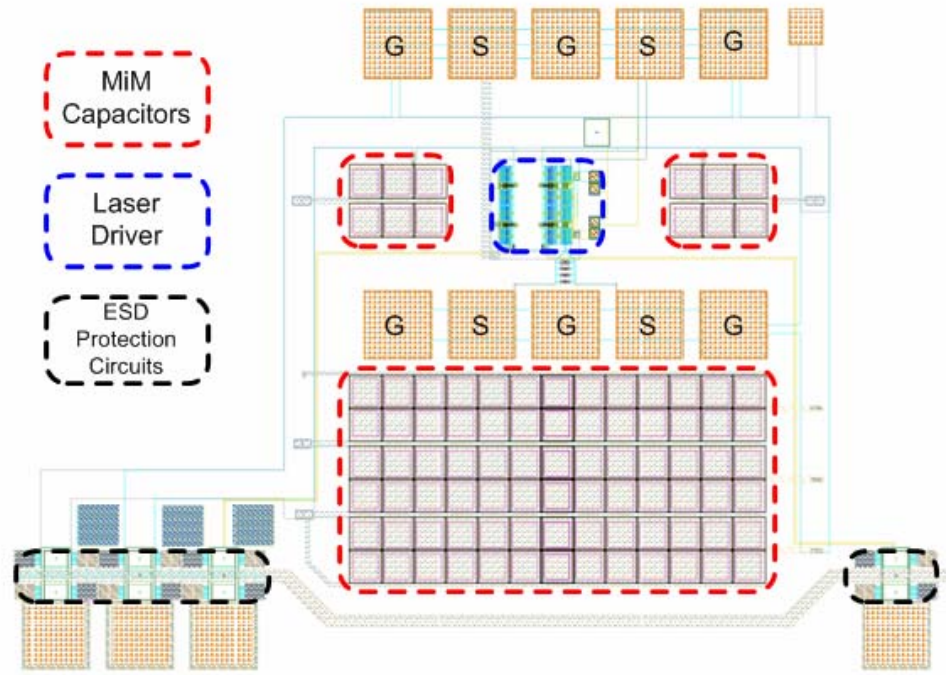


Figure 3.10. The layout of designed laser driver circuits with ESD circuitry, GSGSG probes, MiM capacitors

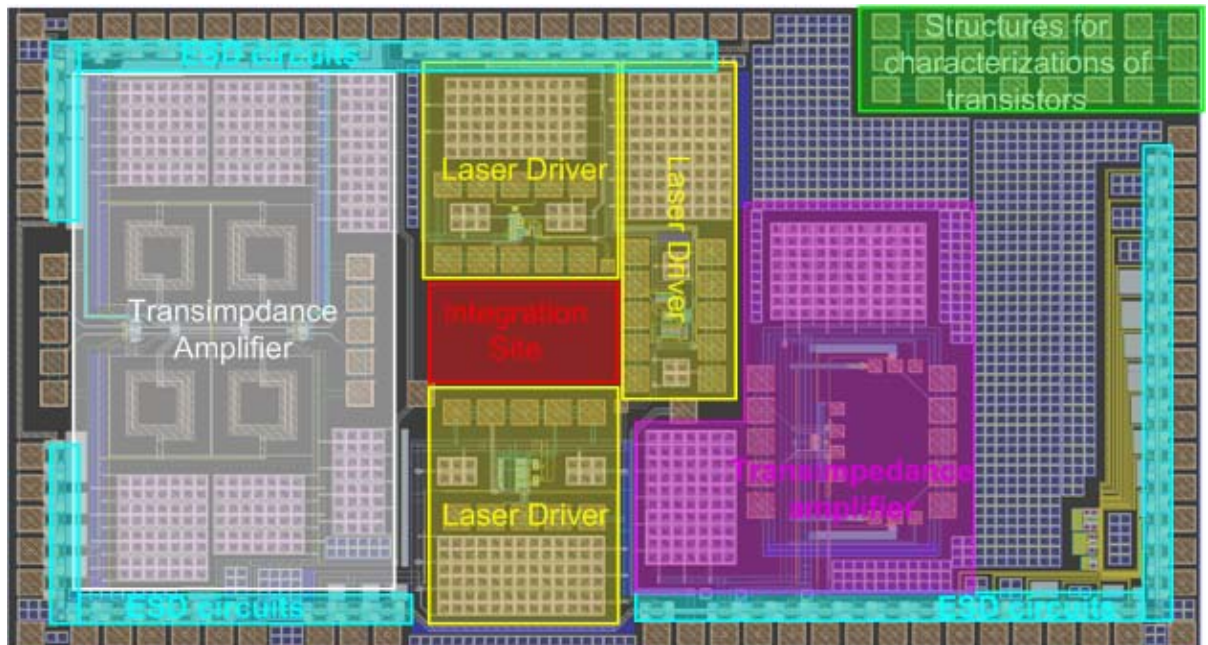


Figure 3.11. The layout out of whole chip, which includes laser driver, transimpedance amplifier. The empty space in the middle of chip is for a laser and detector integration site.

The structure consisted of two sizes of transistors with 10 μm and 20 μm of channel width. In addition, they can be measured by microwave on-wafer probes. Since there are process variations, these structures could be one of the sources to verify the deviations from expected performances of the model used in simulations. Therefore, it is very helpful to find the optimized conditions for circuit operations when the circuit is tested. The integration site in the middle of chip is just empty space when thin film devices are integrated onto the CMOS chip.

Moreover, the TSMC 0.18 μm mixed-signal CMOS process has a minimum density rule, which means each metal and poly layer density is much greater than or equal to a certain percentage that is derived from total chip area. For example, a minimum poly layer should be over 14 % of the chip area. The density of a layer in a particular region is calculated as total area covered by drawn features on that layer divided by total the chip area. The minimum density rule came from a process using chemical-mechanical polishing (CMP) to achieve planarity for a fine-featured process. Therefore, to meet the minimum density rule, the right side of the chip shown in Figure 3.11 was filled with dummy metal and with poly layers shown as a blue rectangle. The next step for the layout-based simulations is to extract a SPICE file from the drawn layout using the Cadence layout tools. The extracted SPICE file, including the parasitic components, is attached to the Appendix. In addition to the parasitic components, the packaging parasitics should be included in the simulations. In Figure 3.12, the block diagram of the packaging parasitic simulation is illustrated to determine the value of decoupling capacitors to suppress the delta I noise, which cannot be completely removed by differential topology alone.

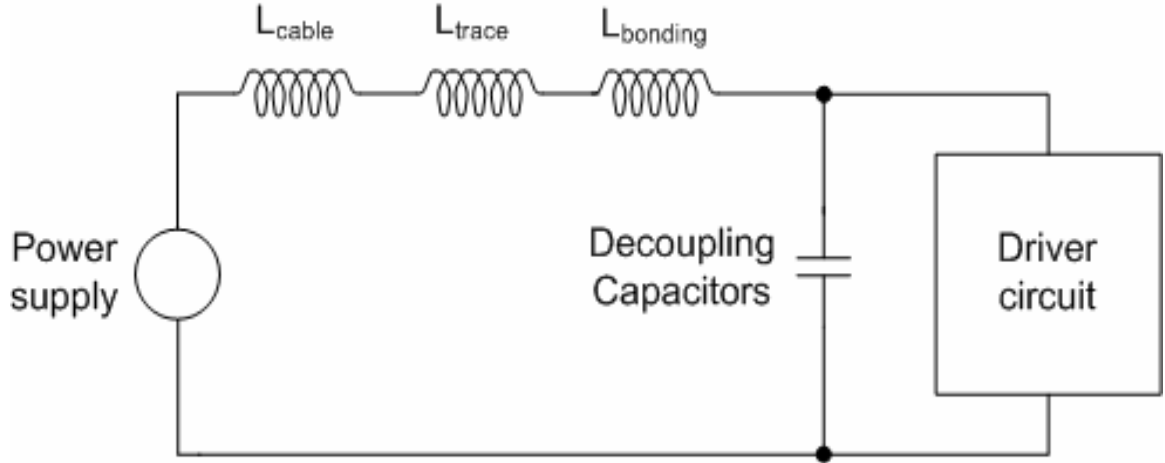


Figure 3.12. Simplified circuit schematic: The circuit model includes parasitic inductance, L_{cable} on cable, L_{trace} of the power line on the PCB, and L_{bonding} on wire bonding.

Figure 3.13 shows the transient response with packaging components in which the parasitic inductance was assumed to be 10nH for the power supply interconnect (L_{cable}), 5nH for traces on the test board (L_{trace}), and 2nH for the bonding wires (L_{bonding}). The top trace represents the output current of the laser driver, the second trace is the eye diagram of the laser current, and the last trace represents the voltage fluctuation in power supply rails. The eye diagram in Figure 3.13 shows that circuit performance is degraded significantly because of these packaging and parasitic components. The current fluctuations in power supply rails have about 10 mA_{p-p}. To solve the problem of degradation of signal integrity, a decoupling technique was used in this research.

Decoupling capacitance is the major consideration in controlling impedance and noise on power supply. The effectiveness of the decoupling capacitors can be proven by a simple equation.

$$I = C \frac{dV}{dt} \Rightarrow \frac{dV}{dt} = \frac{I}{C} \quad (3.3.4)$$

As the value of the decoupling capacitance C is increased, the voltage fluctuation dV/dt is decreased. Therefore, the decoupling capacitor between the power supply rails can reduce the power supply ripple. Capacitors used for decoupling purposes are only capacitive at low frequencies. At high frequencies, the capacitor becomes an inductor whose inductance is related to the path that current takes through the capacitor, almost as if it were made of a conductive material. Resonance occurs at frequency

$$f = \frac{1}{2\pi\sqrt{LC}} \quad (3.3.5)$$

where L and C are the value of capacitance and inductance respectively. The impedance of the capacitor at resonance is the equivalent series resistance (ESR). A decoupling capacitor is modeled as a resistor, capacitor, and inductor in series, as shown in Figure 3.14. Therefore, the value of the capacitors should be carefully chosen because capacitors also have their own parasitic inductance and resistance.

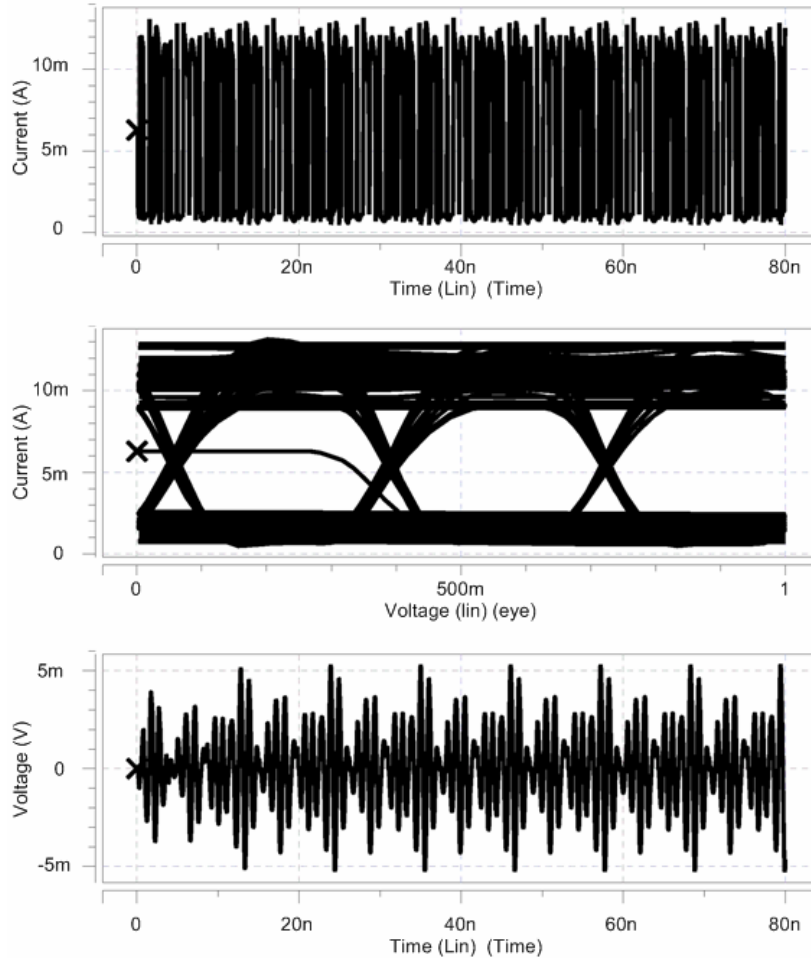


Figure 3.13. Transient simulation with line parasitics and no decoupling capacitors. The top trace represents the output current of laser diode, the second trace shows the eye diagram of the laser driver, and the last trace represents the voltage fluctuation of the power supply rails.

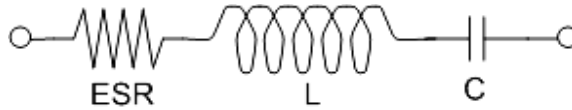


Figure 3.14. Equivalent circuit model of capacitor.

To determine the value of the decoupling capacitor, it is necessary to estimate the instantaneous current required when all the outputs of an IC switch from LOW to HIGH.

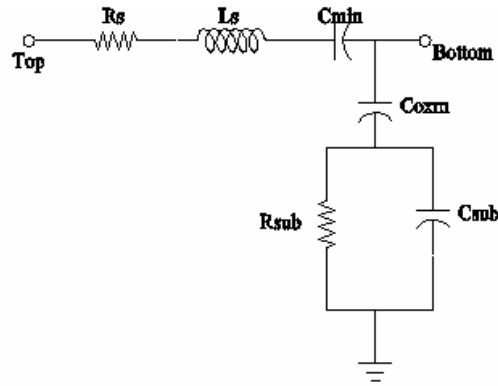
The amount of capacitance required to maintain the power supply to within some ripple specification is calculated by

$$C = \frac{dQ}{dV} = \frac{I}{2f_c \times V_{dd} \times n} \quad (3.3.6)$$

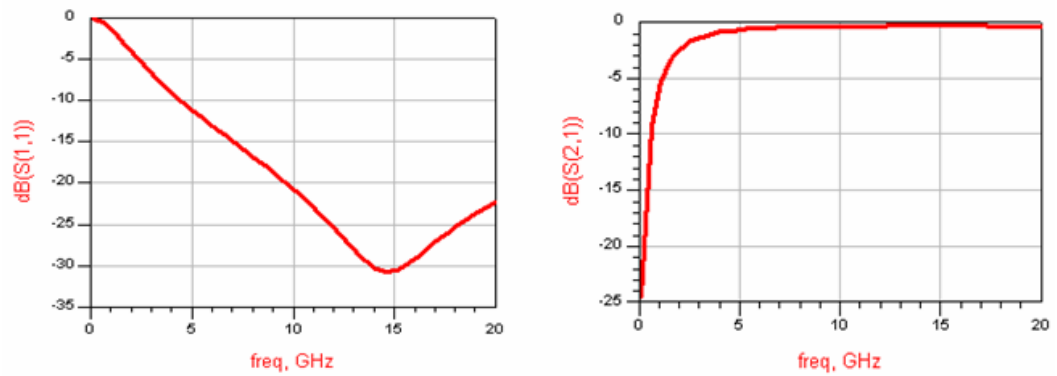
where dQ is the charge per burst, f_c is the clock frequency, V_{dd} is the power supply voltage, and n is the fraction of ripple voltage allowed.

In this research, an on-chip metal-insulator-metal (MiM) based on the equivalent model provided by the MOSIS foundry, shown in Figure 3.15 (a), was used as the decoupling capacitor. Here, R_s , L_s , and C_{min} represent the general capacitor model shown in Figure 3.14. Moreover, C_{oxm} , R_{sub} , and C_{sub} were added to represent the substrate effects of the chip. Figure 3.15 (b) shows the s-parameter simulation with this capacitor model. The bottom plot shows 14 GHz of resonance frequency of this capacitor, which is effective as a capacitor below 14 GHz. The top plot represents the broad coupling at high frequency range.

Figure 3.16 and Figure 3.17 show the frequency response of the laser driver with and without decoupling capacitors, respectively. By using 90 parallel MiM capacitors for a total capacitance of around 85.59 nF, a decoupling technique was employed with the laser driver. As shown in Figure 3.16, the packaging components created huge peaks of output currents at a relatively low frequency range, and Figure 3.17 shows the decoupling technique effectively suppressed the peaking. In addition, the frequency response shows the broadband operations of the laser over 10 Gbps.



(A)



(B)

Figure 3.15. (a) Equivalent circuit of MiM capacitor. (b) the MiM capacitor simulated s-parameters, S21 (top) shows broad coupling and S11 (bottom) shows the resonance frequency of the capacitor.

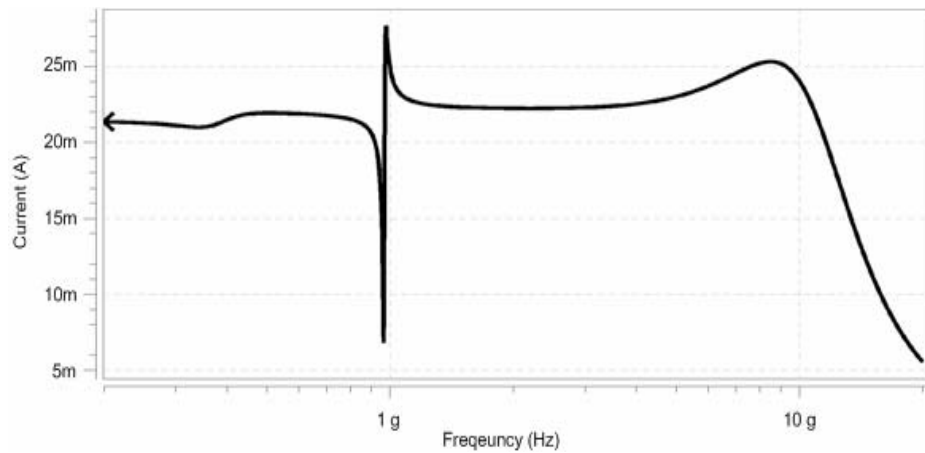


Figure 3.16. Frequency response of the laser driver without decoupling capacitors.

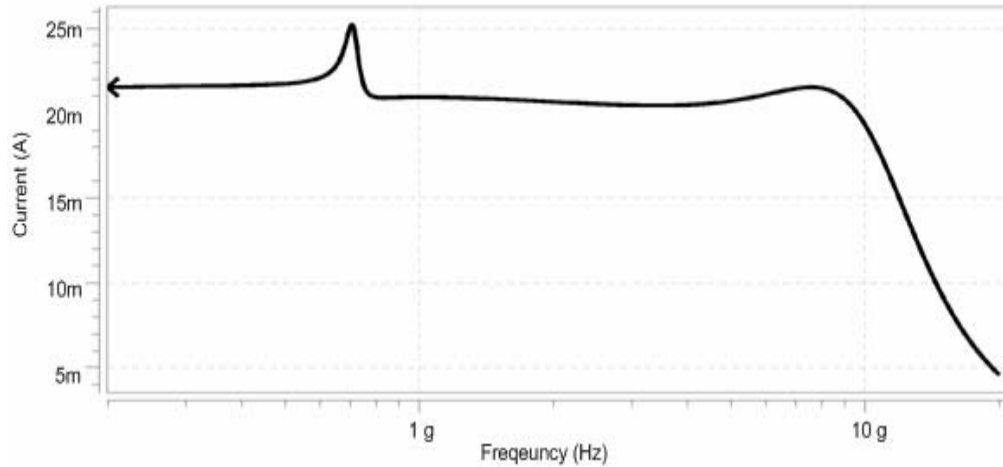


Figure 3.17. Frequency response of the laser driver with decoupling capacitors.

The transient response at 10 Gbps with decoupling capacitors is shown in Figure 3.18. The first trace represents the input voltage of the laser driver, the second one shows the eye diagram of the output currents, and the third one shows the voltage fluctuation in power supply rails. By the decoupling capacitors, compared to the eye diagram in Figure 3.13, the eye diagram shown in Figure 3.18 has larger open eyes, which means the laser driver can operate at 10 Gbps. In addition, decoupling capacitors suppressed by about 70 % the power supply ripple shown in the last trace.

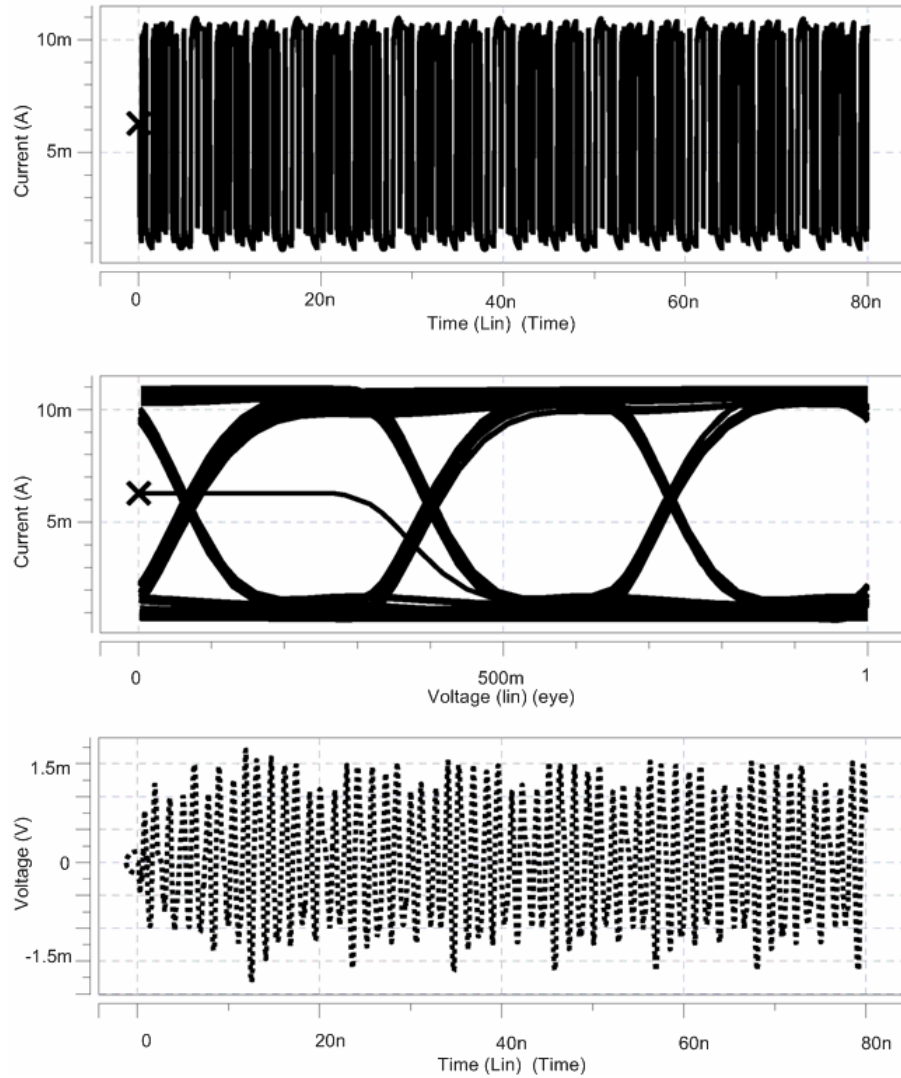


Figure 3.18. Transient simulation with MiM capacitors and line parasitics at 10 Gbps. The top trace represents the output current of laser diode, the second trace shows the eye diagram of the laser drivers, and the last trace represents the output voltage fluctuations of power supply rails.

Temperature effects also should be considered to ensure that the circuit works well at high temperatures. This is necessary because the integrated circuits slow as the temperature increases because of mobility variation. Figure 3.19 shows the transient response of the laser driver with temperatures of 27 °C, 100 °C, and 200 °C. The output

becomes little bit slower as the temperature increases but still works within the design specifications, as indicated by the open eye diagram at 200 °C.

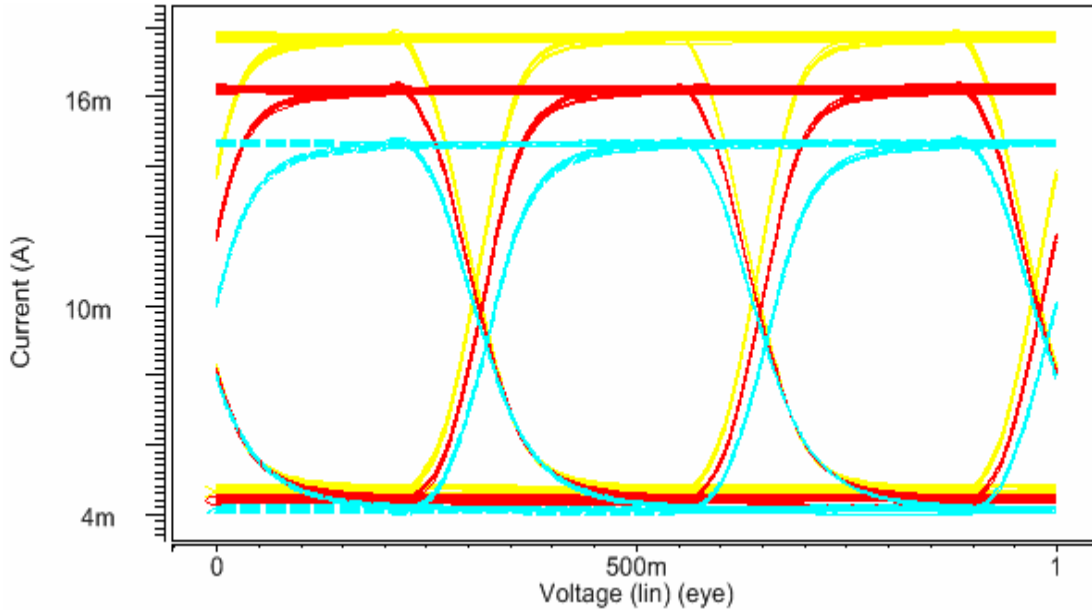


Figure 3.19. The eye diagram of laser driver at 10 Gbps with the temperature variations. The yellow line is at 27 °C, the red line is at 100 °C, and the cyan line is at 200 °C.

3.4 Experimental Results

3.4.1 Test setup

The laser driver circuits were fabricated using a TSMC 0.18 μm mixed signal/RF process using non-epitaxial wafers. This CMOS process has a silicide block, thick gate oxide (3.3V), NT_N, deep n well, Thick Top Metal (inductor), and MiM options [59].

Figure 3.20 illustrates the block diagram of measurement setup for testing the laser driver. An HP 71512B Bit Error Rate Tester (BERT) generates different modes of pseudo random bit streams (PRBS) and measures the probability of a transmitted data

error rate through the device under test. Keitley 236 and 238 source measurement units (SMU) provide precise modulation and bias currents and measure voltage or current.

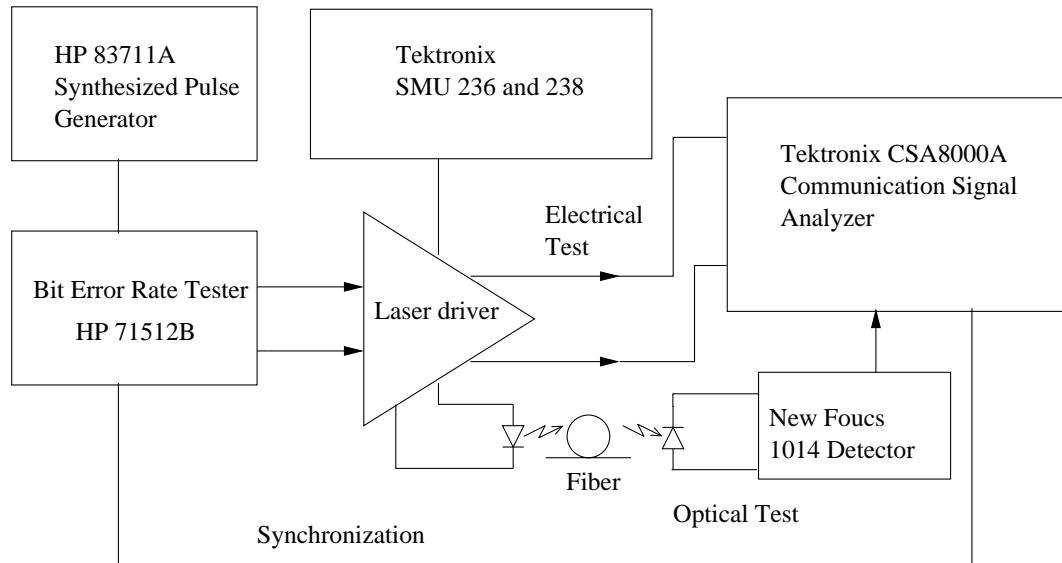


Figure 3.20. Block diagram of test setup.

A New Focus 1014 Photodetector measures the optical signal output from the laser diode. In addition, a Tektronix CSA 000A oscilloscope monitors the output of the laser and measures the eye diagram and pulse waveforms.

A test board for the laser driver is fabricated through a printed circuit board manufacturer. Figure 3.21 shows the layout of the test board and Figure 3.22 shows the momentum simulations of the designed board. The transmission characteristic, $S(2,1)$, shows that 3 dB frequency of the trace on the board is over 5 GHz as shown Figure 3.23.

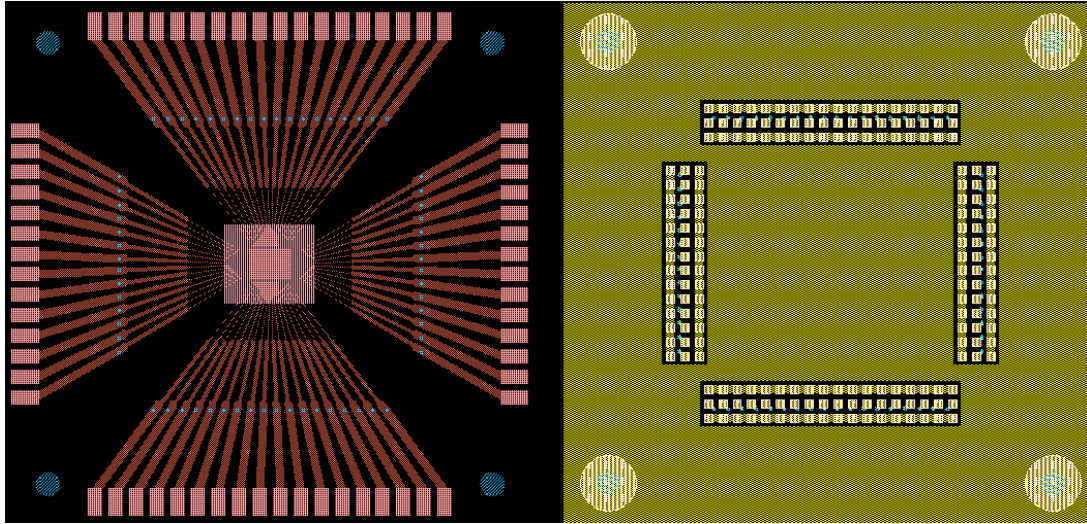


Figure 3.21. Layout of test board of the laser driver.

Figure 3.24 is a picture of the fabricated FR4 PCB test board. This test board is only used to provide the power supplies, dc bias, modulation current, and ESD power supplies to avoid signal degradation at high frequency. The input and output will be performed by probing with GSGSG probes. The box on the backside of the test board indicates the external decoupling chip capacitor site in case internal on-chip capacitors are not enough to suppress the supply noise. The chip is mounted in the center of the PCB test board, and then all pads are wire-bonded to the board. Figure 3.25 shows a microphotograph of the laser driver with wire bonding.

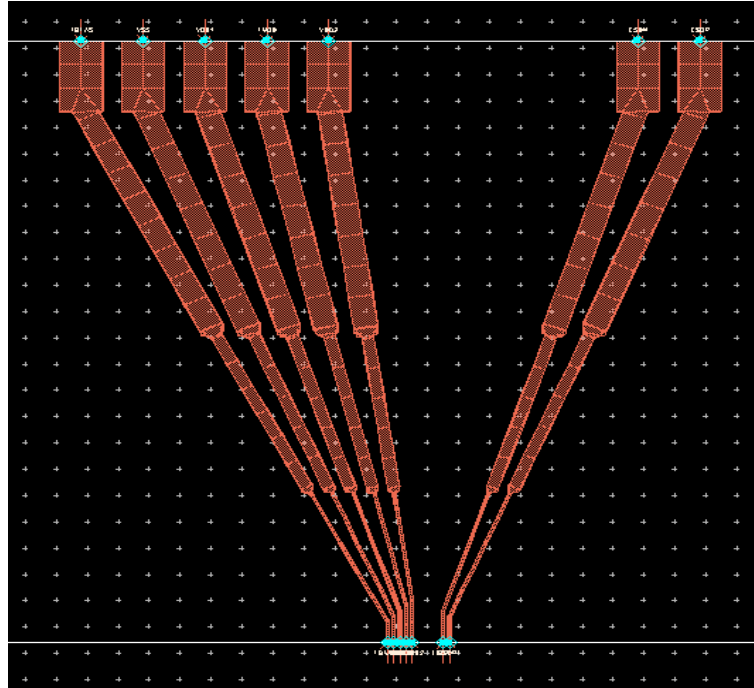


Figure 3.22. Momentum simulations of the FR4 test board with HPADS.

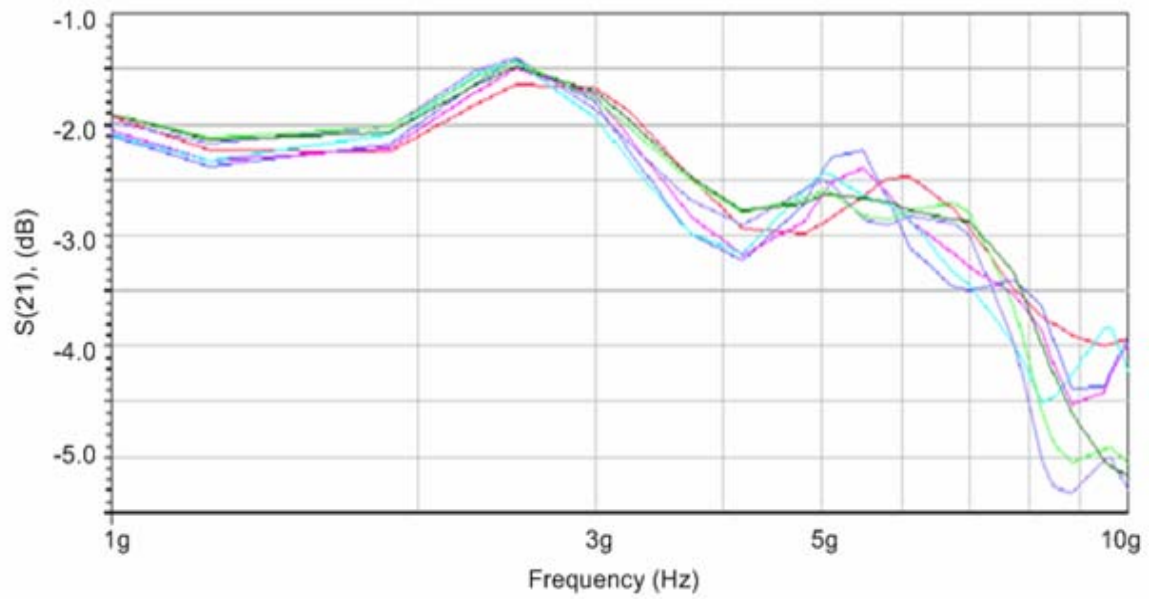


Figure 3.23. Transmission characteristics of the traces on the test board.

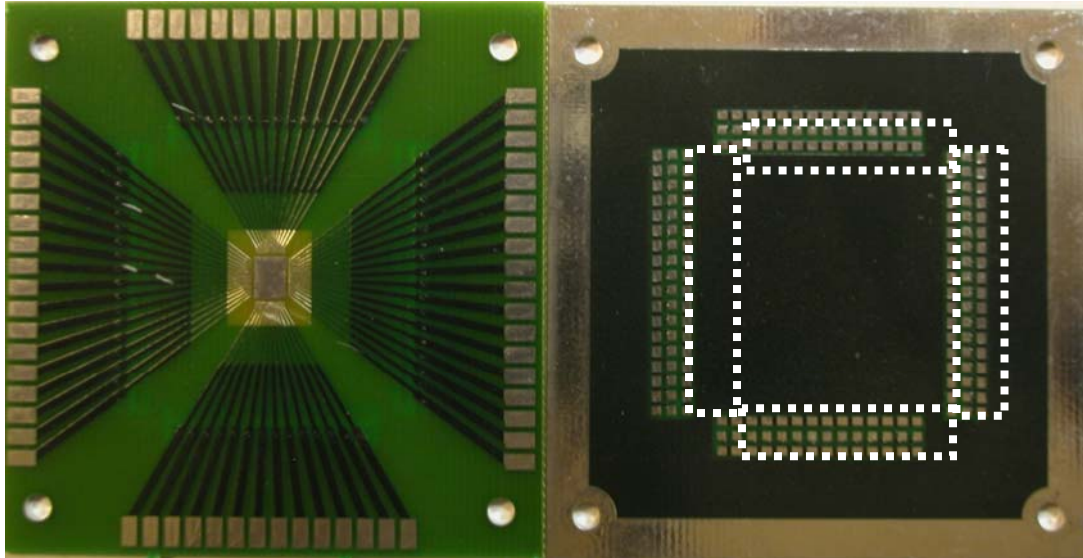


Figure 3.24. Picture of test board.

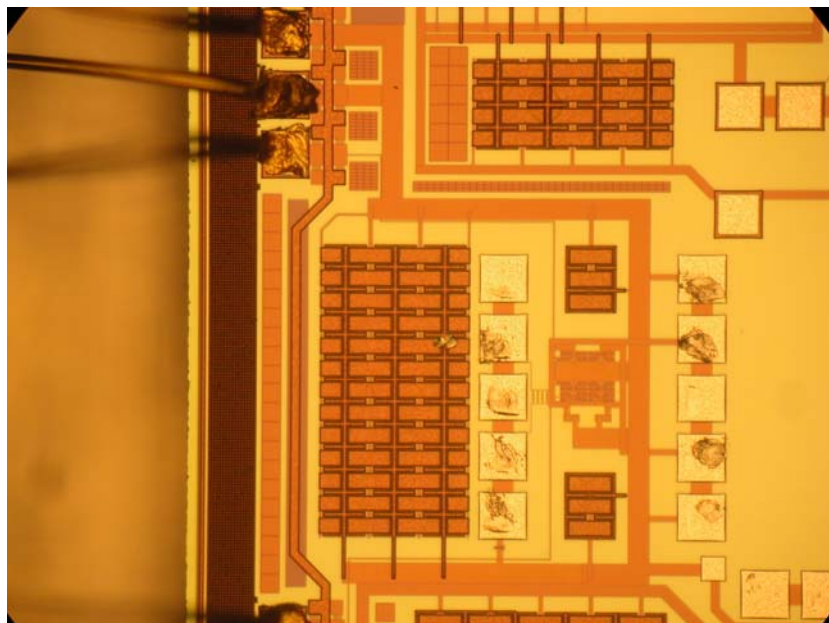


Figure 3.25. A microphotograph of the wire-bonded laser driver.

3.4.2 Measurements

An eye diagram and a pulsed waveform of the laser driver were measured using $2^{11}-1$ non-return to zero (NRZ) PRBS input, which simulates the real data pattern specified in SONET specifications. The target operating speed is more than 10 Gbps. Bias currents and laser dc currents were adjusted to achieve optimized operating. Tektronix communication analyzer (CSA 8000A) was used as an electrical output and captured the eye diagrams for the operating laser driver.

Figure 3.26 and Figure 3.27 represent the measured eye diagram at 1 and 5 Gbps to verify the broadband operation of the laser driver. Figure 3.28 and 3.29 show the measured pulsed waveforms and the eye diagram at the electrical output of the laser driver, respectively. The input signal is a $2^{11}-1$ pseudorandom bit sequence (PRBS) at 10 Gbps with 800 mV_{p-p} amplitude. The amplitude of the signal output is 350 mV_{p-p} into a 50 ohm load with bit error rate greater than (BER) of 3.11×10^{-14} . The overall power consumption is 65.5 mW. The SONET OC-192/STM-64 transmitter mask was provided for comparison in Figure 3.30. It shows that the output is good enough to meet the eye pattern specifications of SONET OC-192/STM-64 recommendations. Figure 3.31 shows the measured eye diagram at 12 Gbps. It showed the laser driver could be operating at 12 Gbps. The details of optimized bias information and specifications at 10 Gbps are summarized in Table 3-2.

Table 3-2. Optimized bias conditions and specifications of the laser driver.

Specifications	Conditions
VDD	2.5 V
VSS	0 V
Laser modulation	up to 12 mA
Power Dissipation	65.5W
Speed	over 10 Gbps
BER	$> 3.11 \times 10^{-14}$
Area	825 $\mu\text{m} \times 613 \mu\text{m}$

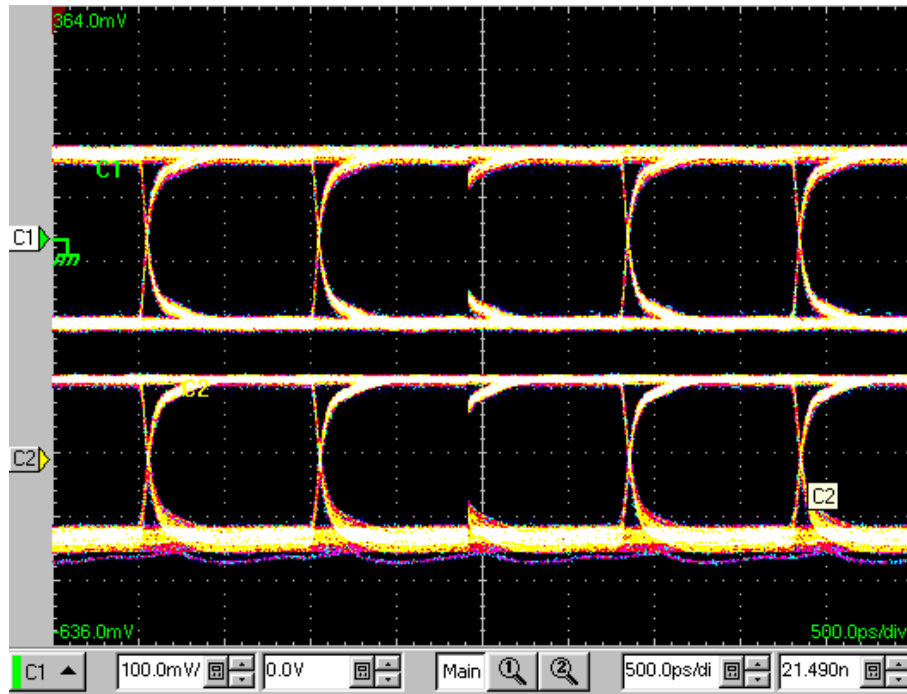


Figure 3.26. Measured eye diagram at 1 Gbps.

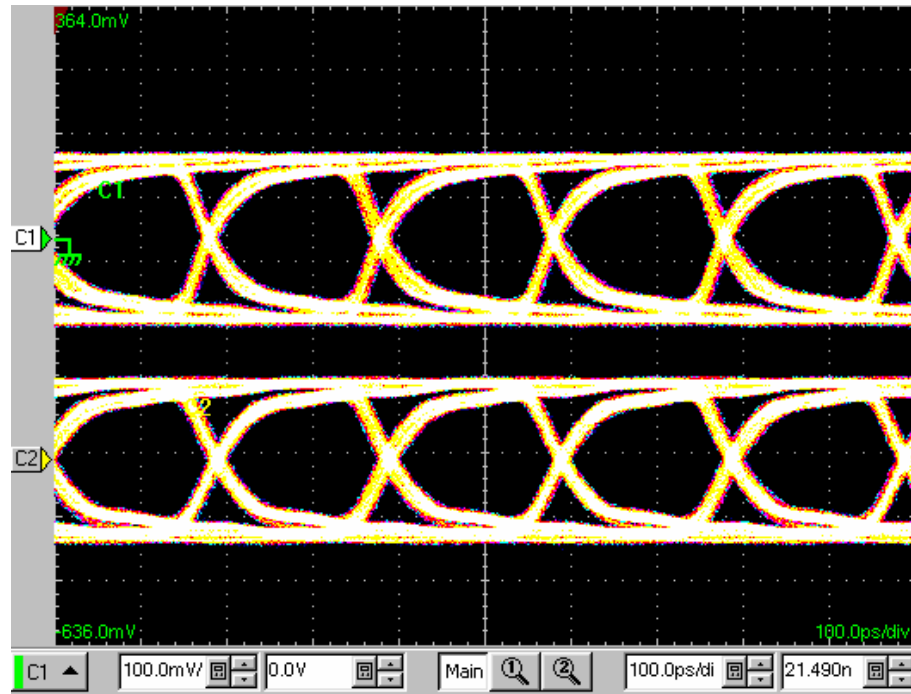


Figure 3.27. Measured eye diagram at 5 Gbps.

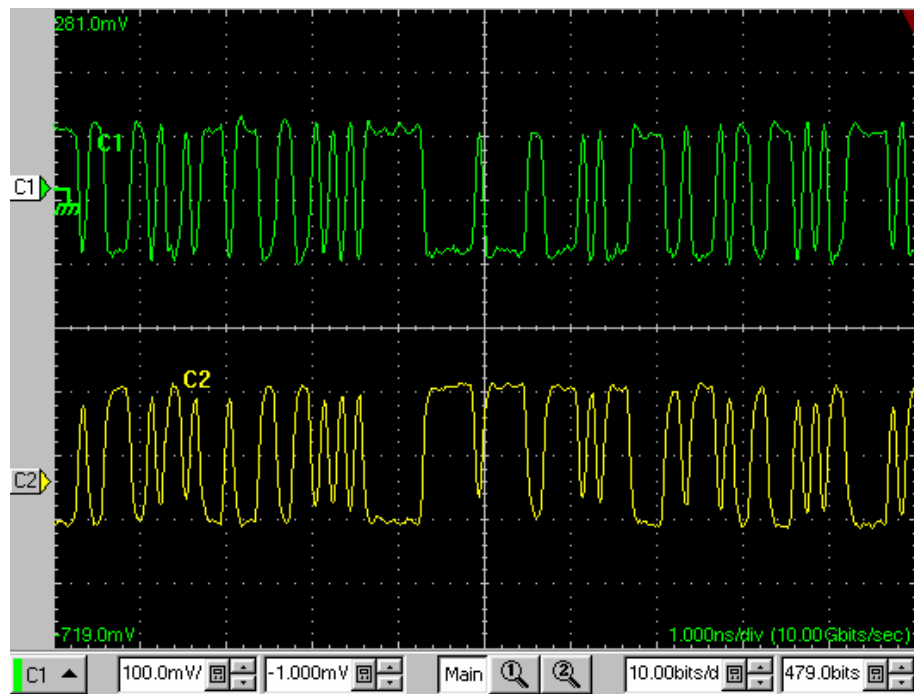


Figure 3.28. Electrically measured output data stream at 10 Gbps.

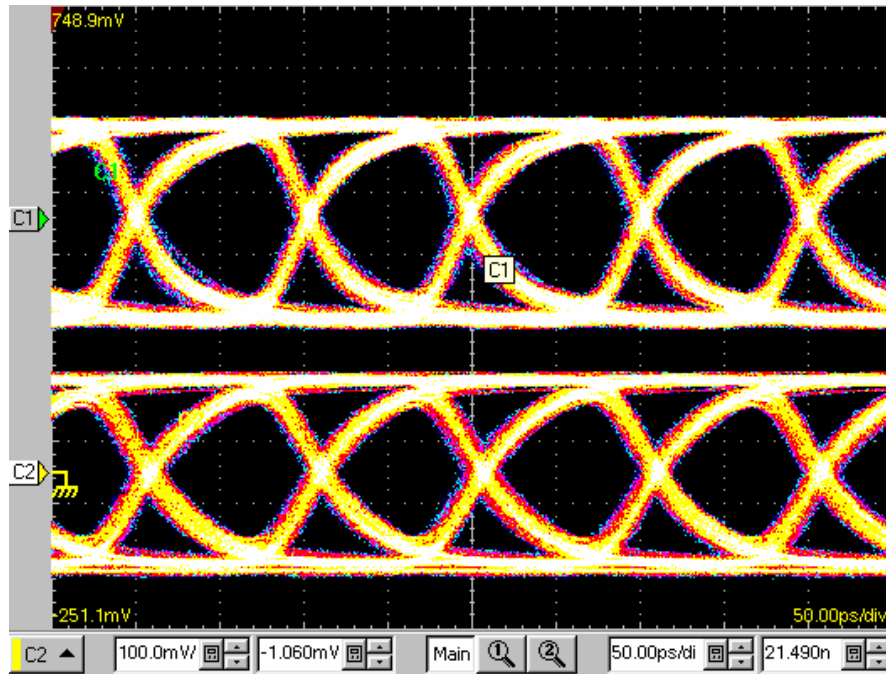


Figure 3.29. Electrically measured eye diagram at 10 Gbps.

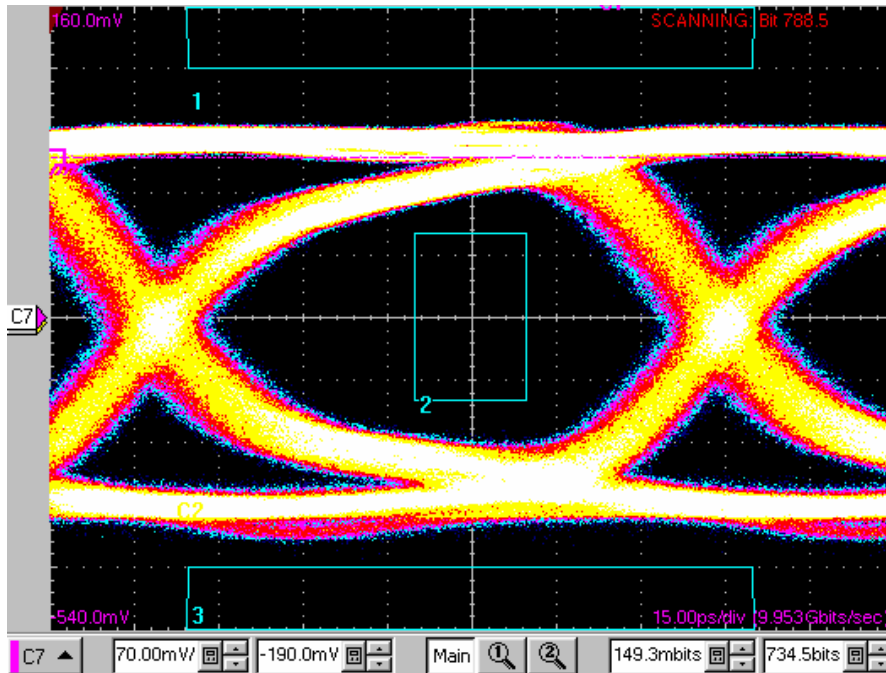


Figure 3.30. Eye diagram with SONET OC-192 eye mask.

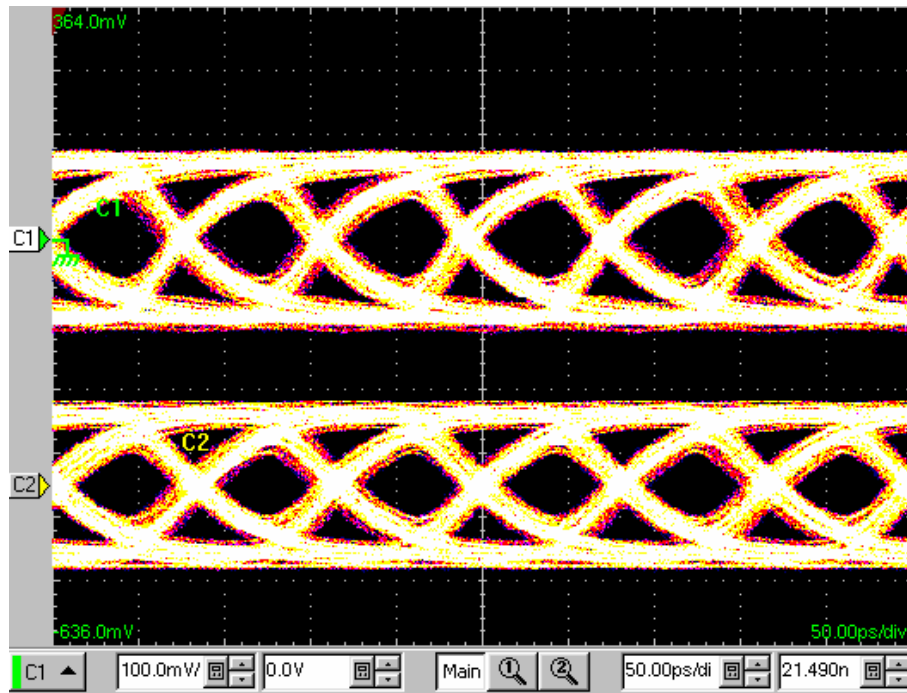


Figure 3.31. Electrical measured eye diagram at 12 Gbps.

CHAPTER IV

THIN FILM LASER INTEGRATION ONTO CMOS

CIRCUITS

A high-speed optical transmitter consists of a laser driver circuit and a laser diode as mentioned in Chapter II. This chapter discusses thin film integration in the implementation of optical transmitters. The advantages of the approaches are followed and compared with other solutions used to implement the optical transmitters. Then, thin film laser devices fabricated at Georgia Tech are discussed.

4.1 Introduction

A smart pixel is defined as an optoelectronic structure composed of electronic processing circuitry enhanced with optical inputs and/or outputs [60]. The basic concept of a smart pixel is to integrate both electrical systems and individual optical device on a common chip to take advantage of electrical circuit complexity and the speed of optical devices [61]. Arrays of these smart pixels would bring with them the advantage of parallelism that could provide new opportunities to utilize dramatically greater bandwidths. A number of approaches have been studied to implement smart pixels. The most common approaches in use today are monolithic integration and hybrid integration.

Monolithic integration is a technique that allows both electronics and optical devices to be integrated in a common semiconductor material in a single growth process or by utilizing a re-growth technique [61]. This approach, potentially, would produce

high-performance smart pixels. The speed and noise performance of optoelectronic devices can be improved by monolithic integration because of the reduction of parasitic components. A further advantage of monolithic integration on a compound semiconductor comes from having much better heat-conduction than silicon technology, an advantage can directly improve the power efficiency of individual components such as lasers and transistors. In addition, the monolithic integration of many elements on a single chip makes the number of components required for system construction much less than when discrete devices are used. This would result in more compact and more reliable system.

However, two major challenges remain before these advantages result in a mainstream technology: simultaneous optimization of both the optical devices and the electronic circuitry and a general lack of maturity of compound semiconductor technology. The optimization techniques used for electronic circuitry to provide increased functionality are not the same as the optimization techniques required to produce high-quality optical devices. Therefore, trade-offs must be made that reduce some performance metric associated with the overall system. If the re-growth technique is used, the large difference in lattice constants between direct-gap III-V compounds and silicon has prevented the monolithic integration of semiconductors with silicon-based electronic circuitry. Moreover, it is necessary to develop new techniques or complex processing to implement the monolithic optical system.

The second challenge, technological maturity, is associated with the differences in the technological maturity of silicon processes compared with those of compound semiconductors. Mainstream silicon-based technology such as CMOS has been

successfully developed during the past several decades and led to tremendous technology advancement. Compound semiconductors, however, remain a relatively expensive, niche technology with lower levels of integration than a state-of-the-art the silicon CMOS process. As a result, the tools necessary for designing, modeling and fabricating compound semiconductor devices are not as well developed as those used for silicon devices. These two challenges severely limit the usefulness of monolithic integration as a common integration approach for smart pixel technology.

Hybrid integration technology, therefore, must be considered because of the lack of a completely monolithic solution to the problem of fabricating optimized optoelectronic devices. In hybrid integration technology, optical devices are developed and optimized separately from the electrical circuitry. There are a number of approaches to hybrid integration. Conventional wire bonding has been used because this scheme is relatively simple and easy. However, its applicability is limited to chips with a relatively small number of channels and, moreover, the parasitic components associated with the wire bond pads, interconnect traces, and inductance of wires significantly degrade the performance of the whole system.

One promising approach for hybrid integration is flip-chip bonding. Flip-chip bonding was introduced into mainstream electronics by IBM more than thirty years ago [62] and is used today as a quite common commercial bonding technology to take advantage of the very high-density area array interconnections, the self-aligning nature of the bonding process [62], and the low electrical parasitics associated with the flip-chip solder bond [60]. This technique requires high temperature annealing to bring the structure into alignment through the surface tension of the solders. Also, because optical

devices are inverted during the flip-chip bonding process, when they are involved, the substrate must be either transparent or removed during a subsequent process [60, 63, 64].

The other promising approach is thin film integration, also called epitaxial liftoff (ELO). In this technology, optical devices are grown and optimized separately from silicon circuitry and removed from the fabrication substrate using a technique called ELO, and then bonded to the CMOS circuitry using either Van der Waals bonding or adhesion between the host and ELO epitaxial layer. Some unique advantages of the thin film integration technology are that because the thin film devices can be inverted from the fabrication substrates, both sides of the thin film devices can be processed [63]. This is an important feature when considering three-dimensional interconnect and structures [65] and embedding OE devices into waveguides [63].

4.2 Thin Film Lasers

The material structure [66] of the thin film lasers developed by the integrated optoelectronics group at Georgia Institute of Technology are illustrated in Table 4-1. After the substrate of the laser was removed, the thin film lasers were then bonded to host substrates, BCB coated silicon substrate, for verification of their functionality. L-I and V-I measurements of the thin film lasers were performed. The measured threshold currents were approximately 25 mA when the injected currents have a pulsed-mode input with 10 % of duty cycle and 0.1 μ s pulse width. More details with different duty cycles of injected currents are shown in Figure 4.1. As the duty cycle is increased, the thin film laser has more optical power. However, going over 10 % of the duty cycle of the injected currents decreased the optical power of the laser. The fabricated thin film laser, therefore, showed an optimized operating point: 10 % of the duty cycle of the pulse current. In

addition, the measured V-I graph is shown in Figure 4.2. The thin film lasers have a thermal problem that restricts the high power continuous-wave (CW) operation of the laser, which is a normally used operating method for a laser driver. Therefore, the thin film laser, in this research, should be operated with pulsed mode input currents to prevent the thin film laser from harmful thermal damage.

Table 4-1. Thin film laser material structure.

Layers	Thickness (μm)
InGaAs: p-contact	0.1
p-InP	1
InGaAsP ($\lambda=1.3 \mu\text{m}$) :	0.3
5 multiple quantum well	
n-InP	1
n-InGaAs (n-contact)	0.2
n-InP	2
n-InGaAs (etch stop layer)	0.2
InP substrate	

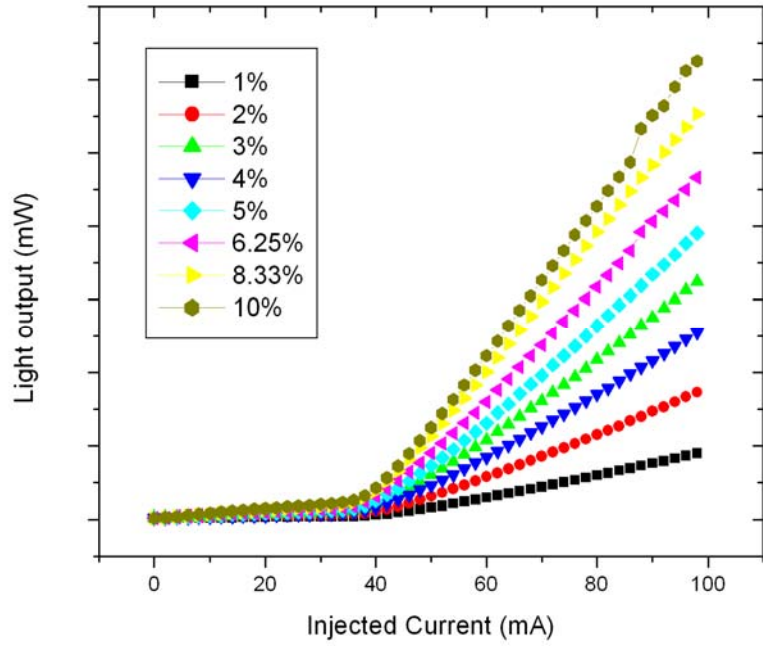


Figure 4.1. L-I measurement: the thin film laser on BCB coated silicon wafer. The measured threshold current is approximately 25 mA when the injected current has 10 % of the duty cycle.

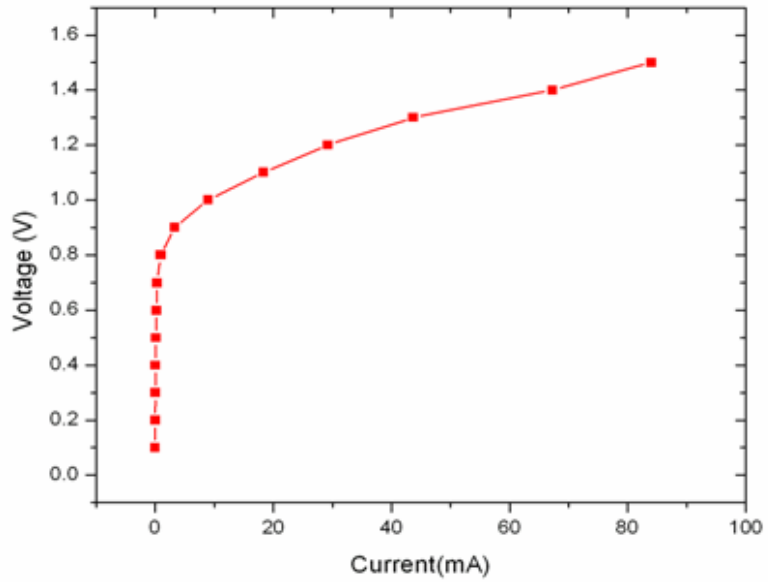


Figure 4.2. V-I measurement: the thin film laser on BCB coated silicon wafer.

As a simple experiment example, scattering parameter measurements of a commercial laser were performed to compare the differences between pulsed mode and CW mode operations and to verify the availability of a test setup for pulsed mode operation. The laser used in this example had a wavelength of 1310 nm, and it was supposed to work properly up to 622 Mbps. The test setup and measurement results are shown in Figure 4.3 and 4.4, respectively. A pulse current generator was used for biasing the laser with the internal bias tee in a lightwave network analyzer. Light output from the laser was collected by the internal photodetector. In Figure 4.4, the upper black line represents the electrical-to-optical (E/O) transfer function of the laser in CW mode operation. The other red line shows the E/O function of the laser in pulsed mode operation with 0.3 μ s pulse width and 10 % duty cycle. Although the red line is not exactly matched into the upper black line, the trend of the red line is very similar to that of the black line. Therefore, using the experimental setup, we can expect the 3-dB frequency of the thin film laser in a pulsed-mode operation.

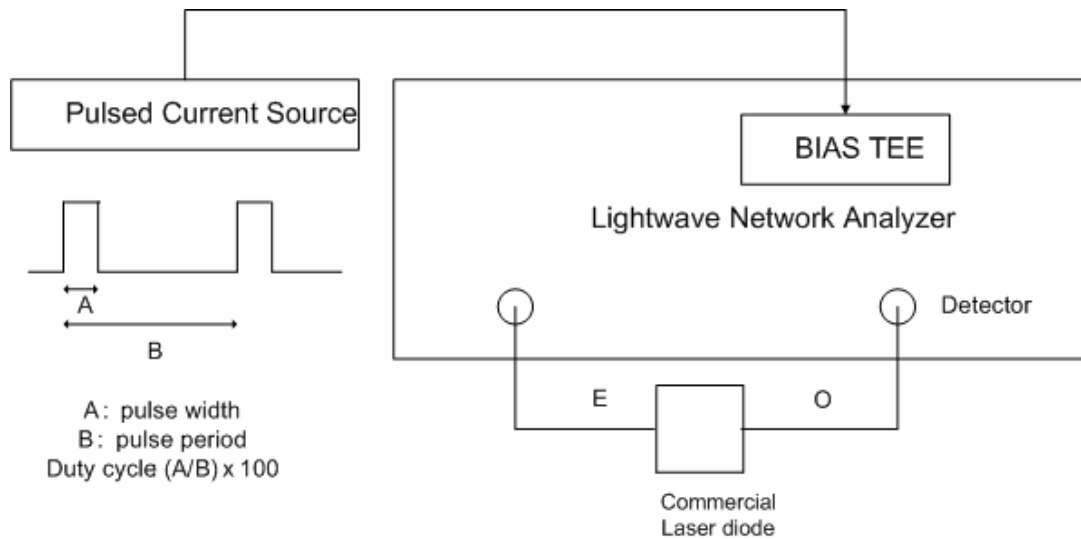


Figure 4.3. Pulsed mode s-parameter measurement setup.

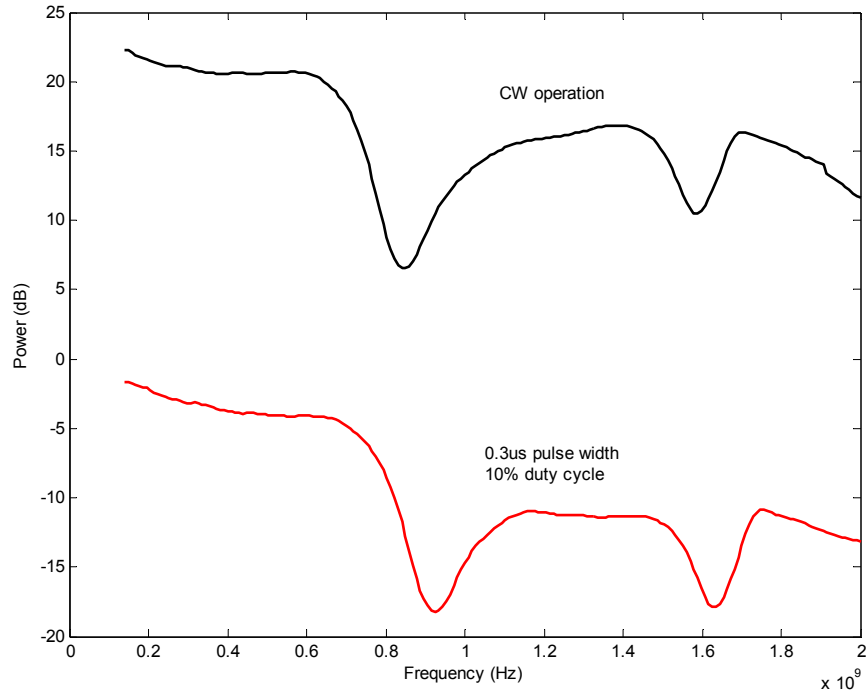


Figure 4.4. Performance comparison between pulsed mode and CW mode operations.

The above experiment shows the potential of the thin film laser in pulsed-mode operation. Then, the next step is to make the laser driver operate in pulsed-mode. The pulsed bias current and modulation signal can be generated by providing pulsed currents to modulation and bias current ports at the laser driver. The laser driver described in Chapter II was used for this test. Then, the output data of the laser driver were captured through an oscilloscope. The captured data were overlapped within the pulse period to build an eye diagram. Then, the eye diagram of the pulsed-mode laser driver can be obtained. Figure 4.5 shows the test setup for obtaining the time domain transient and eye diagram.

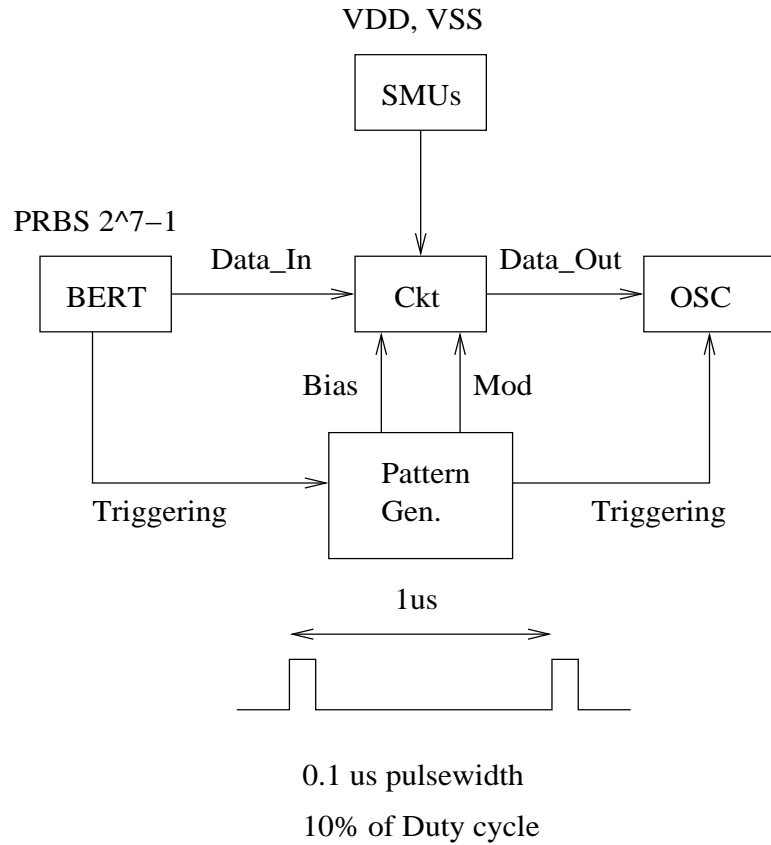


Figure 4.5. Test setup for pulsed-mode laser driver.

The BERT generates 10 Gbps PRBS input and provides it to the circuit and triggers a pattern generator, which produces a current input of 0.1 us pulse width and 10 % of the duty cycle and provides this currents to the circuit. The resulting outputs are shown in Figure 4.6. The top window represents raw data from the circuit. The second and third windows are zoomed images of the first window. As shown in the second and third windows, the circuit is working properly in the pulsed-mode condition. The data shown in the third window are captured to build an eye diagram. The eye diagram using Matlab is shown in Figure 4.7. The eye diagram shows that this pulsed-mode test setup can be applied to measure the transient response of the thin film laser.

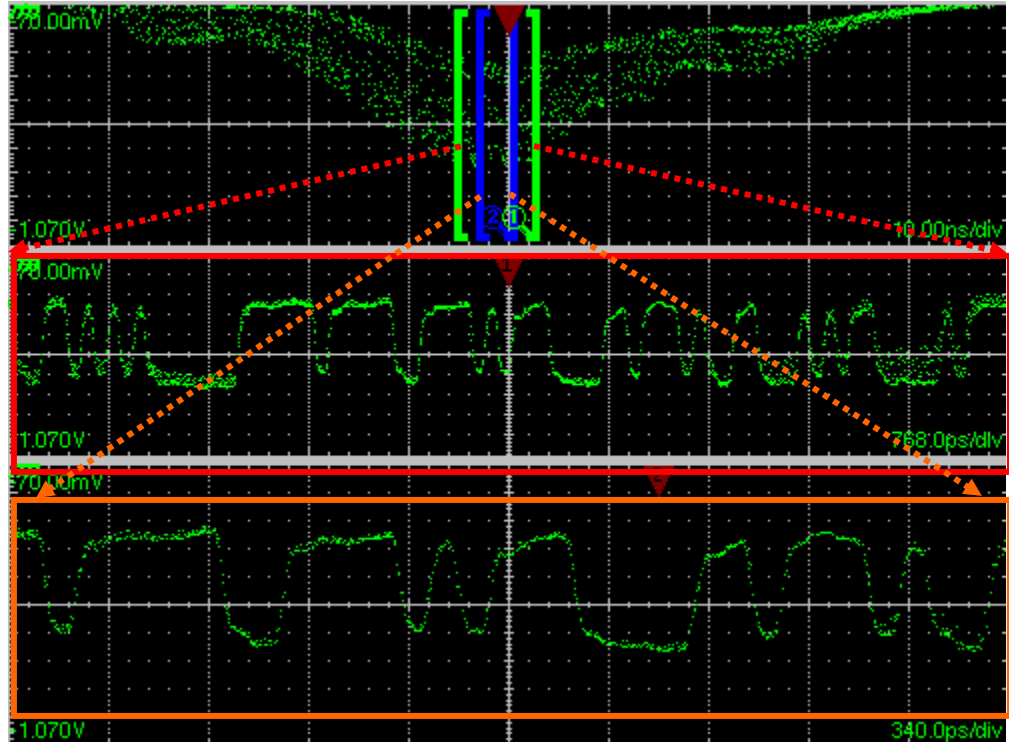


Figure 4.6. The output shows the pulsed-mode operation of the laser driver at the oscilloscope. Top window represents raw data captured at the output of the circuit. The second and third windows are zoomed data.

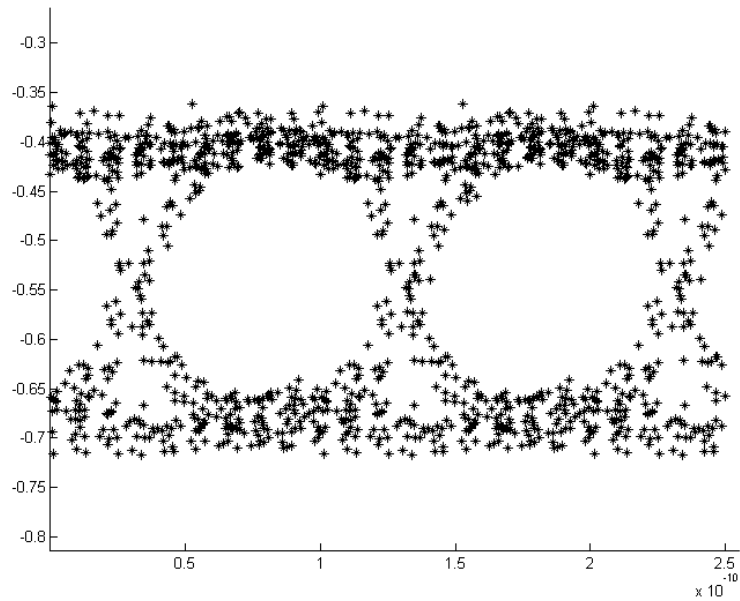


Figure 4.7. The eye diagram out of the pulsed data output.

4.3. Simulations

The electrical equivalent laser model used in Chapter III was modified to use the thin film laser to simulate the optical transmitter. Initially, the small-signal impedance out of the measured V-I characteristics was applied to the dominant factor of the model from which the inductance of bonding wire was removed. It was removed because the thin film laser will be connected with patterned metal line using conventional post-processing techniques. Successful high frequency signal transmission through the patterned metal line requires isolation from the lossy substrate. To insulate the lines from the substrate, a 3 μm of layer of silicon dioxide (SiO_2) is spun on the substrates. Coplanar waveguide transmission lines are fabricated on silicon wafers with and without SiO_2 to compare the loss on the different substrates. Using the HPADS momentum simulator, the characteristics of the transmission lines, 500 μm length, and 20 μm spacing, on SiO_2 coated silicon substrate were expected and compared to measured data, as shown in Figure 4.8. The measured data results show that the loss characteristic of the transmission line has little effects on the high frequency signaling when the 3 μm SiO_2 coated silicon substrate is used. Compared with the transmission lines without the SiO_2 on substrate, shown in Figure 4.9, which are expected to work properly below 1 GHz, the transmission lines on SiO_2 can be used at rates higher than 20 GHz without any degradation of signal. The characteristics of transmission lines on a ceramic substrate, as measured by a calibration kit used to measure high frequency devices working up to 40 GHz, show the almost identical characteristics as transmission lines on the SiO_2 coated silicon substrate. Therefore, the thin film laser model without the effects of the inductance of bonding wires can be applied to the laser driver simulations. In addition,

the results of the momentum simulations show promise of delivering the characteristics of various shapes of the transmission lines.

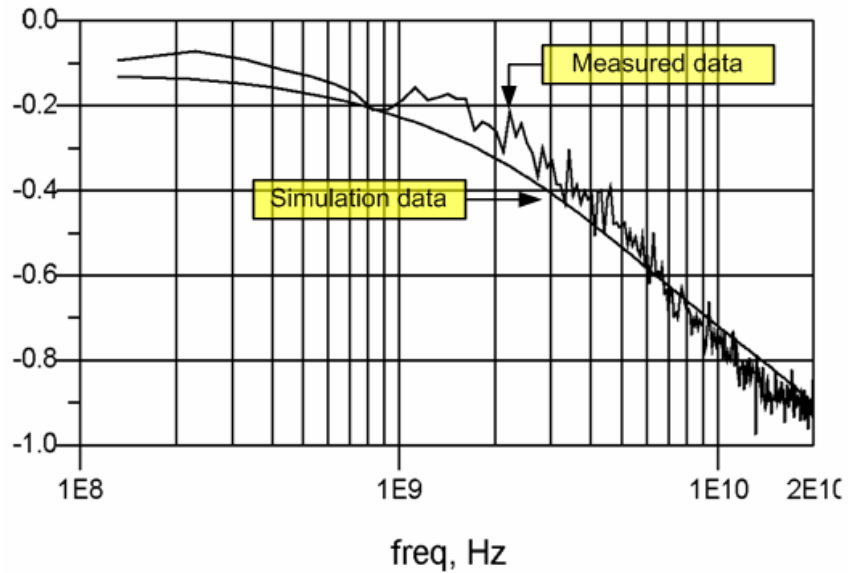


Figure 4.8. The comparison of the transfer characteristics (S21) of the transmission line between measurement and simulation.

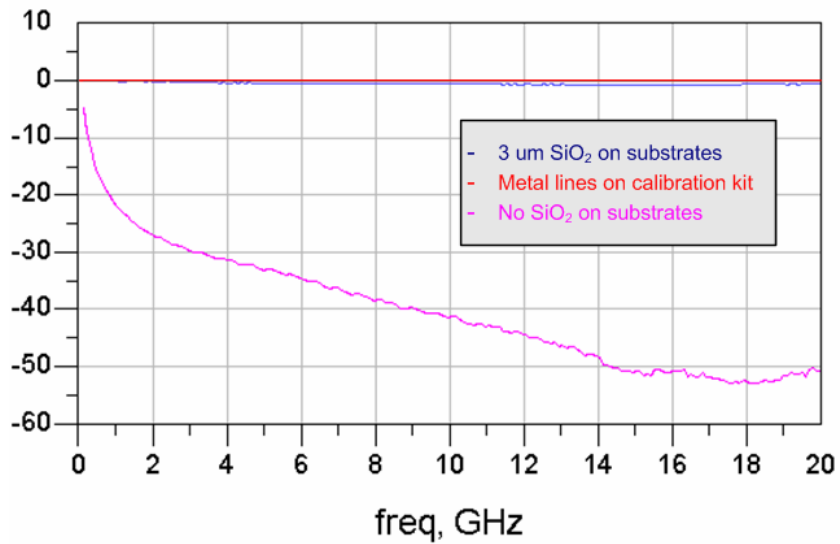


Figure 4.9. The transfer characteristics of transmission lines on silicon substrate with and without SiO₂ coatings.

The laser driver circuit used in Chapter III was used to perform transient simulations with the modified thin film laser model. Figure 4.10 shows the results, and the change of small-signal resistance does not critically affect the circuit's operation at 10 Gbps with the open eye diagram. This simulation assumed that the inductance of bonding wire was 0.1 nH and the small-signal resistance obtained from the V-I measurement was 25 ohms.

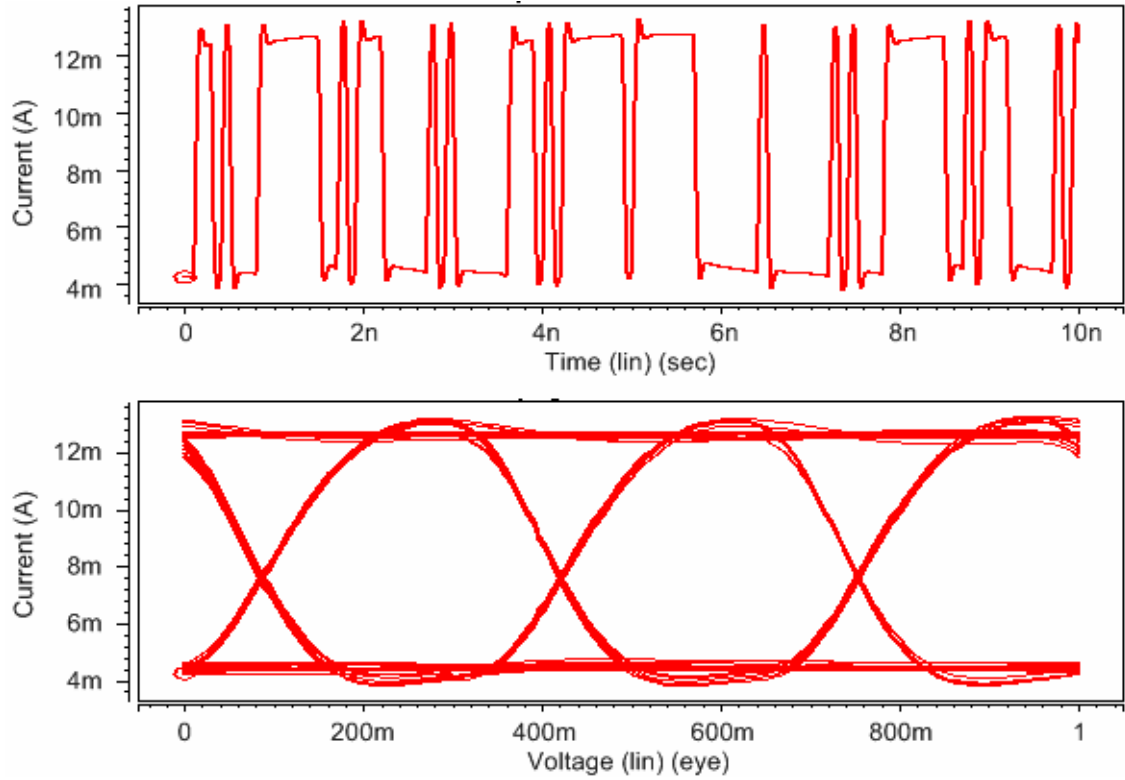


Figure 4.10. Transient response of thin film laser.

4.4 Measurements

In previous sections, the thin film laser was bonded onto an oxide-coated silicon substrate. The SiO₂-coated silicon host substrate is very similar to a silicon CMOS

circuit. Using a transfer diaphragm heterogeneous integration process, a thin film laser was integrated onto a silicon substrate that had 3 μm of SiO_2 deposited onto it. All the fabrication and integration processes were performed by Professor Nan Jokerst's research group at Georgia Tech. Figure 4.11 shows a microphotograph of the optical transmitter with the thin film laser.

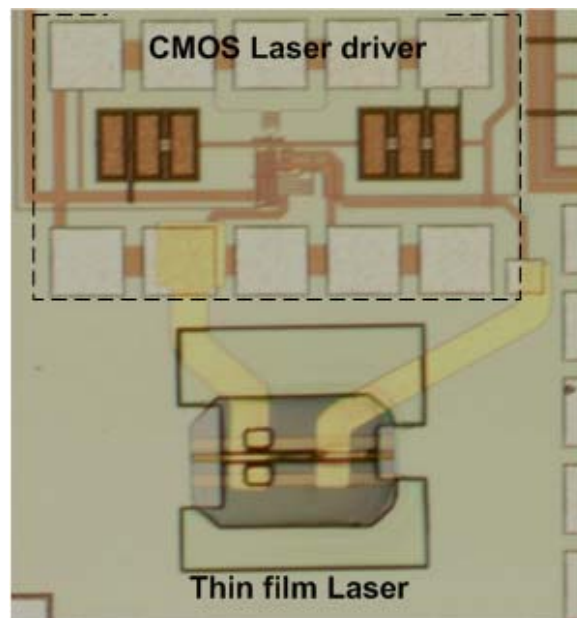


Figure 4.11. A microphotograph of the thin film laser integrated onto a CMOS circuit.

The transfer diaphragm heterogeneous integration process is illustrated in Figure 4.12. Once the thin film laser passes the functional test, the systems are bonded to the test board used in Chapter III. The test board is designed, except differential inputs, with all variable pads for adjusting biases. Differential inputs are provided by probing with microwave probes. After bonding the system to the board, the laser driver is wire bonded

as shown in Figure 4.13. A microphotograph of the wire-bonded circuits is shown in Figure 4.14.

Once the circuit is bonded to the test board and the wire-bonding is completed, functionality tests are performed to verify that the thin film laser is still working. The L-I curve of the thin film laser on the circuit was measured using a ILX Lightwave LDP 3811 precision-pulsed current source to drive the laser. The output light was coupled into a multimode step index optical fiber with a core diameter of 600 μm and a numerical aperture (NA) of 0.48. The other end of the fiber was FC connected to a Hewlett Packard lightwave 8153A multimeter to measure light output power. The measured L-I curve of the laser, shown in Figure 4.15, shows a very low light output power for the laser because the alignment of the fiber to the laser is inaccurate. This L-I measurement is for the functionality test, as stated earlier.

The speed tests of the optical transmitter with the thin film laser were performed with the pulsed measurement setup; however, collecting enough light output from the laser was difficult because of the fiber alignment to the laser and the characteristics of the laser itself. The speed tests of the optical transmitter will be performed soon as part of additional research.

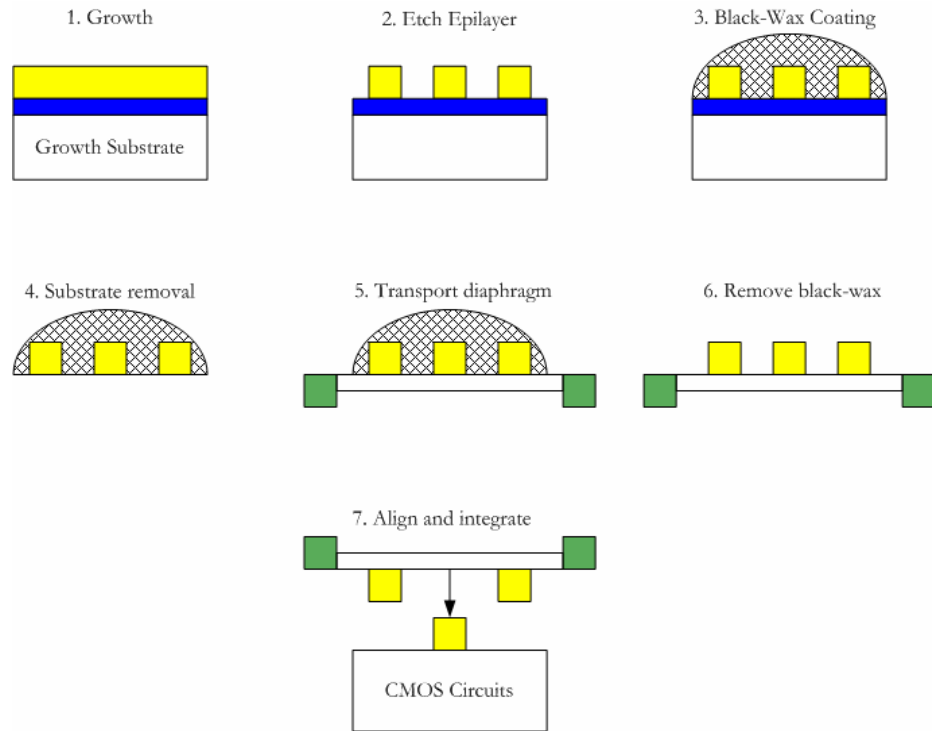


Figure 4.12. Thin film laser integration process.

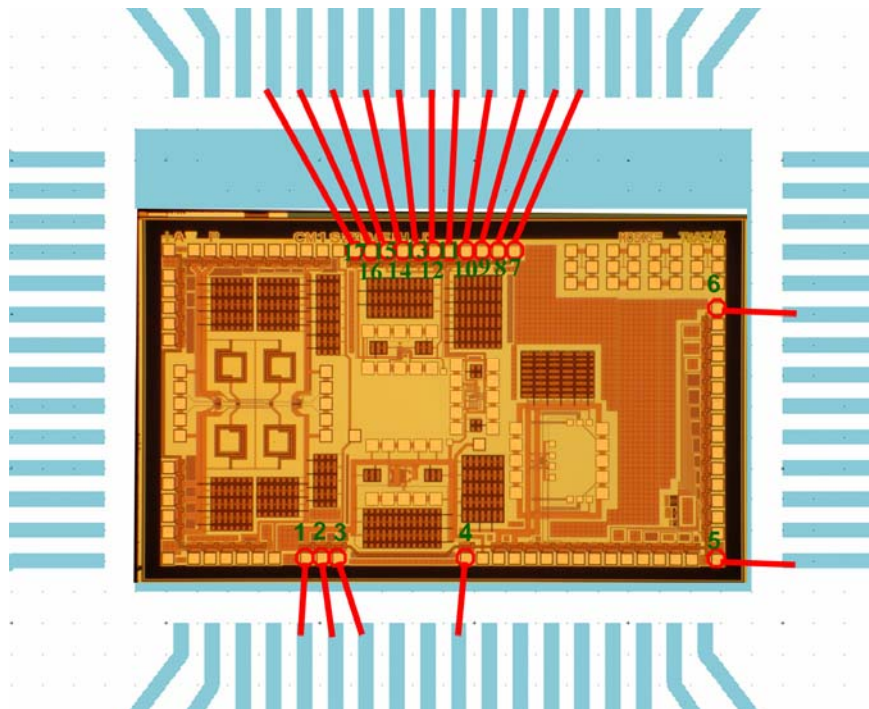


Figure 4.13. Circuit photo with wirebonding diagram.

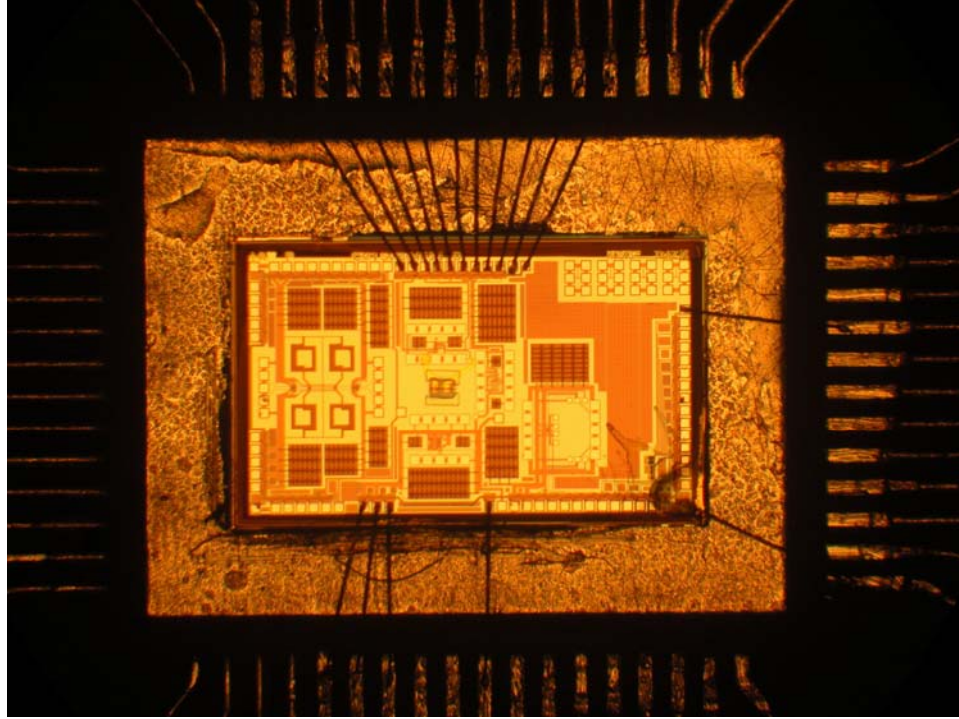


Figure 4.14. Integrated circuit photo with wirebonds.

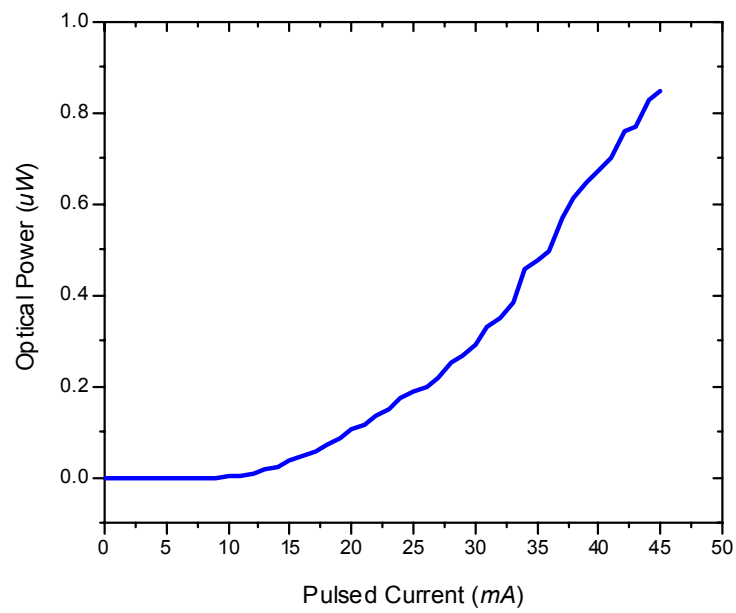


Figure 4.15. L-I measurement of the thin film laser on CMOS circuitry. The pulsed current was applied to minimize the thermal problem of the thin film laser.

CHAPTER V

DESIGN OF HIGH CURRENT LASER DRIVER FOR LVDS

This chapter presents the design of a laser driver in which the bias and modulation currents of the lasers are required to be much larger than the laser used in Chapter III. In addition, the laser driver is compatible with the IEEE standard for low-voltage differential signals (LVDS). Also covered in this chapter is a review of bandwidth enhancement techniques to understand and design the laser driver.

5.1 Introduction

Many high-speed communication links now operate at 1,310 nm or 1,550 nm wavelength because fiber attenuation decreases with wavelength, exhibiting two low-loss windows, as shown in Figure 5.1 (a). Moreover, as shown in Figure 5.1 (b), single-mode fiber dispersion equals zero at 1310 nm wavelength, which is called the zero-dispersion wavelength at which fiber has its maximum information carrying capacity. However, the long-wave length (1,310/1,550 nm) VCSEL has been the subject of research in recent years for next generation optical communication systems. It is difficult to obtain a more than 10 Gbps VCSEL at the time of this writing. Consequently, the laser driver involved will be required to be able to driver other types of lasers, including FP, DFB, and MQW, etc. Laser drivers for these applications should provide large modulation currents and large laser bias currents compared with the driving conditions of VCSELs.

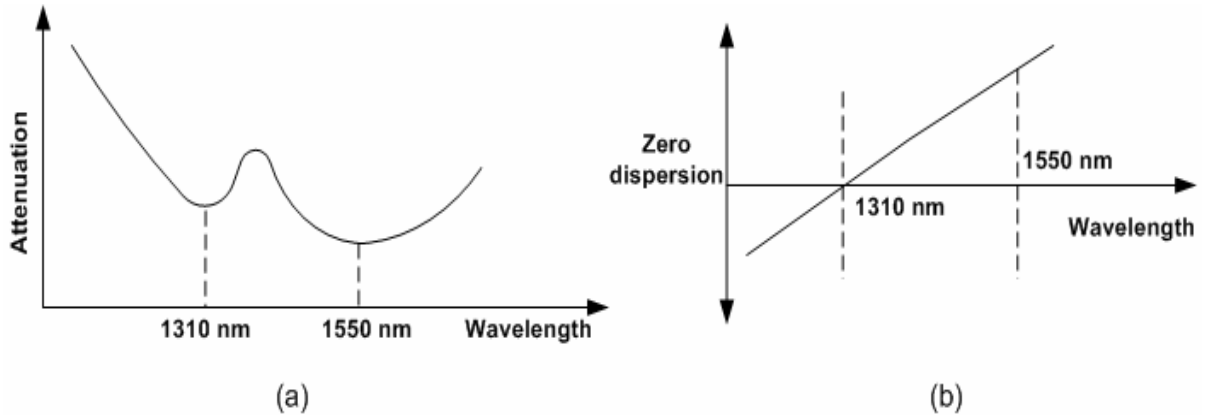


Figure 5.1. (a) Typical attenuation versus wavelength plot for a silica-based optical fiber [67, 68]. (b) Typical single-mode fiber dispersion vs. wavelength curve.

As a result of the advanced technology of communications, data transfers are increasing dramatically, and demands for low power consumption and more bandwidth have been increased. In order to meet those requirements, LVDS use high-speed analog circuit techniques and is a generic standard for high-speed data transmission. Because LVDS has low voltage swings, the system consumes little power, and the equal and opposite currents create electromagnetic fields that cancel each other out. Also, LVDS do not need a specialized board design because they are usually less sensitive to imperfections in the transmission line environment [69]. Therefore, the laser driver with an LVDS input interface requires satisfying the demand for broad bandwidth at low power.

5.2 Bandwidth Enhancement Techniques

To meet the LVDS standard at the input interface, the laser driver should have a high-speed and high-gain CMOS laser driver, then a pre-amplifier stage is added into the

current steering output stage of the laser drivers. Here, some useful techniques to increase bandwidth in CMOS technology are introduced.

5.2.1 Shunt Peaking Technique

Although inductors are commonly used with narrow-band circuits, they are useful in broadband circuits as well. The idea is to allow the capacitance that limits the bandwidth to resonate with an inductor, thereby improving the speed. A simple common source (CS) amplifier is illustrated in Figure 5.2. For simplicity, the parasitic capacitance, channel length modulation, and body effects are omitted.

The frequency response of this amplifier 5.2 (a) is given as:

$$\frac{V_{out}}{V_{in}}(\omega) = \frac{g_m R}{1 + j\omega RC} \quad (5.2.1)$$

When the inductor L is connected in series with a load resistor in the amplifier, which is called shunt peaking and shown in Figure 5.2 (b), the frequency response of the amplifier is changed as

$$\frac{V_{out}}{V_{in}}(\omega) = \frac{g_m(R + j\omega L)}{1 + j\omega RC - \omega^2 LC} \quad (5.2.2)$$

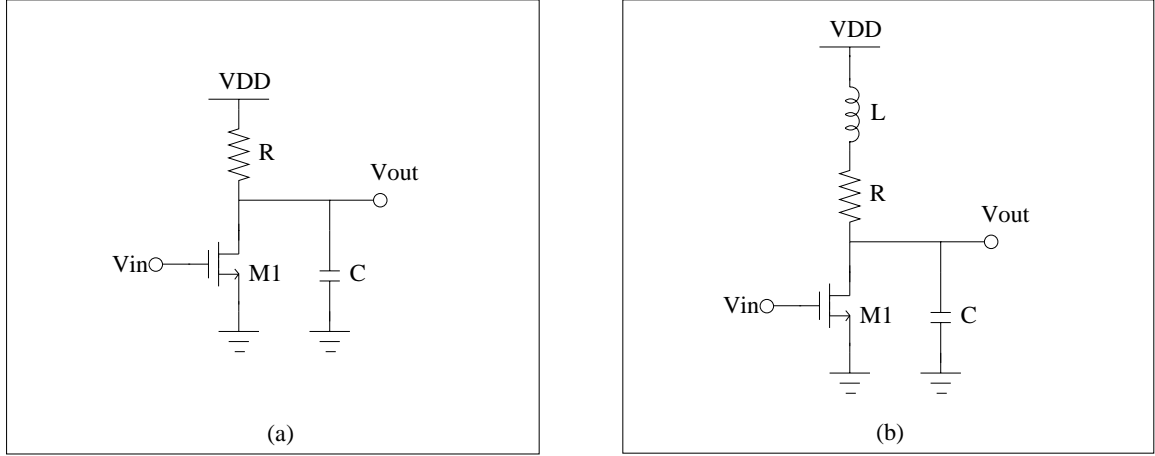


Figure 5.2. Schematics of common source (CS) amplifier with and without shunt peaking.

And it can be written in the form

$$A(s) = A(0) \frac{N(s)}{1 + \frac{s}{\omega_0 Q} + \frac{s^2}{\omega_0^2}} \quad (5.2.3)$$

Then, the Q factor results in

$$Q = \sqrt{\frac{L}{RC}} \quad (5.2.4)$$

The small-signal transfer function (5.2.2) shows a zero at frequency R/L , which extends the bandwidth of the stage. However, this inductance value can result in significant gain peaking, which causes signal degradation in broadband applications. When the value of the Q factor is 0.68, this shunt peaking technique can extend bandwidth by 78 % without creating any any gain peaking in the amplifier. Thus, when this technique is applied to laser driver design, the optimized value of inductance should be used [51, 70]. If chip area is critical, shunt peaking can be implemented by means of

an active inductor [51, 71]. Figure 5.4 (a) shows a simplified active inductor using a transistor and a resistor. Omitting the gate-drain capacitor, body effect, and channel-length modulation, the small-signal equivalent circuit is illustrated in Figure 5.4 (b). Then, Z_{in} can be written as

$$Z_{in}(s) = \frac{V_x}{i_x} = \frac{1 + sRC_{gs}}{g_m + sC_{gs}} \quad (5.2.5)$$

Therefore, $|Z_{in}(0)| = 1/g_m$ and $|Z_{in}(\infty)| = R$. For Z_{in} to behave as an inductor, it is required that $R \gg 1/g_m$, then the impedance increases with frequency. However, this active inductor usually has a headroom problem that requires large supply voltage technology [71, 72].

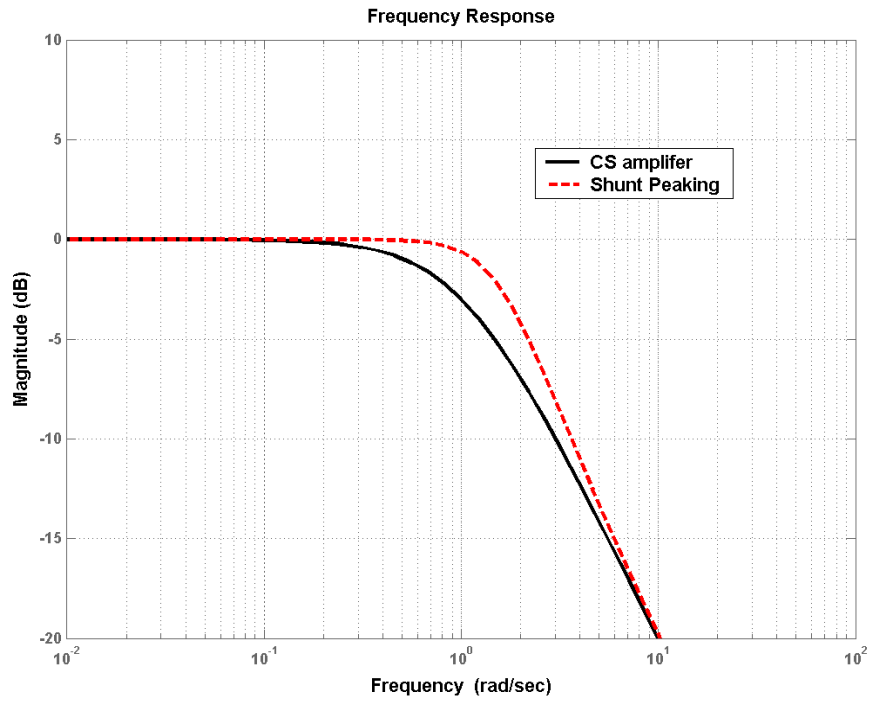


Figure 5.3. Frequency response of CS amplifier and shunt peaking.

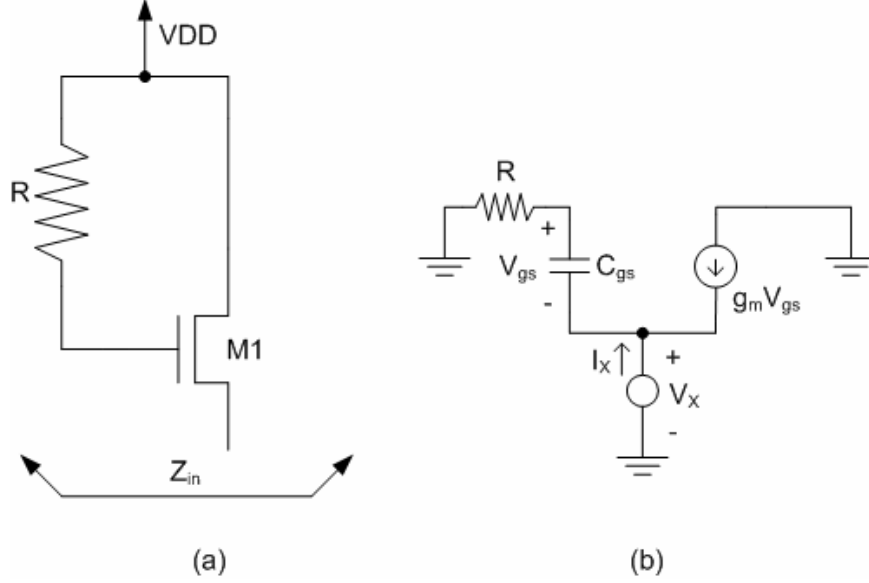


Figure 5.4. (a) Schematic of simplified active inductor. (b) Small-signal equivalent circuit.

5.2.2 Source Degeneration

The bandwidth of a differential amplifier can be widened by including the resistance and capacitance between sources, as shown in Figure 5.5. This is achieved at the cost of a reduction in the low-frequency gain. To evaluate the effect of the resistance and capacitance on frequency response, Figure 5.5 (b) uses the half circuit of a differential amplifier. Its effective transconductance and voltage gain becomes

$$G_m = \frac{g_m}{1 + g_m \left(\frac{R_s}{2} \parallel \frac{1}{2C_s s} \right)} = \frac{1}{2} \left[\frac{g_m (1 + R_s C_s s)}{g_m R_s + 2(1 + R_s C_s s)} \right] \quad (5.2.6)$$

$$A_v = G_m R_d = \frac{g_m}{1 + g_m \left(\frac{R_s}{2} \parallel \frac{1}{2C_s s} \right)} R_d \cong \frac{g_m R_d}{1 + g_m R_s / 2} \quad (5.2.7)$$

The transconductance hence contains a zero at $1/R_s C_s$ and a pole at $(1 + g_m R_s / 2) / (R_s C_s)$.

If the zero cancels the pole at the drain, $R_S C_S = R_D C_L$, then the amplifier's overall bandwidth is increased by a factor of $1 + g_m R_S / 2$ compared with that of a CS amplifier. The gain, as mentioned, is decreased by a factor of $1 + g_m R_S / 2$ at low frequencies [73]. Another advantage of this configuration is that the input pole magnitude seen at the preceding stage is decreased by a factor of $1 + g_m R_S / 2$, if $R_G C_{GS} \gg (R_S C_S + R_S C_{GS} / 2)$. Therefore, the input capacitance is decreased. In addition, the thermal noise of R_S may pose difficulties.

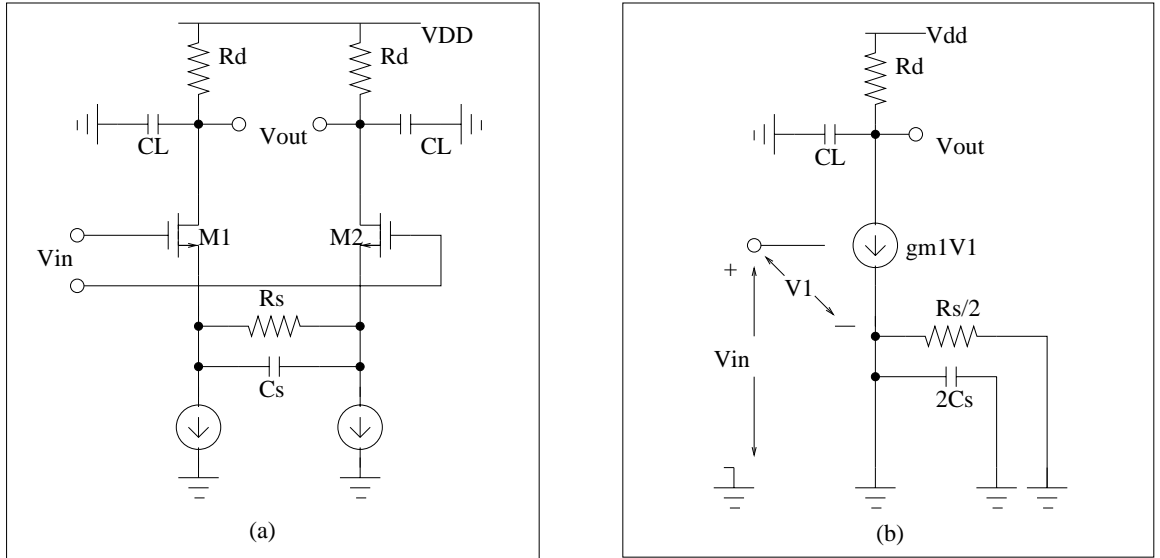


Figure 5.5. (a) Differential pair with capacitive degeneration. (b) Small-signal model with half circuit.

5.2.3 Cherry-Hooper Topology

The Cherry-Hooper topology is widely used to provide broadband characteristics with high gain. Figure 5.6 (a) shows a schematic of the circuit topology. The differential mode half circuit of the amplifier in Figure 5.6 (a) is shown in Figure 5.6 (b). The first

differential pair acts as a transconductance stage that converts the input voltage signal into a current. The current-mode signal then is amplified and converted back into voltage by a transimpedance stage. The shunt feedback resistor lowers the input impedance of the transimpedance stage, and provides excellent high-frequency performances. The input impedance of the transimpedance stage becomes

$$Z_{in} = \frac{V_{in}}{I_{in}} = \frac{R_D + R_F}{1 + g_{m1}R_D} \quad (5.2.8)$$

The low-frequency gain is calculated as

$$\frac{V_{out}}{V_{in}} = \frac{g_{m3}R_d(g_{m1}R_f - 1)}{1 + g_{m1}R_d} = \frac{g_{m3}g_{m1}R_dR_f}{1 + g_{m1}R_d} - \frac{g_{m3}R_d}{1 + g_{m1}R_d} \quad (5.2.9)$$

If $g_{m1}R_d \gg 1$ and $R_f \gg (g_{m1})^{-1}$, then, the gain becomes

$$Av \approx g_{m3}R_f - \frac{g_{m3}}{g_{m1}} \approx g_{m3}R_f \quad (5.2.10)$$

The gain is equal to that of a simple common source (CS) stage having a load resistance of R_f . The pole frequencies of this circuit can be considered approximately as $\omega_{p1} \approx g_{m3}/C3$ and $\omega_{p2} \approx g_{m1}/C2$, much higher than those of a CS stage circuit, $(RC)^{-1}$. Thus, this topology provides a voltage gain of approximately $g_{m3}R_f$ and high frequency poles. However, this amplifier encounters headroom problems when it used in low supply voltage technology. For instance, the minimum supply voltage to the Cherry-Hooper amplifier equal to

where $V_{min,Is1}$ is the minimum voltage required across $Is1$ source. To solve the gain-headroom trade-off, modified Cherry-Hooper topologies have been reported and utilized in high-speed circuits [73-75].



Table 5-1 describes the design goals for the high-current laser driver. The laser driver circuit should have more than 40 mA_{p-p} modulation currents and bias currents. Therefore, the previous designed laser driver, which was optimized for 10 mA_{p-p} modulation and bias currents, cannot be applied to the design specifications

Table 5-1. Design goals for high-current laser driver.

Specification	Design Goal
Speed	Over 10 Gbps
LVDS input amplitude	100mV _{p-p}
Technology	TSMC 0.18 μ m CMOS
Output	Modulation currents: 40 mA _{p-p} Bias current: 30 mA

It is hard to design the output current switch with LVDS input amplitude of a maximum 100 mV_{p-p}. Because of this difficulty, the pre-driver stages must be designed so that the high-gain and high-speed laser driver to interface with LVDS input voltage. Therefore, the design of the pre-driver should incorporate one of bandwidth enhancement techniques.

The shunt peaking technique with passive inductors, though it is easily implemented to increase the bandwidth, was excluded. The reasons for this exclusion are its requirement of a large chip area, its high parasitic capacitance. In addition, the source degeneration technique decreases the gain by a factor of $1+g_m R_S/2$, although its bandwidth increases by the same factor. Instead, this research uses the modified Cherry-Hooper topology [73-75] and shunt peaking with active inductors to implement the laser driver.

Figure 5.7 illustrates the gain cells for the pre-driver stage using the modified Cherry-Hooper topology and the shunt peaking technique with active inductors. To alleviate gain-headroom problems in the Cherry-Hooper amplifier at low supply voltage,

shown in Figure 5.6, the circuit was modified as shown in Figure 5.7(a), where PMOS loads (M5 and M5) provide part of the bias current of the input differential pair. In addition, triode-mode PMOS loads (M5, M6, M10, and M11) were used to increase the gain of the core amplifier because they have better headroom than diode-connected NMOS loads.

Figure 5.7 (b) depicts the gain cell using the shunt peaking technique with active inductors. As mentioned in previous sections, the resistance value of PMOS (M6 and M7) seen by the source should be larger than the $1/g_m$ (M4 and M5) to behave as inductors. Thus, wide bandwidth operation can be achieved. The overall voltage gain of the circuit is determined by the size ratio of M1 and M4, where

$$A_v = \frac{g_{m1}}{g_{m4}} = \sqrt{\frac{(W/L)_1}{(W/L)_4}} \quad (5.3.1)$$

In this design, the approximate voltage gain of 2 was used to avoid bandwidth degradation caused by Miller capacitance.

The pre-driver circuit's design started with the optimization of the output current switch so that it can provide the required currents for laser diodes. Once the current switch was optimized, the pre-driver stage was designed to have enough bandwidth and gain with the input impedance of the current switch. After the pre-drivers were optimized for the given specifications, the current switch was re-optimized to account for parasitic effects. Overall laser driver schematics are shown in Figure 5.8 and in Figure 5.9. For the pre-driver with shunt peaking, two stages are taped to the left to provide enough gain and bandwidth.



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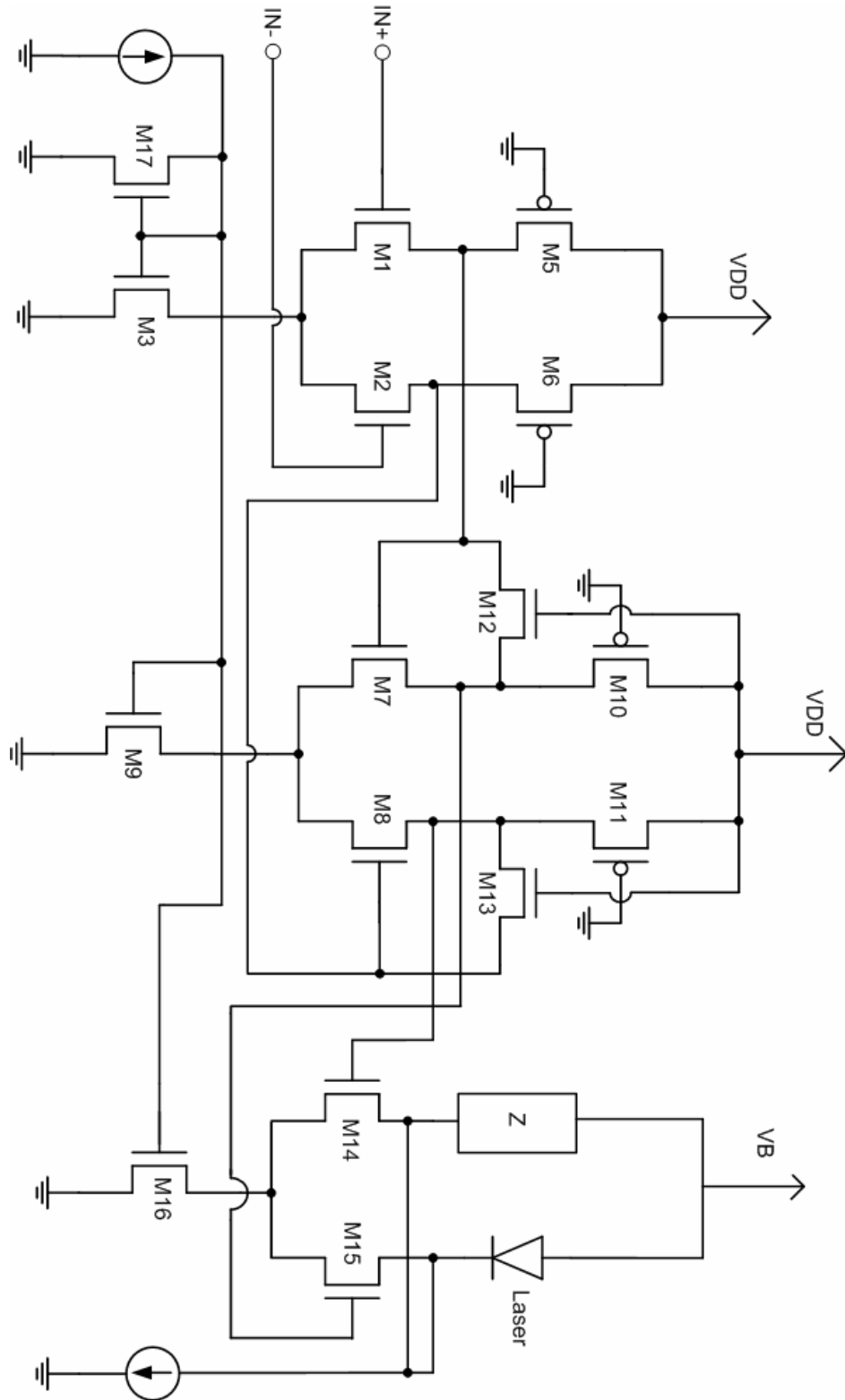


Figure 5.8. Schematic of high-current laser driver with pre-driver stage.

5.4 Simulations

Simulations were performed using HSPICE and TSMC 0.18 μm mixed-signal CMOS BSIM3 model parameters (See Appendix) provided by MOSIS. Figure 5.10 shows the frequency response of the pre-driver stage. The red line represents the modified Cherry-Hooper amplifier, and the blue line represents the shunt peaking amplifier. The pre-drivers were designed to have a the gain of 12.5 dB and a 3dB frequency of 6.56 GHz and 8 GHz, respectively. The frequency response of the shunt peaking amplifier shows about 22 % more bandwidth increase than the modified Cherry-Hooper amplifier without incurring any gain peaking.

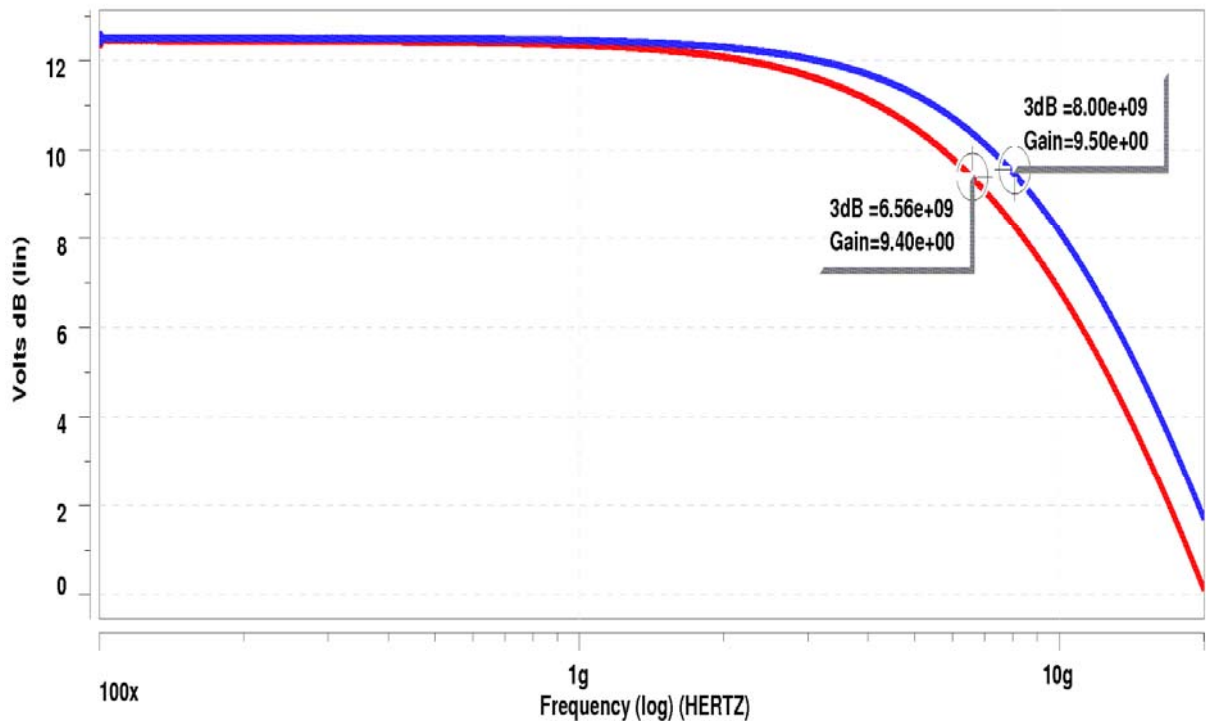


Figure 5.10. Frequency response of the pre-drivers. The blue line represents the shunt peaking amplifier and the red one represents the modified Cherry-Hooper amplifier.

Figure 5.11 illustrates the transient response of the overall laser driver using the modified Cherry-Hooper amplifier, shown in Figure 5.8 (a), for 10 Gbps operation. The first trace shows the pulse waveform of input to the pre-driver stage, and the second trace shows the pulse train of output from the laser driving stage. This trace was shown to determine if there are missing bits that cannot be easily revealed in an eye diagram. The last trace shows the eye diagram of output from the laser driver. The eye diagram shows few jitters at 10 Gbps.

Figure 5.12 shows the transient response of the laser driver using shunt peaking techniques with active inductors. The first, second, and last trace represent input voltage, output current, and an eye diagram at 10 Gbps, respectively. As shown in Figure 5.9, this topology has more bandwidth than the modified Cherry-Hooper amplifier. Therefore, the eye diagram of output current is clearer.

Based on these simulations, the high-output current laser driver was designed using bandwidth enhancement techniques. The shunt peaking techniques in the pre-driver stages have better performance. However, both techniques can be applied to implement high-output current laser driver because the simulation results meet the required specifications. More specified circuit performances are summarized in Table 5-2.

Table 5-2. Specified circuit performances.

Performance	LD with the modified CH	LD with active inductors
Speed	10 Gbps	10 Gbps
Input	100mV _{p-p}	100mV _{p-p}
Output	Mod: 40mA _{p-p} Bias: 30mA	Mod: 40mA _{p-p} Bias: 30mA
Power	694 mW	312 mW

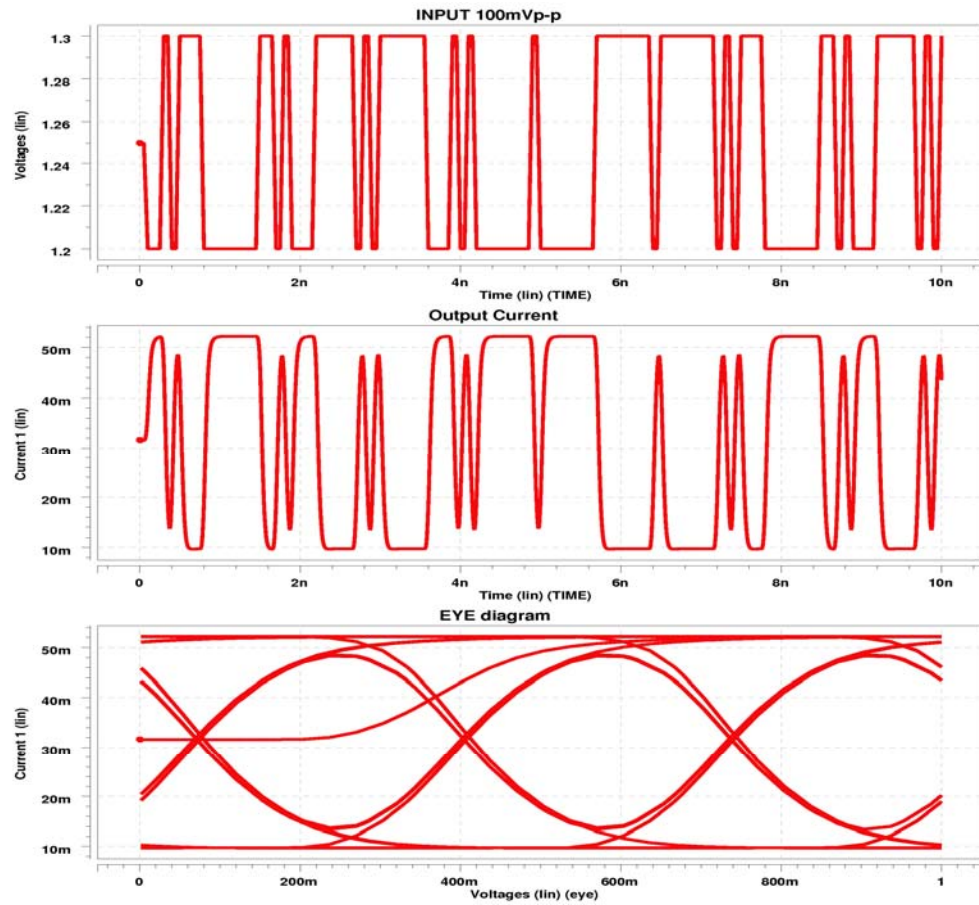


Figure 5.11. Transient response of high-current laser driver using the modified Cherry-Hooper amplifier at 10 Gbps.

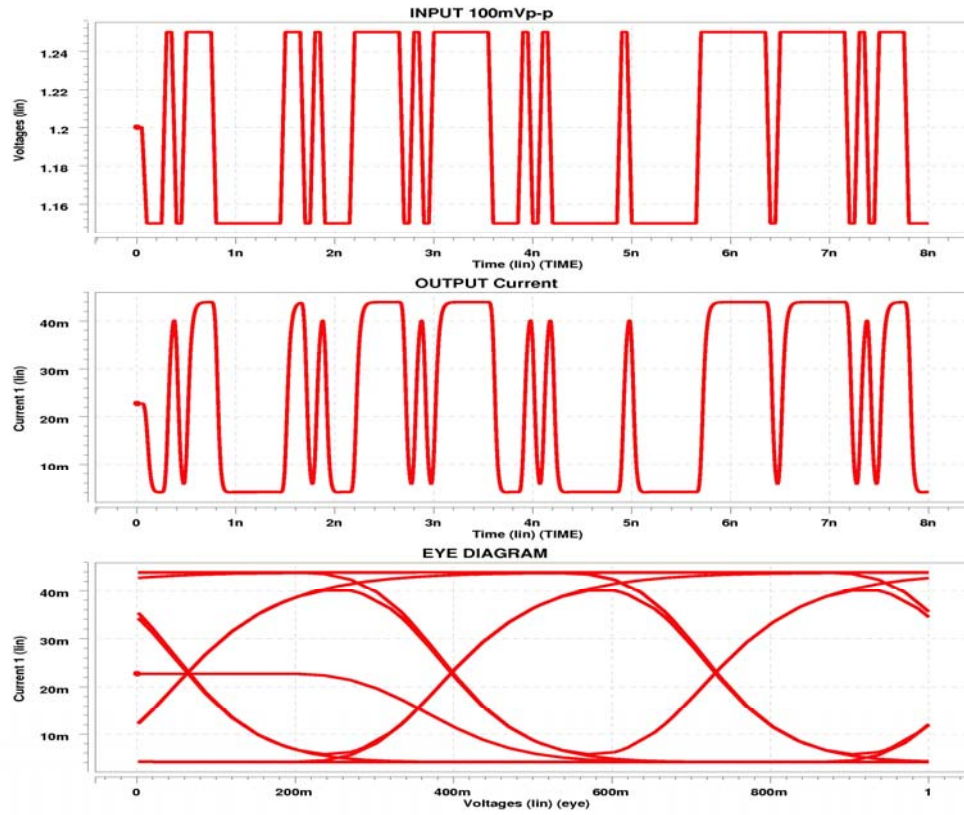


Figure 5.12. Transient response of high-current laser driver using the shunt peaking with active inductors.

CHAPTER VI

CONCLUSIONS AND FUTURE RESEARCH

This chapter covers the contributions associated with the research accomplished in development of a high-speed optical laser driver using a standard mixed-signal CMOS process and an optical transmitter with a thin film laser by using the heterogeneous integration. In addition, future research is addressed.

6.1 Contributions

The laser drivers were implemented for optical data communication using standard commercial CMOS 0.18 μm technology. These circuits work at up to 10 Gbps speed with 10^{-14} BER performance. They are the first digital CMOS laser drivers developed to date at this speed with low power consumption of 65 mW. Table 6-1 shows the performance comparison between this laser driver and the recently published lasers.

Moreover, this research was focused to co-design the laser driver and the laser device. Most circuit designers have focused only on the performance of the circuit itself without regard to the laser model as they assumed the lasers to be 50 ohm resistors. However, in this research, all simulations were performed with parasitics extracted from the layout of circuits and from the packaging models, including bonding wires and test board traces, to minimize unexpected effects when measurements were performed. In addition, performance was measured in terms of BER and eye diagrams even though most of researchers provided only scope captured data or eye-diagrams without BER data.

Using the heterogeneous integration technique, a thin film laser was integrated onto a CMOS laser driver. The hybrid integration approach used in this research illustrated the availability for independent design, optimization, and fabrication of each component in an optical transmitter. The thin film laser was integrated onto a silicon CMOS laser driver to show that an optical transmitter can not only be independently optimized but also integrated with separately optimized circuitry as well. This co-design approach carries a great potential for the implementation of high-speed and low cost optical transmitters that can be employed in optical data communication

To the best of author's knowledge, no CMOS laser driver circuits with a thin-film laser have been reported. There are two papers reporting 10 Gbps 0.18 μ m technology CMOS driver circuits in Table 6-1. One of them is a modulator driver, which means this is not suitable for direct modulation of a laser diode [70]. The other paper has only reported the electrical performance of the driver, not actual laser data [52]. A more detailed comparison of the proposed research and other laser drivers is summarized in Table 6-2.

Besides the development of high-speed and low-power laser driver, bandwidth enhancement techniques were used to design laser drivers for high modulation current. Moreover, these laser drivers can be interfaced with LVDS standards to integrate into other digital circuitry. Compared with other published results, shown in Table 6-1, this laser driver has the lowest input voltage used at 10 Gbps speed applications.

Table 6-1. The performance comparison of the laser driver in this research with others recently published.

Authors	Speed	Mod. Current	Bias Current	Input	Etc.
[76] Haralabidis	2.5 Gbps	0~40 mA _{p-p}	0~40 mA _{p-p}	2Vpp	0.8 μ m CMOS
[55] Chen, X.	2.5 Gbps	40 mA _{p-p}	N/A	PECL	0.35 μ m CMOS
[77] Annen, R.	500Mbps	2.1 mA _{p-p}	N/A		tr,tf=82ps
[78] Chan, C.T.	2.5 Gbps	20 mA _{p-p}	N/A		0.18 μ m CMOS
[51] Chen, G.C.	2.5 Gbps	20 mA _{p-p}	5~10 mA _{p-p}	PECL	0.35 μ m CMOS
[79] Lin, C.H.	2.5 Gbps	5~20 mA _{p-p}	4~10 mA _{p-p}	PECL	0.35 μ m CMOS
[52] Petersen, K	10 Gbps	30 mA _{p-p}	40 mA _{p-p}	500mV	0.18 μ m CMOS
[70] Cao, J	10 Gbps	8 mA _{p-p}	N/A	LVDS	0.18 μ m CMOS
[54] Calal, S.	10 Gbps	100 mA _{p-p}	N/A	800mV	0.18 μ m CMOS

Table 6-2. The comparison of proposed laser driver and Peterson's laser driver.

	Speed	Mod. Current	Input	Power	Technology
Petersen's work [52]	10 Gbps	30 mA _{p-p}	500 mV _{p-p}	492.9mW	Intel CMOS 0.18 μ m
This research	10 Gbps	10 mA _{p-p}	800 mV _{p-p}	62.5mW	TSMC CMOS 0.18 μ m
This research	10 Gbps	40 mA _{p-p}	100 mV _{p-p}	312 mW	TSMC CMOS 0.18 μ m

6.2 Future Research

This research covers two types of high-speed CMOS laser drivers; low-power applications and high-modulation current laser drivers of up to 10 Gbps in speed of operation. However, the implementation of an external modulator driver, which is widely used in optical communication system, is necessary for future research. To drive the external modulator, the driver circuitries must provide voltage output instead of the current output of laser. In addition, the programmable circuitry to compensation for the variation of laser characteristics because of aging and temperature change is left for future research. In this research, those effects can be compensated for by manually adjustment of external current source.

High-speed measurements of the optical transmitter with a thin film laser are one of the main tasks left to perform. Currently, the thermal properties of the thin film laser are insufficient for continuous operation. Therefore, to improve upon the work that has been done for this thesis, the thin film devices with different materials are under development. Moreover, to improve the light output coupling efficiency of the circuitry, a micro lens could be integrated on the thin film laser. Finally, the implemented optical transmitter could be part of an optical transceiver with optical receivers and waveguide. It will give commercial and government sectors the ability to build a low-cost and high-speed optoelectronic transceiver that can be employed in chip-to-chip interconnection, fiber-to-the curb/home/building/desktop, and local area network (LAN) applications.

Other function blocks such as multiplexers to serialize the low-speed parallel incoming data stream to high-speed signals and to utilize the advantages of optoelectronics in parallel networks are necessary for future research.

6.3. Conclusions

A silicon CMOS laser driver was designed by using differential topology to minimize unwanted delta I noise and common mode noise. The laser driver was fabricated by using standard mixed-signal CMOS technology through the MOSIS foundry under a minimum feature size of 0.18 μm . The performance of this laser driver has been verified along with BER measurement results and eye diagrams at the data rate of 10 Gbps non-return-to-zero pseudorandom bit stream (PRBS). Decoupling techniques are suggested to reduce the effect of parasitics, and the effectiveness of the technique was verified in simulations and measurements. In addition, the accurate model of parasitic effects was incorporated in the simulation to predict the actual behavior in the real measurement environment.

A thin film laser device was integrated onto the silicon CMOS laser driver using the heterogeneous integration method to create an optical transmitter. This optical transmitter was tested by a pulsed-mode measurement setup to solve the thermal problems in the thin film laser. Also, the capability of pulsed-mode test setup was verified in Chapter IV with an experiment.

In Chapter V, the high-current laser drivers for an LVDS input interface, which is widely used as a common standard, was introduced. These laser drivers also support a 10 Gbps data rate with a 100 mV_{p-p} input data stream and consist of a differential current switch and high-speed and high gain pre-driver stages that used the modified Cherry-Hooper topology and shunt peaking amplifier with active inductors. These laser drivers will be fabricated and tested.

APPENDIX

HSPICE INPUT CONTROL FILES AND BSIM MODELS

A.1 Low Power CMOS Laser Driver Input Control File

```
*****
*
*   High Speed Laser Driver Simulations   *
*
*****

.option post list accurate
.lib 'models/mm018.l' TT
.lib 'models/rf018.l' TT_RFMOS
.lib 'models/mm018.l' DIO
.inc 'models/PSPLspice.txt'
.option cshunt=1e-15 gshunt=1e-12

*****
*
*   Modified Laser Model                 *
*
*****

.param N=3.25 IS=3e-11 IK=1.16e-3 RS=15.78
.model D D(N=N IS=IS IK=IK RS=RS )
.subckt SonyVCSEL 1 2
Lbond 1      L1      0.2n
D      L1      L11    D
L      L11     3       0.892n
R1     3       4       39.5
C1     3       4       0.04p
C2     3       22      0.479p
C3     4       22      101p
R2     4       22      8.8
Lbond2 22     2       0.2n
.ends

XVC  VDD VCN Sonyvcsel
VM   VCN VCN 0
```



```

*****
*
*      Electrical Test
*      (50 ohm w/ dc block)
*
*****

```

```

* XRR1   VCN   VMR   DCB5501
* XRR2   EOUT1 VMD   DCB5501
* RVM2   VMR   0    50
* RVM3   VMD   0    50

```

```

*****
*
*      Power Supply
*
*****

```

```

VESDP   ESDVDD   0    3.
VESDN   ESDVSS   0    0
VDD     VDDP     0    3.
VSS     VSSP     0    0
LVDD    VDDP     VDD   15.2n
LVSS    VSSP     VSS   15.2n

```

```

*****
*
*      Bias and modulation currents
*
*****

```

```

.param biasN=0.3m imod=3m
Ibiasn   VSS   IBIAS   biasN
Imod     VSS   IMOD    imod

```

```

*****
*
*      input
*
*****

```

```

.param imid1=1.5 imid2=1.5
.param tt=.10ns Ihigh1=imid1+.4
+Ilow1=imid1-0.4 slope1=0.020ns
.param tt=.10ns Ihigh2=imid2+.4
+Ilow2=imid2-0.4 slope2=0.020ns

```

```

.inc 'ldu.in'

```

```

*****
*
*           Analysis
*
*****

.op
* .trans .005ns 80n
.ac DEC 1000 100Mega 20giga
.probe il(d166)
.incl 'LD_U_Cinc.ext'
*.inc 'tsmc_ch_u.ext'
.END

*****
*
*           ldu.in files
*
*****

CIN1   innn inn 0.01u
*Xcin1   innn inn cd BT5580
Rin1   101 INNn 0
Vlin   101 VSS ac 1 pwl
+ 0     Imid1, 'tt-slope1' Imid1,
+ 'tt'  llow1, 'tt*3-slope1' llow1,
+ 'tt*3' Ihigh1, 'tt*4-slope1' Ihigh1,
+ 'tt*4' llow1, 'tt*5-slope1' llow1,
+ 'tt*5' Ihigh1, 'tt*8-slope1' Ihigh1,
+ 'tt*8' llow1, 'tt*15-slope1' llow1,
+ 'tt*15' Ihigh1, 'tt*17-slope1' Ihigh1,
+ 'tt*17' llow1, 'tt*18-slope1' llow1,
+ 'tt*18' Ihigh1, 'tt*19-slope1' Ihigh1,
+ 'tt*19' llow1, 'tt*22-slope1' llow1,
+ 'tt*22' Ihigh1, 'tt*27-slope1' Ihigh1,
+ 'tt*27' llow1, 'tt*28-slope1' llow1,
+ 'tt*28' Ihigh1, 'tt*29-slope1' Ihigh1,
+ 'tt*29' llow1, 'tt*30-slope1' llow1,
+ 'tt*30' Ihigh1, 'tt*36-slope1' Ihigh1,
+ 'tt*36' llow1, 'tt*39-slope1' llow1,
+ 'tt*39' Ihigh1, 'tt*40-slope1' Ihigh1,
+ 'tt*40' llow1, 'tt*41-slope1' llow1,
+ 'tt*41' Ihigh1, 'tt*42-slope1' Ihigh1,
+ 'tt*42' llow1, 'tt*49-slope1' llow1,
+ 'tt*49' Ihigh1, 'tt*50-slope1' Ihigh1,
+ 'tt*50' llow1, 'tt*57-slope1' llow1,
+ 'tt*57' Ihigh1, 'tt*64-slope1' Ihigh1,
+ 'tt*64' llow1, 'tt*65-slope1' llow1,
+ 'tt*65' Ihigh1, 'tt*72-slope1' Ihigh1,
+ 'tt*72' llow1, 'tt*73-slope1' llow1,
+ 'tt*73' Ihigh1, 'tt*74-slope1' Ihigh1,
+ 'tt*74' llow1, 'tt*75-slope1' llow1,
+ 'tt*75' Ihigh1, 'tt*78-slope1' Ihigh1,

```

```

+ 'tt*78' Ilow1, 'tt*85-slope1' Ilow1,
+ 'tt*85' Ihigh1, 'tt*87-slope1' Ihigh1,
+ 'tt*87' Ilow1, 'tt*88-slope1' Ilow1,
+ 'tt*88' Ihigh1, 'tt*89-slope1' Ihigh1,
+ 'tt*89' Ilow1, 'tt*92-slope1' Ilow1,
+ 'tt*92' Ihigh1, 'tt*97-slope1' Ihigh1,
+ 'tt*97' Ilow1, 'tt*98-slope1' Ilow1,
+ 'tt*98' Ihigh1, 'tt*99-slope1' Ihigh1,
+ 'tt*99' Ilow1, 'tt*100-slope1' Ilow1,
+ 'tt*100' Ihigh1, 'tt*106-slope1' Ihigh1,
+ 'tt*106' Ilow1, 'tt*109-slope1' Ilow1,
+ 'tt*109' Ihigh1, 'tt*110-slope1' Ihigh1,
+ 'tt*110' Ilow1, 'tt*111-slope1' Ilow1,
+ 'tt*111' Ihigh1, 'tt*112-slope1' Ihigh1,
+ 'tt*112' Ilow1, R 'tt'

```

```
* Xcin2      inpp inp ab BT5580
```

```

Cin2  201  INP  0.01u
Vlin2  201  VSS  ac 1 pwl
+ 0    Imid2, 'tt-slope2' Imid2,
+ 'tt' Ihigh2, 'tt*3-slope2' Ihigh2,
+ 'tt*3' Ilow2, 'tt*4-slope2' Ilow2,
+ 'tt*4' Ihigh2, 'tt*5-slope2' Ihigh2,
+ 'tt*5' Ilow2, 'tt*8-slope2' Ilow2,
+ 'tt*8' Ihigh2, 'tt*15-slope2' Ihigh2,
+ 'tt*15' Ilow2, 'tt*17-slope2' Ilow2,
+ 'tt*17' Ihigh2, 'tt*18-slope2' Ihigh2,
+ 'tt*18' Ilow2, 'tt*19-slope2' Ilow2,
+ 'tt*19' Ihigh2, 'tt*22-slope2' Ihigh2,
+ 'tt*22' Ilow2, 'tt*27-slope2' Ilow2,
+ 'tt*27' Ihigh2, 'tt*28-slope2' Ihigh2,
+ 'tt*28' Ilow2, 'tt*29-slope2' Ilow2,
+ 'tt*29' Ihigh2, 'tt*30-slope2' Ihigh2,
+ 'tt*30' Ilow2, 'tt*36-slope2' Ilow2,
+ 'tt*36' Ihigh2, 'tt*39-slope2' Ihigh2,
+ 'tt*39' Ilow2, 'tt*40-slope2' Ilow2,
+ 'tt*40' Ihigh2, 'tt*41-slope2' Ihigh2,
+ 'tt*41' Ilow2, 'tt*42-slope2' Ilow2,
+ 'tt*42' Ihigh2, 'tt*49-slope2' Ihigh2,
+ 'tt*49' Ilow2, 'tt*50-slope2' Ilow2,
+ 'tt*50' Ihigh2, 'tt*57-slope2' Ihigh2,
+ 'tt*57' Ilow2, 'tt*64-slope2' Ilow2,
+ 'tt*64' Ihigh2, 'tt*65-slope2' Ihigh2,
+ 'tt*65' Ilow2, 'tt*72-slope2' Ilow2,
+ 'tt*72' Ihigh2, 'tt*73-slope2' Ihigh2,
+ 'tt*73' Ilow2, 'tt*74-slope2' Ilow2,
+ 'tt*74' Ihigh2, 'tt*75-slope2' Ihigh2,
+ 'tt*75' Ilow2, 'tt*78-slope2' Ilow2,
+ 'tt*78' Ihigh2, 'tt*85-slope2' Ihigh2,
+ 'tt*85' Ilow2, 'tt*87-slope2' Ilow2,

```

```

+ 'tt*87' Ihigh2, 'tt*88-slope2' Ihigh2,
+ 'tt*88' Ilow2, 'tt*89-slope2' Ilow2,
+ 'tt*89' Ihigh2, 'tt*92-slope2' Ihigh2,
+ 'tt*92' Ilow2, 'tt*97-slope2' Ilow2,
+ 'tt*97' Ihigh2, 'tt*98-slope2' Ihigh2,
+ 'tt*98' Ilow2, 'tt*99-slope2' Ilow2,
+ 'tt*99' Ihigh2, 'tt*100-slope2' Ihigh2,
+ 'tt*100' Ilow2, 'tt*106-slope2' Ilow2,
+ 'tt*106' Ihigh2, 'tt*109-slope2' Ihigh2,
+ 'tt*109' Ilow2, 'tt*110-slope2' Ilow2,
+ 'tt*110' Ihigh2, 'tt*111-slope2' Ihigh2,
+ 'tt*111' Ilow2, 'tt*112-slope2' Ilow2,
+ 'tt*112' Ihigh2, R 'tt'

```

Veye eye 0

+ pulse 0 1 0n '3*tt-slope1/100000' 'slope1/100000' 0n '3*tt'

Reye eye 0 1T

```

*****
*
*          PSPLspice.txt          *
*
*****

```

.SUBCKT DCB5501 1 2

* Subcircuit for PSPL model 5501A DC Block

* 0.22uF, 50V, 7kHz - >26GHz

* J.R.Andrews, PSPL, 7/30/01

* This is NOT the actual circuit -- but a

* phenomological model. Model not valid for

* $f > 25\text{GHz}$. Good approx. for IL & RL

C1 1 3 0.22UF

* ; -50%,+80% TOLERANCE

R1 3 4 6

L1 3 4 0.18NH

R2 4 5 7

L2 4 5 0.2NH

C2 4 5 14PF

R3 5 2 270

L3 5 2 10PH

C3 5 2 3.75PF

.ENDS

*

*

.SUBCKT BT5580 1 2 3

* Subcircuit for PSPL model 5580 bias tee

* 0.22uF,50V,1mH,1 Amp,0.8ohm,10kHz-15GHz

* J.R.Andrews, PSPL, 8/4/01

* This is NOT the actual circuit -- but a

```

* phenomenological model. Model not valid for
* f > 20GHz. Good approx. for IL & RL
* node 1 is AC port, node 2 is AC+DC port
* node 3 is DC port
C1 1 6 0.22UF
* ; -50%, +80%% TOLERANCE
Rdc 6 4 0.8
L1 4 3 1.1MH
* ; +-25% TOLERANCE
R1 4 3 3.3K
R2 6 5 220
C2 5 0 0.05UF
R3 6 7 180
L3 7 8 33NH
C3 8 0 30FF
R4 6 9 110
L4 9 10 4.7NH
C4 10 0 43FF
R5 6 11 150
L5 11 12 3.3NH
C5 12 0 27FF
C6 6 0 0.29PF
L6 6 2 0.72NH
C7 2 0 0.29PF
.ENDS

```

A.2 High Current Laser Driver Input Control Files

```

.option post list
.option relv=1e-4 relvar=1e-2

.lib '~/research/SONY/models/mm018.l' TT
.param imid1=1.25 imid2=1.25
.param tt=.10ns lhigh1=imid1+.05 llow1=imid1-0.05 slope1=0.050ns
.param tt=.10ns lhigh2=imid2+.05 llow2=imid2-0.05 slope2=0.050ns
.inc 'os_input.l'

.inc 'CH_LD1.ext'
.op
.tran 0.002n 10n
.end

```

```

.option post list
.option relv=1e-4 relvar=1e-2

.lib '~/research/SONY/models/mm018.l' TT
.param imid1=1.2 imid2=1.2
.param tt=.10ns lhigh1=imid1+.05 llow1=imid1-0.05 slope1=0.050ns

```

```
.param tt=.10ns lhigh2=imid2+.05 llow2=imid2-0.05 slope2=0.050ns

.inc 'os_input.l'
.inc 'AI_LD1.ext'
.op
.probe dbgain=par('db(V(out1))')
.tran 0.002n 8n
.end
```

A.3 Laser Driver Netlist File

```
X8 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X10 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X12 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X14 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X16 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X18 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X20 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X22 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X24 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X26 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X28 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X30 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X32 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X34 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X36 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X38 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X40 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X42 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X44 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X46 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X48 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X50 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X52 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X54 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X56 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X58 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X60 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X62 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X64 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X66 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X68 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X70 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X72 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X74 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X76 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X78 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X80 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X82 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
```

X84 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X86 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X88 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X90 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X92 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X94 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X96 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X98 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X100 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X102 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X104 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X106 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X108 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X110 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X112 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X114 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X116 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X118 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X120 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X122 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X124 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X126 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X128 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X130 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X132 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X134 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X136 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X138 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X140 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X142 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X144 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X146 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X148 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X150 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X152 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X154 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X156 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X158 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X160 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0
X162 VDD VSS MIMCAP LT=29.9999992421363E-6 M=1.0

D164 VDD 6 PDIO AREA=100.000001335143E-12 PJ=39.999998989515E-6 W=10E-6
+L=10E-6 M=1.0
D166 6 EOUT1 PDIO AREA=100.000001335143E-12 PJ=39.999998989515E-6 W=10E-6
+L=10E-6 M=1.0

X168 VCN1 VDD RNODWO_RF W=1.99999999495049E-6 L=9.99999974737875E-6
X170 VCN1 VDD RNODWO_RF W=1.99999999495049E-6 L=9.99999974737875E-6
X172 VCN1 VDD RNODWO_RF W=1.99999999495049E-6 L=9.99999974737875E-6
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C674 VSS 4 45.3158193092967E-18
C676 VSS 3 401.225345782275E-18
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C680 VSS 1 5.25573017046274E-15
C682 INP 5 131.974284452671E-18
C684 INP 4 1.41759359937097E-15
C686 INP 2 534.359840379558E-18
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 C778 VCN 1 22.8936285212459E-15
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 C788 VCN ESDVSS 96.2127445314036E-15
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* Include files

* End of Netlist

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 +AD=528.000006997514E-15 AS=297.00000054797E-15 PD=3.16000000566419E-6
 +PS=1.64000005042908E-6 M=+1.00000000E+00
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 +AD=297.00000054797E-15 AS=297.00000054797E-15 PD=1.64000005042908E-6
 +PS=1.64000005042908E-6 M=+1.00000000E+00
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 +AD=297.00000054797E-15 AS=528.000006997514E-15 PD=1.64000005042908E-6
 +PS=3.16000000566419E-6 M=+1.00000000E+00
 M392 1 INP EOUT1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
 +AD=297.00000054797E-15 AS=297.00000054797E-15 PD=1.64000005042908E-6
 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M394 VCN INN 1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
 +AD=297.00000054797E-15 AS=297.00000054797E-15 PD=1.64000005042908E-6
 +PS=1.64000005042908E-6 M=+1.00000000E+00
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 +AD=528.000006997514E-15 AS=297.00000054797E-15 PD=3.16000000566419E-6
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 +AD=297.00000054797E-15 AS=297.00000054797E-15 PD=1.64000005042908E-6
 +PS=1.64000005042908E-6 M=+1.00000000E+00
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 +AD=297.00000054797E-15 AS=528.000006997514E-15 PD=1.64000005042908E-6
 +PS=3.16000000566419E-6 M=+1.00000000E+00
 M402 VCN INN 1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
 +AD=297.00000054797E-15 AS=297.00000054797E-15 PD=1.64000005042908E-6
 +PS=1.64000005042908E-6 M=+1.00000000E+00
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 +AD=297.00000054797E-15 AS=297.00000054797E-15 PD=1.64000005042908E-6
 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M406 1 INN VCN ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
 +AD=297.00000054797E-15 AS=297.00000054797E-15 PD=1.64000005042908E-6
 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M408 EOUT1 INP 1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
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 +PS=3.16000000566419E-6 M=+1.00000000E+00
 M410 VCN INN 1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
 +AD=297.00000054797E-15 AS=297.00000054797E-15 PD=1.64000005042908E-6

+PS=1.64000005042908E-6 M=+1.00000000E+00
 M412 1 INP EOUT1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
 +AD=528.000006997514E-15 AS=297.00000054797E-15 PD=3.16000000566419E-6
 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M414 1 INN VCN ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
 +AD=297.00000054797E-15 AS=528.000006997514E-15 PD=1.64000005042908E-6
 +PS=3.16000000566419E-6 M=+1.00000000E+00
 M416 EOUT1 INP 1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
 +AD=297.00000054797E-15 AS=297.00000054797E-15 PD=1.64000005042908E-6
 +PS=1.64000005042908E-6 M=+1.00000000E+00
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 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M420 1 INP EOUT1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
 +AD=297.00000054797E-15 AS=297.00000054797E-15 PD=1.64000005042908E-6
 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M422 1 INN VCN ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
 +AD=297.00000054797E-15 AS=297.00000054797E-15 PD=1.64000005042908E-6
 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M424 EOUT1 INP 1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
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 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M426 VCN INN 1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
 +AD=297.00000054797E-15 AS=297.00000054797E-15 PD=1.64000005042908E-6
 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M428 1 INP EOUT1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
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 +PS=3.16000000566419E-6 M=+1.00000000E+00
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 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M432 EOUT1 INP 1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
 +AD=528.000006997514E-15 AS=297.00000054797E-15 PD=3.16000000566419E-6
 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M434 VCN INN 1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
 +AD=297.00000054797E-15 AS=528.000006997514E-15 PD=1.64000005042908E-6
 +PS=3.16000000566419E-6 M=+1.00000000E+00
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 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M438 1 INN VCN ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
 +AD=528.000006997514E-15 AS=297.00000054797E-15 PD=3.16000000566419E-6
 +PS=1.64000005042908E-6 M=+1.00000000E+00
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 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M442 VCN INN 1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
 +AD=297.00000054797E-15 AS=297.00000054797E-15 PD=1.64000005042908E-6
 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M444 1 INP EOUT1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
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+PS=1.64000005042908E-6 M=+1.00000000E+00
 M446 EOUT1 INP 1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
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 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M448 1 INN VCN ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
 +AD=297.00000054797E-15 AS=297.00000054797E-15 PD=1.64000005042908E-6
 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M450 EOUT1 INP 1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
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 +PS=3.16000000566419E-6 M=+1.00000000E+00
 M452 1 INP EOUT1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
 +AD=297.00000054797E-15 AS=297.00000054797E-15 PD=1.64000005042908E-6
 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M454 VCN INN 1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
 +AD=297.00000054797E-15 AS=297.00000054797E-15 PD=1.64000005042908E-6
 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M456 1 INP EOUT1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
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 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M458 EOUT1 INP 1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
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 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M460 1 INN VCN ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
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 +PS=3.16000000566419E-6 M=+1.00000000E+00
 M462 EOUT1 INP 1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
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 M464 1 INP EOUT1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
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 +PS=1.64000005042908E-6 M=+1.00000000E+00
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 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M468 1 INP EOUT1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
 +AD=297.00000054797E-15 AS=297.00000054797E-15 PD=1.64000005042908E-6
 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M470 EOUT1 INP 1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
 +AD=297.00000054797E-15 AS=528.000006997514E-15 PD=1.64000005042908E-6
 +PS=3.16000000566419E-6 M=+1.00000000E+00
 M472 1 INN VCN ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
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 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M474 EOUT1 INP 1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
 +AD=297.00000054797E-15 AS=297.00000054797E-15 PD=1.64000005042908E-6
 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M476 1 INP EOUT1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
 +AD=528.000006997514E-15 AS=297.00000054797E-15 PD=3.16000000566419E-6
 +PS=1.64000005042908E-6 M=+1.00000000E+00
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[illegible]

[illegible]

+PS=1.64000005042908E-6 M=+1.00000000E+00
 M582 VSS IMOD 1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
 +AD=297.00000054797E-15 AS=297.00000054797E-15 PD=1.64000005042908E-6
 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M584 1 IMOD VSS ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
 +AD=528.000006997514E-15 AS=297.00000054797E-15 PD=3.16000000566419E-6
 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M586 VSS IMOD 1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
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 +PS=1.64000005042908E-6 M=+1.00000000E+00
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 +PS=3.16000000566419E-6 M=+1.00000000E+00
 M590 VSS IMOD 1 ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
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 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M592 1 IMOD VSS ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
 +AD=297.00000054797E-15 AS=297.00000054797E-15 PD=1.64000005042908E-6
 +PS=1.64000005042908E-6 M=+1.00000000E+00
 M594 1 IMOD VSS ESDVSS NCH L=180.000000682412E-9 W=1.09999996311672E-6
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 +PS=2.53999996857601E-6 M=+1.00000000E+00
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 +PS=2.53999996857601E-6 M=+1.00000000E+00
 M608 VSS IBIAS VCN ESDVSS NCH L=180.000000682412E-9 W=1.9999999495049E-6
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 M612 VSS IBIAS VCN ESDVSS NCH L=180.000000682412E-9 W=1.9999999495049E-6
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M650 VSS IBIAS EOUT1 ESDVSS NCH L=180.000000682412E-9 W=1.99999999495049E-6
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+AD=540.000010852693E-15 AS=959.999983153603E-15 PD=2.53999996857601E-6
+PS=4.95999984195805E-6 M=+1.00000000E+00
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+PS=2.53999996857601E-6 M=+1.00000000E+00
M656 VSS IBIAS IBIAS ESDVSS NCH L=180.000000682412E-9 W=1.99999999495049E-6
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+PS=2.53999996857601E-6 M=+1.00000000E+00
M658 IBIAS IBIAS VSS ESDVSS NCH L=180.000000682412E-9 W=1.99999999495049E-6
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+PS=2.53999996857601E-6 M=+1.00000000E+00
M660 VSS IBIAS IBIAS ESDVSS NCH L=180.000000682412E-9 W=1.99999999495049E-6
+AD=540.000010852693E-15 AS=540.000010852693E-15 PD=2.53999996857601E-6
+PS=2.53999996857601E-6 M=+1.00000000E+00
M662 IBIAS IBIAS VSS ESDVSS NCH L=180.000000682412E-9 W=1.99999999495049E-6
+AD=540.000010852693E-15 AS=959.999983153603E-15 PD=2.53999996857601E-6
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R1 NET075 NET076 50.0
R0 NET075 NET084 50.0
V6 NET075 0 3.3
V5 NET076 NET0116 0.0
V2 NET084 NET0108 0.0
V3 VB 0 1.2
V4 NET1 0 1.8
V1 NET080 0 1.0

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* Include files
* End of Netlist

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+PD=5.54E-6 PS=6.44333E-6 M=+8.40000000E+01
MPM3 NET064 0 NET1 NET1 PCH L=180E-9 W=5E-6 AD=1.35E-12 AS=1.525E-12
+PD=5.54E-6 PS=6.44333E-6 M=+8.40000000E+01
MPM1 NET0132 0 NET1 NET1 PCH L=180E-9 W=5E-6 AD=1.35E-12 AS=1.525E-12
+PD=5.54E-6 PS=6.44333E-6 M=+8.40000000E+01
MPM0 NET0136 0 NET1 NET1 PCH L=180E-9 W=5E-6 AD=1.35E-12 AS=1.525E-12
+PD=5.54E-6 PS=6.44333E-6 M=+8.40000000E+01
MNM11 NET0132 NET1 NET060 0 NCH L=180E-9 W=5E-6 AD=1.42E-12 AS=1.42E-12
+PD=5.90133E-6 PS=5.90133E-6 M=+1.50000000E+01
MNM9 NET0136 NET1 NET064 0 NCH L=180E-9 W=5E-6 AD=1.42E-12 AS=1.42E-12
+PD=5.90133E-6 PS=5.90133E-6 M=+1.50000000E+01
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+PD=5.90133E-6 PS=5.90133E-6 M=+1.05000000E+02
MNM4 NET064 INP NET067 0 NCH L=180E-9 W=5E-6 AD=1.42E-12 AS=1.42E-12
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MNM5 NET067 VB 0 0 NCH L=180E-9 W=5E-6 AD=1.42E-12 AS=1.42E-12 PD=5.90133E-
6

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+PS=5.90133E-6 M=+1.95000000E+02
 MNM6 NET0116 NET0132 NET0111 0 NCH L=180E-9 W=6E-6 AD=1.62E-12 AS=1.872E-12
 +PD=6.54E-6 PS=7.824E-6 M=+6.00000000E+01
 MNM7 NET0111 NET080 0 0 NCH L=180E-9 W=6E-6 AD=1.62E-12 AS=1.872E-12
 +PD=6.54E-6 PS=7.824E-6 M=+6.00000000E+01
 MNM8 NET0108 NET0136 NET0111 0 NCH L=180E-9 W=6E-6 AD=1.62E-12 AS=1.872E-12
 +PD=6.54E-6 PS=7.824E-6 M=+6.00000000E+01
 MNM1 NET0132 NET060 NET18 0 NCH L=180E-9 W=5E-6 AD=1.42E-12 AS=1.42E-12
 +PD=5.90133E-6 PS=5.90133E-6 M=+9.00000000E+01
 MNM0 NET0136 NET064 NET18 0 NCH L=180E-9 W=5E-6 AD=1.42E-12 AS=1.42E-12
 +PD=5.90133E-6 PS=5.90133E-6 M=+9.00000000E+01
 MNM2 NET18 VB 0 0 NCH L=180E-9 W=5E-6 AD=1.42E-12 AS=1.42E-12 PD=5.90133E-6
 +PS=5.90133E-6 M=+1.50000000E+02

R0 NET088 NET094 50.0
 R1 NET088 NET086 50.0
 V0 NET088 0 3.3
 V1 NET090 0 1.2
 V7 NET086 NET0124 0.0
 V2 NET094 NET0116 0.0
 V3 VB 0 900E-3
 V4 NET0123 0 1.8

* Include files

* End of Netlist

MPM6 NET087 0 NET0123 NET0123 PCH L=180E-9 W=2E-6 AD=960E-15 AS=960E-15
 +PD=4.96E-6 PS=4.96E-6 M=+5.20000000E+01
 MPM4 NET085 0 NET0123 NET0123 PCH L=180E-9 W=2E-6 AD=960E-15 AS=960E-15
 +PD=4.96E-6 PS=4.96E-6 M=+6.30000000E+01
 MPM5 NET0115 0 NET0123 NET0123 PCH L=180E-9 W=2E-6 AD=960E-15 AS=960E-15
 +PD=4.96E-6 PS=4.96E-6 M=+6.30000000E+01
 MPM7 NET0119 0 NET0123 NET0123 PCH L=180E-9 W=2E-6 AD=960E-15 AS=960E-15
 +PD=4.96E-6 PS=4.96E-6 M=+5.20000000E+01
 MNM21 NET0116 OUT1 NET0180 0 NCH L=180E-9 W=6E-6 AD=1.62E-12 AS=1.872E-12
 +PD=6.54E-6 PS=7.824E-6 M=+6.00000000E+01
 MNM20 NET0180 NET090 0 0 NCH L=180E-9 W=6E-6 AD=1.62E-12 AS=1.872E-12
 +PD=6.54E-6 PS=7.824E-6 M=+8.00000000E+01
 MNM19 NET0124 OUT2 NET0180 0 NCH L=180E-9 W=6E-6 AD=1.62E-12 AS=1.872E-12
 +PD=6.54E-6 PS=7.824E-6 M=+6.00000000E+01
 MNM12 NET0123 NET0115 NET064 0 NCH L=180E-9 W=5E-6 AD=2.4E-12 AS=2.4E-12
 +PD=10.96E-6 PS=10.96E-6 M=+4.00000000E+01
 MNM13 NET0123 NET085 NET060 0 NCH L=180E-9 W=5E-6 AD=2.4E-12 AS=2.4E-12
 +PD=10.96E-6 PS=10.96E-6 M=+4.00000000E+01
 MNM14 NET064 INN NET0104 0 NCH L=180E-9 W=5E-6 AD=2.4E-12 AS=2.4E-12
 +PD=10.96E-6 PS=10.96E-6 M=+2.28000000E+02
 MNM15 NET060 INP NET0104 0 NCH L=180E-9 W=5E-6 AD=2.4E-12 AS=2.4E-12
 +PD=10.96E-6 PS=10.96E-6 M=+2.28000000E+02
 MNM16 NET0104 VB 0 0 NCH L=180E-9 W=5E-6 AD=2.4E-12 AS=2.4E-12 PD=10.96E-6
 +PS=10.96E-6 M=+7.70000000E+01


```

MNM18 NET0123 NET0119 OUT2 0 NCH L=180E-9 W=2E-6 AD=960E-15 AS=960E-15
+PD=4.96E-6 PS=4.96E-6 M=+1.18000000E+02
MNM1 OUT2 NET060 NET18 0 NCH L=180E-9 W=5E-6 AD=2.4E-12 AS=2.4E-12
+PD=10.96E-6 PS=10.96E-6 M=+1.18000000E+02
MNM17 NET0123 NET087 OUT1 0 NCH L=180E-9 W=2E-6 AD=960E-15 AS=960E-15
+PD=4.96E-6 PS=4.96E-6 M=+1.18000000E+02
MNM0 OUT1 NET064 NET18 0 NCH L=180E-9 W=5E-6 AD=2.4E-12 AS=2.4E-12
+PD=10.96E-6 PS=10.96E-6 M=+1.18000000E+02
MNM2 NET18 VB 0 0 NCH L=180E-9 W=5E-6 AD=2.4E-12 AS=2.4E-12 PD=10.96E-6
+PS=10.96E-6 M=+8.90000000E+01

```

A.4 TSMC 0.18 μm Model Parameters

```

.param
+toxn = 4.08e-09      toxp = 4.08e-09
+dvthn = 0            dvthp = 0
+dxl = 0              dxw = 0
+cjn = 0.001000266   cjp = 0.001121
+cjswgn = 2.040547e-10  cjswp = 2.481e-10
+cjswgn = 3.340547e-10  cjswgp = 4.221e-10
+cgon = 3.665e-10     cgop = 3.28e-10
+hdifn = 2e-07        hdifp = 2e-07
.lib 'mm018.l' mos

MODEL nch.6 NMOS ( LMIN = 1.8E-07
+LMAX = '5E-07-dxl' WMIN = '1.3E-06-dxw' WMAX = '1.01E-05-dxw'
+NOIMOD = 1 EF = 0.825 AF = 0.8256 KF = 4.000E-29
+LEVEL = 49 TNOM = 25 VERSION = 3.2
+TOX = toxn TOXM = toxn XJ = 1.6E-07 NCH = 3.9E+17
+LLN = -1 LWN = 1 WLN = 1
+WWN = 1 LINT = 1E-08 LL = 0
+LW = 0 LWL = 0 WINT = 1E-08
+WL = 0 WW = 0 WWL = 0
+MOBMOD = 1 BINUNIT = 2 XL = '-2E-08+dxl'
+XW = '0+dxw' DWG = 0 DWB = 0
+ACM = 12 LDIF = 9E-08 HDIF = hdifn
+RSH = 6.8 RD = 0 RS = 0
+VTH0 = '0.4751247+dvthn' LVTH0 = 5.306376E-09 WVTH0 = 1.062077E-09
+PVTH0 = 5.180826E-15 K1 = 0.3998241 LK1 = 4.964413E-08
+WK1 = 9.765969E-08 PK1 = -6.472741E-15 K2 = 0.06352166
+LK2 = -2.388411E-08 WK2 = -4.203799E-08 PK2 = 5.416945E-15
+K3 = 0 DVT0 = 0 DVT1 = 0
+DVT2 = 0 DVT0W = 0 DVT1W = 0
+DVT2W = 0 NLX = 0 W0 = 0
+K3B = 0 VSAT = 84292.05 LVSAT = -0.00020125
+WVSAT = 0.001466182 UA = -9.057631E-10 LUA = 4.215886E-18
+WUA = 4.675041E-16 PUA = -5.258461E-23 UB = 2.760486E-18
+LUB = 5.400765E-27 WUB = -1.020856E-24 PUB = 1.584294E-33
+UC = 1.234253E-10 LUC = 4.240396E-18 WUC = -6.630735E-17

```

```

+PUC = -1.06277E-24 RDSW = 170 PRWB = 0
+PRWG = 0 WR = 1 U0 = 0.04387662
+LU0 = 1.283432E-09 WU0 = -5.211112E-09 PU0 = -3.156964E-16
+A0 = 0.5262759 LA0 = 8.277392E-08 WA0 = 1.447255E-07
+PA0 = -7.306591E-14 KETA = -0.04428695 LKETA = 3.242273E-09
+WKETA = 2.458758E-08 PKETA = -2.8368E-15 A1 = 0
+A2 = 0.99 AGS = -0.02836364 LAGS = 1.170909E-09
+WAGS = 8.430546E-08 PAGS = -1.180276E-14 B0 = 0
+B1 = 0 VOFF = -0.1246745 LVOFF = -1.468027E-09
+WVOFF = 1.245329E-09 PVOFF = -7.81931E-16 NFACTOR = 1
+CIT = 0.0002756616 LCIT = 1.031957E-10 WCIT = -3.764672E-11
+PCIT = 1.731749E-17 CDSC = 0 CDSCB = 0
+CDSCD = 0 ETA0 = -0.00029375 LETA0 = 1.81125E-10
+ETAB = 0.0013875 LETAB = -6.8425E-10 DSUB = 0
+PCLM = 1.102557 LPCLM = 3.813286E-08 WPCLM = 5.111752E-08
+PPCLM = 4.393024E-14 PDIBLC1 = 1E-06 PDIBLC2 = -0.006146589
+LPDIBLC2 = 5.060522E-09 WPDIBLC2 = 2.107634E-09 PPDIBLC2 = -2.950686E-16
+PDIBLCB = 0.01 DROUT = 0 PSCBE1 = 4E+08
+PSCBE2 = 1E-06 PVAG = 0 DELTA = 0.01
+ALPHA1 = 0.448150714 BETA0 = 11.59263 KT1 = -0.2268918
+LKT1 = 5.127722E-09 WKT1 = -2.576878E-09 PKT1 = -2.087376E-15
+KT2 = -0.02937242 LKT2 = 6.06917E-10 WKT2 = -1.65007E-09
+PKT2 = -3.93619E-17 AT = 20000 UTE = -2.172423
+LUTE = 8.369503E-08 WUTE = 9.001274E-07 PUTE = -1.336361E-13
+UA1 = 1.217414E-09 LUA1 = 9.220962E-19 WUA1 = 8.430593E-18
+PUA1 = -1.180283E-24 UB1 = -3.852224E-18 LUB1 = 4.306491E-25
+WUB1 = 3.248998E-24 PUB1 = -4.814262E-31 UC1 = -1.568814E-10
+LUC1 = 3.286692E-17 WUC1 = 1.868985E-16 PUC1 = -3.254285E-23
+KT1L = 0 PRT = 0 CJ = cjn
+PB = 0.6882682 MJ = 0.3595262 CJSW = cjswn
+PBSW = 0.6882682 MJSW = 0.2003879 CJSWG = cjswgn
+PBSWG = 0.6882682 MJSWG = 0.43879 CGDO = cgon
+CGSO = cgon TCJ = 0.001040287 TCJSW = 0.000645489 TCJSWG =
0.000645489
+TPB = 0.001554306 TPBSW = 0.001554306 TPBSWG = 0.001554306 JS =
8.38E-06
+JSW = 1.6E-11 N = 1 XTI = 3
+CAPMOD = 3 NQSMOD = 0 XPART = 1
+CF = 0 TLEV = 1 TLEVC = 1
+CALCACM = 1 SFVTFLAG = 0 ALPHA0 = 0
+DLC = 3E-9 LLC = -0.039 )

```

```

.model pch.6 pmos ( lmin = 1.8e-07
+lmax = '5e-07-dxl' wmin = '1.3e-06-dxw' wmax = '1.01e-05-dxw'
+noimod = 1 ef = 1.25 af = 1.052 kf = 6.100e-28
+level = 49 tnom = 25 version = 3.2
+tox = toxp toxm = toxp xj = 1.7e-07 nch = 3.9e+17
+lhn = -1 lwn = 1 wln = 1
+wwn = 1 lint = 1.5e-08 ll = 0
+lw = 0 lwl = 0 wint = 1.5e-08
+wl = 0 ww = 0 ww1 = 0

```

```

+mobmod = 1          binunit = 2          xl   = '-2e-08+dxl'
+xbw   = '0+dxw'     dwg   = 0           dwb   = 0
+acm   = 12          ldif  = 9e-08        hdif  = hdifp
+rsh   = 7.2         rd    = 0           rs    = 0
+vth0  = '-0.4493721+dvthp' lvth0 = -8.06576e-09 wvth0 = 1.067962e-08
+pvth0 = -1.742597e-15 k1    = 0.5178921 lk1   = 1.88712e-08
+wk1   = 1.445133e-07 pk1   = -2.057092e-14 k2    = 0.04280981
+lk2   = -6.758558e-09 wk2  = -5.283713e-08 pk2   = 8.796957e-15
+k3    = 0           dvt0  = 0           dvt1  = 0
+dvt2  = 0           dvt0w = 0           dvt1w = 0
+dvt2w = 0           nlx   = 0           w0    = 0
+k3b   = 0           vsat  = 130812.5    lvsat  = -0.0003656236
+ua    = 9.499295e-10 lua   = -1.785002e-16 wua   = -7.679882e-16
+pua    = 1.845406e-22 ub    = 4.958583e-19 lub    = 1.373112e-25
+wub    = 4.379602e-25 pub   = -1.528556e-31 uc    = -1.587904e-10
+luc    = 1.958586e-17 wuc   = 2.922792e-17 puc    = -1.081963e-23
+rdsw   = 530        prwb  = 0           prwg  = 0
+wr     = 1          u0    = 0.009831898 lu0   = -1.291645e-10
+wu0    = -2.92769e-09 pu0   = 3.012566e-16 a0    = 1.27343
+la0    = 3.369685e-09 wa0   = -5.001745e-07 pa0   = 1.278843e-13
+keta   = 0.01500061 lketa  = -5.831355e-10 wketa  = 8.661148e-09
+pketa  = -2.468804e-15 a1   = 0          a2    = 0.4
+ags    = 0.02       b0    = 0          b1    = 0
+voff   = -0.1308178 lvoff  = 1.554266e-10 wvoff  = 5.518163e-09
+pvoff  = -1.905712e-15 nfactor = 1          cit   = -6.280855e-05
+lcit   = 1.18189e-10 wcit  = 2.219781e-10 pcit  = -8.554223e-17
+cdsc   = 0          cdsb  = 0          cdsd  = 0
+eta0   = -0.0004687502 leta0 = 2.559375e-10 etab  = 0.001136754
+letab  = -5.565394e-10 wetab = -5.903965e-10 petab  = 2.656785e-16
+dsb    = 0          pclm  = 0.91154    lpclm  = 3.980698e-08
+wpclm  = -1.310087e-08 ppclm = 5.895399e-15 pdiblc1 = 1e-06
+pdiblc2 = 0.00796875 lpdiblc2 = 9.140624e-10 pdiblc3 = 0.01
+dROUT  = 0          pscbe1 = 3.5e+08    pscbe2 = 5e-07
+pvag   = 0          delta  = 0.01       alpha1 = 6.8730453846
+beta0  = 22.67827   kt1   = -0.2368895 lkt1  = -2.463487e-09
+wkt1   = 2.014118e-08 pkt1  = -2.009008e-15 kt2   = -0.02567999
+lkt2   = -7.622315e-11 wkt2 = 8.089046e-09 pkt2  = -1.558648e-15
+at     = 10000      ute    = -0.7213691 lute   = 5.387008e-10
+wute   = 1.230652e-07 pute  = 1.059462e-14 ua1   = 1.224e-09
+ub1    = -1.352532e-18 lub1  = 2.549208e-26 wub1   = -2.575436e-25
+pub1   = 3.337843e-32 uc1   = 7.191495e-11 luc1  = -7.869275e-18
+wuc1   = -4.963781e-17 puc1  = 1.019449e-23 kt11  = 0
+prt    = 0          cj     = cjp        pb     = 0.895226
+mj     = 0.4476     cjsw  = cjswp      pbsw  = 0.895226
+mjsw   = 0.3683619 cjswg = cjswgp    pbswg  = 0.895226
+mjswg  = 0.3683619 cgdo  = cgop       cgso  = cgop
+tcj    = 0.0009739001 tcjsw = 0.0004130718 tcjswg = 0.0004130718 tpb    =
0.001572025
+tpbsw  = 0.001572025 tpbswg = 0.001572025 js    = 4.92e-06   jsw    = 9e-10
+n      = 1          xti   = 3          capmod = 3
+nqsmod = 0          xpart  = 1         cf     = 0

```

```

+tlev = 1          tlevc = 1          calcacm = 1
+sfvtflag= 0      alpha0 = 0          dlc = 2e-9
+llc = -0.039     )

```

```

.MODEL PDIO D (                                LEVEL = 3
+ IS = 4.92E-6      RS = 1.0E-10      N = 1.25
+ BV = 10.2        IBV = 1E-3        IK = 1E20
+ IKR = 1E10       JSW = 1.02E-11     AREA = 7.5E-8
+ PJ = 1.1E-3      CJ = 1.121E-3     PB = 0.895226
+ MJ = 0.4476      CJSW = 2.481E-10   PHP = 0.895226
+ MJSW = 0.3683619 TLEV = 1          EG = 1.17
+ XTI = 3          TCV = -8.8E-4      TRS = 1.2E-4
+ TLEVC = 1        CTA = 9.739001E-4  CTP = 4.130718E-4
+ TPB = 1.572025E-3 TPHP = 1.572025E-3 TREF = 25
+ FC = 0           FCS = 0           )

```

```

.subckt rnodwo_rf Hi Lo l=10u w=2u
.param rsh=59 dw=0.0u ptc1=1.47e-3 ptc2=8.32e-7 pvc1=7.55e-4 pvc2=1.97e-4 pt='temper'
.param tfac='1.0+ptc1*(pt-25.0)+ptc2*(pt-25.0)*(pt-25.0)'
rp Hi 5 'rsh*/(w-dw)*(1+pvc1*abs(v(Hi,5))+pvc2*v(Hi,5)*v(Hi,5))*tfac*rnodwo_fac'
ls 5 Lo '(156.525-35.11*w*1e6-1.581*1*1e6+1.158*w*1*1e12)*1e-12*L_fac'
cov1 Hi 6 '(13.7225+3.84875*w*1e6)*1e-15*cj_fac'
rsub1 6 0 '(4.6515-0.22125*w*1e6)*1e3*rsub_fac'
csub1 6 0 '(3.77875-0.12388*w*1e5)*1e-15*csub_fac'
rsub3 6 7 '(1320.6-43.3*w*1e6)*rnodwo_fac'
rsub2 7 0 '(4.6515-0.22125*w*1e6)*1e3*rsub_fac'
csub2 7 0 '(3.77875-0.12388*w*1e5)*1e-15*csub_fac'
cov2 Lo 7 '(13.7225+3.84875*w*1e6)*1e-15*cj_fac'
.ends rnodwo_rf

```

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